

Company: Samsung Electronics Co., Ltd

Test of: WEA403e

To: FCC CFR 47 Part 15 Subpart E 15.407, IC RSS-247

Report No.: EMSC01-U2 Rev A

DFS TEST REPORT



DFS TEST REPORT



Test of: Samsung Electronics Co., Ltd WEA403e

to

To: FCC CFR 47 Part 15 Subpart E 15.407, IC RSS-247

Test Report Serial No.: EMSC01-U2 Rev A

This report supersedes: NONE

Applicant: Samsung Electronics Co., Ltd
129, Samsung-ro Yeongtong-gu,
Suwon-si, Gyeonggi-do,
Korea, 443-742

Product Function: WLAN Access Point

Issue Date: 10th July 2015

This Test Report is Issued Under the Authority of:

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TESTING CERT #2381.01

MiCOM Labs is an ISO 17025 Accredited Testing Laboratory



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1. ACCREDITATION, LISTINGS & RECOGNITION

1.1. TESTING ACCREDITATION

MiCOM Labs, Inc. is an accredited Electrical testing laboratory per the international standard ISO/IEC 17025:2005. The company is accredited by the American Association for Laboratory Accreditation (A2LA) www.a2la.org test laboratory number 2381.01. MiCOM Labs test schedule is available at the following URL; <http://www.a2la.org/scopepdf/2381-01.pdf>



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1.2. RECOGNITION

MiCOM Labs, Inc has widely recognized wireless testing capabilities. Our international recognition includes Conformity Assessment Body designation by APEC MRA countries. MiCOM Labs test reports are accepted globally.

Country	Recognition Body	Status	Phase	Identification No.
USA	Federal Communications Commission (FCC)	TCB	-	US0159 Listing #: 102167
Canada	Industry Canada (IC)	FCB	APEC MRA 2	US0159 Listing #: 4143A-2 4143A-3
Japan	MIC (Ministry of Internal Affairs and Communication)	CAB	APEC MRA 2	RCB 210
	VCCI	--	--	A-0012
Europe	European Commission	NB	EU MRA	NB 2280
Australia	Australian Communications and Media Authority (ACMA)	CAB	APEC MRA 1	US0159
Hong Kong	Office of the Telecommunication Authority (OFTA)	CAB	APEC MRA 1	
Korea	Ministry of Information and Communication Radio Research Laboratory (RRL)	CAB	APEC MRA 1	
Singapore	Infocomm Development Authority (IDA)	CAB	APEC MRA 1	
Taiwan	National Communications Commission (NCC) Bureau of Standards, Metrology and Inspection (BSMI)	CAB	APEC MRA 1	
Vietnam	Ministry of Communication (MIC)	CAB	APEC MRA 1	

EU MRA – European Union Mutual Recognition Agreement.

NB – Notified Body

APEC MRA – Asia Pacific Economic Community Mutual Recognition Agreement. Recognition agreement under which test lab is accredited to regulatory standards of the APEC member countries.

Phase I - recognition for product testing

Phase II – recognition for both product testing and certification

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1.3. PRODUCT CERTIFICATION

MiCOM Labs, Inc. is an accredited Product Certification Body per the international standard ISO/IEC 17065:2012. The company is accredited by the American Association for Laboratory Accreditation (A2LA) www.a2la.org test laboratory number 2381.02. MiCOM Labs test schedule is available at the following URL; <http://www.a2la.org/scopepdf/2381-02.pdf>



United States of America – Telecommunication Certification Body (TCB)
Industry Canada – Certification Body, CAB Identifier – US0159
Europe – Notified Body (NB), NB Identifier - 2280
Japan – Recognized Certification Body (RCB), RCB Identifier - 210



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2. DOCUMENT HISTORY

Document History		
Revision	Date	Comments
Draft	5 th July 2015	
Draft #2	9 th July 2015	
Rev A	10 th July 2015	Initial Release
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In the above table the latest report revision will replace all earlier versions.

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3. TEST RESULT CERTIFICATE

Manufacturer: Samsung Electronics Co., Ltd
129, Samsung-ro Yeongtong-gu,
Suwon-si, Gyeonggi-do,
Korea, 443-742

Tested By: MiCOM Labs, Inc.
575 Boulder Court
Pleasanton
California 94566 USA

Model: WEA403e

Telephone: +1 925 462 0304
Fax: +1 925 462 0306

Type Of Equipment: WLAN Access Point

S/N's: S2LG223914 | S2LG223922

Test Date(s): 19th June – 9th July 2015

Website: www.micomlabs.com

STANDARD(S)

FCC CFR 47 Part 15 Subpart E 15.407
(Limited to DFS Testing)

TEST RESULTS

EQUIPMENT COMPLIES

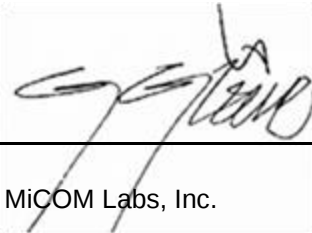
MiCOM Labs, Inc. tested the equipment mentioned in accordance with the requirements set forth in the above standards. Test results indicate that the equipment tested is capable of demonstrating compliance with the requirements as documented within this report.

Notes:

1. This document reports conditions under which testing was conducted and the results of testing performed.
2. Details of test methods used have been recorded and kept on file by the laboratory.
3. Test results apply only to the item(s) tested.

Approved & Released for MiCOM Labs, Inc. by:





Graeme Grieve
Quality Manager MiCOM Labs, Inc.



Gordon Hurst
President & CEO MiCOM Labs, Inc.

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4. REFERENCES AND MEASUREMENT UNCERTAINTY

4.1. Normative References

REF.	PUBLICATION	YEAR	TITLE
I	KDB 662911	Oct 31 2013	Guidance for measurement of output emission of devices that employ single transmitter with multiple outputs or systems with multiple transmitters operating simultaneously in the same frequency band
II	KDB 905462 D07 v01	10th June 2015	Test guidance to demonstrate compliance for U-NII devices subject to DFS requirements.
III	KDB 926956 DO1 v01r02	17th October 2014	U-NII Device Transition Plan
IV	KDB 789033 D02 v01	6th June 2014	General UNII Test Procedures New Rules V01
V	A2LA	June 2015	R105 - Requirement's When Making Reference to A2LA Accreditation Status
VI	ANSI C63.10	2013	American National Standard for Testing Unlicensed Wireless Devices
VII	ANSI C63.4	2014	American National Standards for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz
VIII	CISPR 22	2008	Information technology equipment - Radio disturbance characteristics - Limits and methods of measurement
IX	ETSI TR 100 028	2001-12	Parts 1 and 2 Electromagnetic compatibility and Radio Spectrum Matters (ERM); Uncertainties in the measurement of mobile radio equipment characteristics
X	FCC 06-96	Jun 3 2006	Memorandum Opinion and Order
XI	FCC 47 CFR Part 15.407	2014	Radio Frequency Devices; Subpart E –Unlicensed National Information Infrastructure Devices
XII	ICES-003	Issue 5 2012	Spectrum Management and Telecommunications; Interference-Causing Equipment Standard. Information Technology Equipment (ITE) – Limits and methods of measurement.
XIII	M 3003	Edition 3 Nov. 2012	Expression of Uncertainty and Confidence in Measurements
XIV	RSS-247, Issue 1	May 2015	Digital Transmission Systems (DTSs), Frequency Hopping Systems (FHSs) and Licence-Exempt Local Area Network (LE-LAN) Devices
XV	RSS-Gen, Issue 4	Nov 2014	General Requirements and Information for the Certification of Radiocommunication Equipment
XVI	KDB 644545 D03 v01	August 14th 2014	Guidance for IEEE 802.11ac New Rules
XVII	FCC 47 CFR Part 2.1033	2014	FCC requirements and rules regarding photographs and test setup diagrams.

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4.2. Test and Uncertainty Procedure

Conducted and radiated emission measurements were conducted in accordance with American National Standards Institute ANSI C63.4, listed in the Normative References section of this report.

Measurement uncertainty figures are calculated in accordance with ETSI TR 100 028 Parts 1 and 2.

Measurement uncertainties stated are based on a standard uncertainty multiplied by a coverage factor $k = 2$, providing a level of confidence of approximately 95 % in accordance with UKAS document M 3003 listed in the Normative References section of this report.

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5. PRODUCT DETAILS AND TEST CONFIGURATIONS

5.1. Technical Details

Details	Description
Purpose:	Test of the Samsung Electronics Co., Ltd WEA403e to FCC CFR 47 Part 15 Subpart E 15.407 to Radio Frequency Devices; Subpart E – Unlicensed National Information Infrastructure Devices
Applicant:	Samsung Electronics Co., Ltd 13, 256Beon-gil Jungbu-daero, Yeongtong-Gu Suwon-Shi, Gyeonggi-Do 443-800 South Korea
Manufacturer:	As Applicant
Laboratory performing the tests:	MiCOM Labs, Inc. 575 Boulder Court Pleasanton California 94566 USA
Test report reference number:	EMSC01-U2
Date EUT received:	8 th June 2015
Standard(s) applied:	FCC CFR 47 Part 15 Subpart E 15.407, IC RSS-247
Dates of test (from - to):	19 th June – 9 th July 2015
No of Units Tested:	4
Type of Equipment:	Wireless Access Point
Product Family Name:	WEA403e
Model(s):	WEA403e
Location for use:	Both
Declared Frequency Range(s):	5250 - 5350 MHz; 5470 - 5725 MHz;
Primary function of equipment:	WLAN Access Point
Secondary function of equipment:	None provided
Type of Modulation:	OFDM
EUT Modes of Operation:	20 MHz: 802.11a; 802.11n HT-20 40 MHz: 802.11n HT-40 80 MHz: 802.11ac-80;
Declared Nominal Output Power (Ave):	+14 dBm
Transmit/Receive Operation:	Transceiver - Half Duplex
Rated Input Voltage and Current:	POE (POE adaptor sold with unit) 48Vdc
Operating Temperature Range:	Declared Range 0°C to 45°C
Equipment Dimensions:	205.0mm x 205.0mm x 45.0mm / 8.1" x 8.1" x 1.8" (W x D x H)
Weight:	0.87 kg
Hardware Rev:	PCS01B
Firmware Rev:	3.1.7.T1
Software Rev:	3.1.7.R

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5.2. Scope Of Test Program

Samsung Electronics Co., Ltd WEA403e

The scope of the test program was to test the Samsung Electronics Co., Ltd WEA403e configurations in the frequency ranges 5250 - 5350 MHz; 5470 - 5725 MHz; for compliance against the following specification:

FCC CFR 47 Part 15 Subpart E 15.407

Radio Frequency Devices; Subpart E – Unlicensed National Information Infrastructure Devices

Industry Canada RSS-247

Digital Transmission Systems (DTSS), Frequency Hopping Systems (FHSS) and Licence-Exempt Local Area Network (LE-LAN) Devices

The device have two separate operating modes;

- 1).. Access Point (3 antennas) 802.11a, 802.11n HT-40, 802.11ac-80 modes were exercised
- 2).. Spectrum Monitoring Ports (3 antennas) 802.11a mode was exercised

Both the Access Point and Spectrum Monitor Ports were tested independently for DFS functionality and results for each are contained within this document.

Samsung Electronics Co., Ltd WEA403e



EUT - Top View



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5.3. Equipment Model(s) and Serial Number(s)

Type	Description	Manufacturer	Model	Serial no.	Delivery Date
EUT	Radiated	Samsung Electronics Co., Ltd	WEA403e	S2LG223914	8 th June 2015
EUT	Radiated	Samsung Electronics Co., Ltd	WEA403e	S2LG223922	8 th June 2015

5.4. Antenna Details

Type	Manufacturer	Model	Family	Gain (dBi)	BF Gain	Dir BW	X-Pol	Frequency Band (MHz)
external	ACE Technology	Unknown	Dipole	4.0	-	360	-	5250 – 5350 5470 - 5725
external	ACE Technology	Unknown	Dipole	5.5	-	360	-	5250 – 5350 5470 - 5725
external	ACE Technology	Unknown	Directional	7.0	-	360	-	5250 – 5350 5470 - 5725

BF Gain - Beamforming Gain
Dir BW - Directional BeamWidth
X-Pol - Cross Polarization

5.5. Test Configurations

Results for the following configurations are provided in this report:

Operational Mode(s) (802.11a/b/g/n/ac)	Data Rate with Highest Power MBit/s	Channel Frequency (MHz)		
		Low	Mid	High
5470 - 5725 MHz				
802.11a	6	5,500.00	--	--
802.11ac-80	29.3	5,530.00	--	--
802.11n HT-40	13.5	5,510.00	5,550.00	--

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5.6. Equipment Modifications

The following modifications were required to bring the equipment into compliance:

Issue: The WEA403e device Spectrum Monitoring operational mode had issues with Channel Close Time.

Initial Firmware Release: **Unknown**

Solution: Client updated firmware within the unit, device was retested and complied

Final Firmware Release: 3.1.7.T1

5.7. Deviations from the Test Standard

The following deviations from the test standard were required in order to complete the test program:

1. NONE



6. TEST SUMMARY

List of Measurements

Test Header	Result	Data Link
(h)(2) Dynamic Frequency Selection (DFS)	-	-
Access Point Operation		
(ii) Channel Availability Check	-	-
(a) Power-On CAC	Complies	View Data
(b) Beginning CAC	Complies	View Data
(c) End CAC	Complies	View Data
(iii) Channel Close / Transmission Time	Complies	View Data
(iv) Non-Occupancy Period	Complies	View Data
Probability of Detection	Complies	View Data
Detection Bandwidth	Complies	View Data
Spectrum Monitoring Operation		
(ii) Channel Availability Check	-	-
(a) Power-On CAC	Complies	View Data
(b) Beginning CAC	Complies	View Data
(c) End CAC	Complies	View Data
(iii) Channel Close / Transmission Time	Complies	View Data
(iv) Non-Occupancy Period	Complies	View Data
Probability of Detection	Complies	View Data
Detection Bandwidth	Complies	View Data

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7. TEST EQUIPMENT CONFIGURATION(S)

7.1. DFS - Conducted

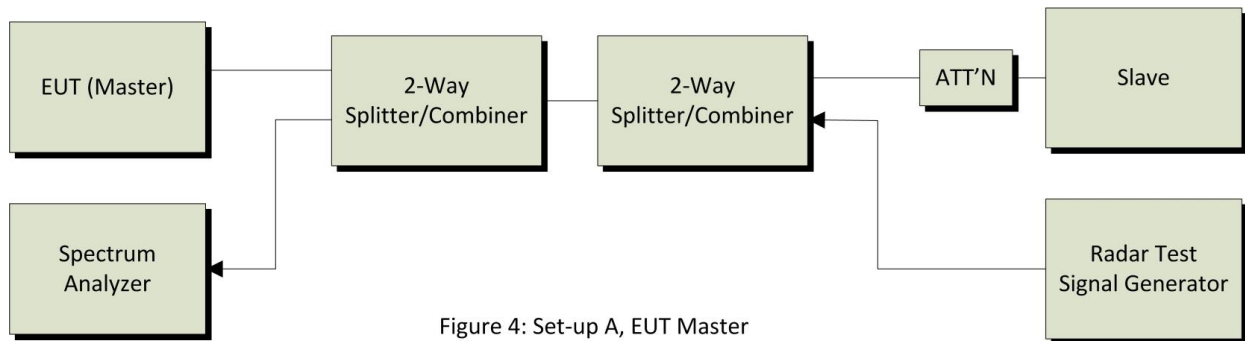


Figure 4: Set-up A, EUT Master

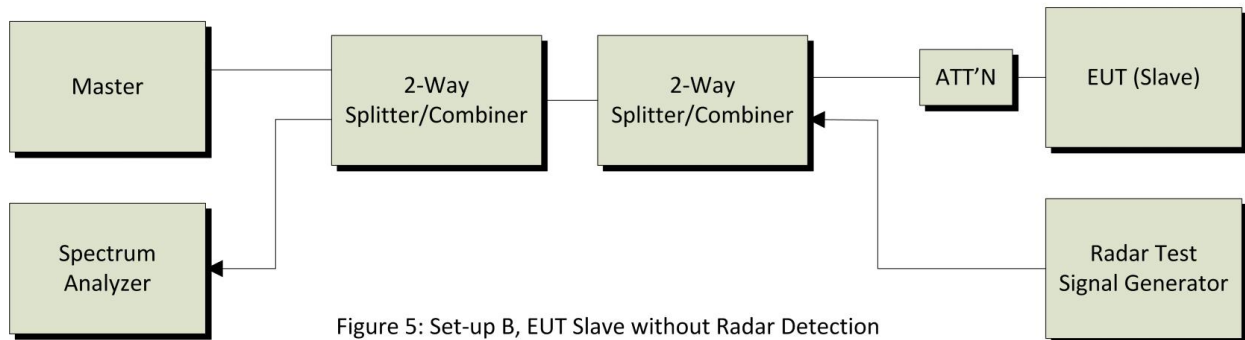


Figure 5: Set-up B, EUT Slave without Radar Detection

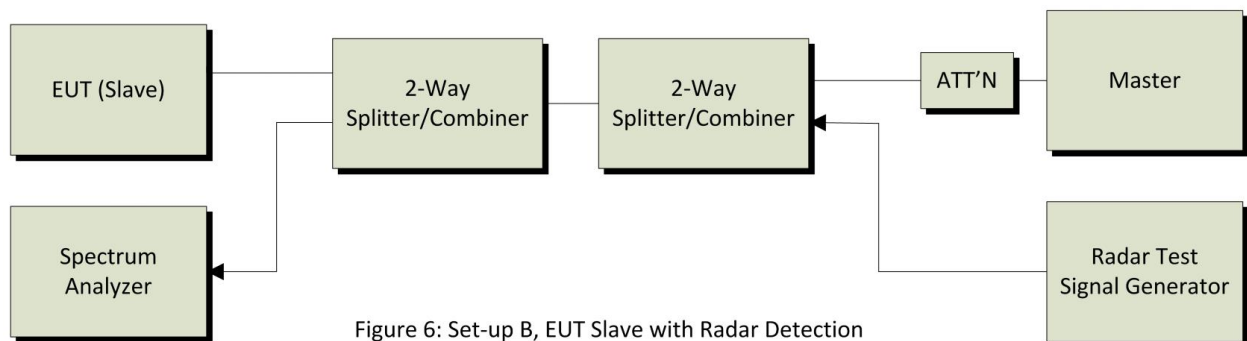


Figure 6: Set-up B, EUT Slave with Radar Detection

A full system calibration was performed on the test station and any resulting system losses (or gains) were taken into account in the production of all final measurement data.



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Asset#	Description	Manufacturer	Model#	Serial#	Calibration Due Date
158	Barometer/Thermometer	Control Company	4196	E2846	4 Dec 2015
193	Receiver 20 Hz to 7 GHz	Rhode & Schwarz	ESI 7	838496/007	14 Jan 2016
299	Test Software DFS Test System	Aeroflex	DFS test Software	V2.4.0	Not Required
359	DFS System	Aeroflex	PXI-1042	300001/004	16 Jul 2015
417	Laptop for DFS with DFS software	Lenova	W520	DFS	Not Required
418	PCI-e interface card	National Instruments	Express 8360	174AAC5	Not Required
422	Splitter/Combiner	Pasternack	PE 2031	001	Cal when used
71	Spectrum Analyser 9KHz-50GHz	HP	8565E	3425A00181	06 Aug 2015
DFS PCIe#1	PCIe cable for Aeroflex	National Instruments	PCIe cable	None	Not Required
DFS SMA#1	SMA Cable for DFS	Megaphase	SMA Cable	None	Cal when used
DFS SMA#2	SMA Cable for DFS	Megaphase	SMA Cable	None	Cal when used
DFS SMA#3	SMA Cable for DFS	Megaphase	SMA Cable	None	Cal when used
DFS SMA#4	SMA Cable for DFS	Megaphase	SMA Cable	None	Cal when used

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8. TEST METHODOLOGY

8.1. Dynamic Frequency Selection (DFS) Overview

A U-NII network will employ a DFS function to detect signals from radar systems and to avoid co-channel operation with these systems. This applies to the 5250-5350 MHz and/or 5470-5725 MHz bands. Within the context of the operation of the DFS function, a U-NII device will operate in either Master Mode or Client Mode. U-NII devices operating in Client Mode can only operate in a network controlled by a U-NII device operating in Master Mode. The following tables summarize the requirements.

Requirement	Master Device or Client with Radar Detection	Client without Radar Detection
	Operational Mode	
DFS Detection Threshold	Yes	Not Required
Channel Closing Transmission Time	Yes	Yes
Channel Move Time	Yes	Yes
U-NII Detection Bandwidth	Yes	Not Required

Additional requirements for devices with multiple bandwidth modes	Master Device or Client with Radar Detection	Client without Radar Detection
U-NII Detection Bandwidth and Statistical Performance Check	All BW modes must be tested	Not required
Channel Move Time and Channel Closing Transmission Time	Test using widest BW mode available	Test using the widest BW mode available for the link
All other tests	Any single BW mode	Not required

NOTE: Frequencies selected for statistical performance check should include several frequencies within the radar detection bandwidth and frequencies near the edge of the radar detection bandwidth. For 802.11 devices it is suggested to select frequencies in each of the bonded 20 MHz channels and the channel center frequency.



The operational behavior and individual DFS requirements associated with these modes are as follows:

8.1.1. Master Devices

- a) The Master Device will use DFS in order to detect Radar Waveforms with received signal strength above the DFS Detection Threshold in the 5250 – 5350 MHz and 5470 – 5725 MHz bands. DFS is not required in the 5150 – 5250 MHz or 5725 – 5850 MHz bands.
- b) Before initiating a network on a Channel, the Master Device will perform a Channel Availability Check for a specified time duration (Channel Availability Check Time) to ensure that there is no radar system operating on the Channel, using DFS described under subsection a) above.
- c) The Master Device initiates a U-NII network by transmitting control signals that will enable other U-NII devices to Associate with the Master Device.
- d) During normal operation, the Master Device will monitor the Channel (In-Service Monitoring) to ensure that there is no radar system operating on the Channel, using DFS described under a).
- e) If the Master Device has detected a Radar Waveform during In-Service Monitoring as described under d), the Operating Channel of the U-NII network is no longer an Available Channel. The Master Device will instruct all associated Client Device(s) to stop transmitting on this Channel within the Channel Move Time. The transmissions during the Channel Move Time will be limited to the Channel Closing Transmission Time.
- f) Once the Master Device has detected a Radar Waveform it will not utilize the Channel for the duration of the Non-Occupancy Period.
- g) If the Master Device delegates the In-Service Monitoring to a Client Device, then the combination will be tested to the requirements described under d) through f) above.

8.1.2. Client Devices

- a) A Client Device will not transmit before having received appropriate control signals from a Master Device.
- b) A Client Device will stop all its transmissions whenever instructed by a Master Device to which it is associated and will meet the Channel Move Time and Channel Closing Transmission Time requirements. The Client Device will not resume any transmissions until it has again received control signals from a Master Device.
- c) If a Client Device is performing In-Service Monitoring and detects a Radar Waveform above the DFS Detection Threshold, it will inform the Master Device. This is equivalent to the Master Device detecting the Radar Waveform and d) through f) of section 5.1.1 apply.
- d) Irrespective of Client Device or Master Device detection the Channel Move Time and Channel Closing Transmission Time requirements remain the same.
- e) The client test frequency must be monitored to ensure no transmission of any type has occurred for 30 minutes. Note: If the client moves with the master, the device is considered compliant if nothing appears in the client non-occupancy period test. For devices that shutdown (rather than moving channels), no beacons should appear.



8.2. DFS Detection Thresholds

The table below provides the DFS Detection Thresholds for Master Devices as well as Client Devices incorporating In-Service Monitoring.

DFS Detection Thresholds for Master Devices and Client Devices with Radar Detection

Maximum Transmit Power	Value (see Notes 1, 2 and 3)
EIRP $\geq$ 200 milliwatt	-64 dBm
EIRP $<$ 200 milliwatt and power density <10 dBm/MHz	-62 dBm
EIRP $<$ 200 milliwatt that do not meet the power spectral density requirement	-64 dBm

NOTE 1: This is the level at the input of the receiver assuming a 0 dBi receive antenna

NOTE 2: Throughout these test procedures an additional 1 dB has been added to the amplitude of the test transmission waveforms to account for variations in measurement equipment. This will ensure that the test signal is at or above the detection threshold level to trigger a DFS response.

NOTE 3: EIRP is based on the highest antenna gain. For MIMO devices refer to KDB Publication 662911 D01.

8.3. Response Requirements

The following table provides the response requirements for Master and Client Devices incorporating DFS.

DFS Response Requirement Values

Parameter	Value
Non-Occupancy Period	Minimum 30 minutes
Channel Availability Check Time	60 seconds
Channel Move Time	10 seconds, see NOTE 1
Channel Closing Transmission Time	200 milliseconds + an aggregate of 60 milliseconds over remaining 10 second period, see NOTES 1 and 2
U-NII Detection Bandwidth	Minimum 100% of the U-NII 99% transmission power bandwidth, see NOTE 3

NOTE 1: Channel Move Time and the Channel Closing Transmission Time should be performed with Radar Type 0. The measurement timing begins at the end of the Radar Type 0 burst.

NOTE 2: The Channel Closing Transmission Time is comprised of 200 milliseconds starting at the beginning of the Channel Move Time plus any additional intermittent control signals required to facilitate a Channel move (an aggregate of 60 milliseconds) during the remainder of the 10 second period. The aggregate duration of control signals will not count quiet periods in between transmissions.

NOTE 3: During the U-NII Detection Bandwidth detection test, radar type 0 should be used. For each frequency step the minimum percentage of detection is 90 percent. Measurements are performed with no data traffic.



8.4. Radar Test Waveforms

This section provides the parameters for required test waveforms, minimum percentage of successful detections, and the minimum number of trials that must be used for determining DFS conformance. Step intervals of 0.1 microsecond for Pulse Width, 1 microsecond for PRI, 1 MHz for chirp width and 1 for the number of pulses will be utilized for the random determination of specific test waveforms.

8.4.1. Short Radar Pulses

Short Pulse Radar Test Waveforms

Radar Type	Pulse Width (μS)	PRI (μS)	Number of Pulses	Minimum Percentage of Successful Detection	Minimum Number of Trials
0	1	1428	18	See Note 1	See Note 1
1	1	Test A: 15 unique PRI values randomly selected from the list of 23 PRI values in Table 5a	Roundup $\left\{ \left(\frac{1}{360} \right) \cdot \left(\frac{19 \cdot 10^6}{\text{PRI}_{\mu\text{sec}}} \right) \right\}$	60%	30
		Test B: 15 unique PRI values randomly selected in the range 518-3066 μS, with a minimum increment of 1 μS, excluding PRI values selected in Test A			
2	1-5	150-230	23-29	60%	30
3	6-10	200-500	16-18	60%	30
4	11-20	200-500	12-16	60%	30
Aggregate (Radar Types 1-4)				80%	120
Note 1: Short Radar Pulse Type 0 should be used for the Detection Bandwidth test, Channel Move Time and Channel Closing Time tests					

A minimum of 30 unique waveforms are required for each of the Short Pulse Radar Types 2 through 4. If more than 30 waveforms are used for Short Pulse Radar Types 2 through 4, then each additional waveform must also be unique and not repeated from the previous waveforms. If more than 30 waveforms are used for Short Pulse Radar Type 1, then each additional waveform is generated with Test B and must also be unique and not repeated from the previous waveforms in Tests A or B.



8.4.2. Long Radar Pulse Test

Long Pulse Radar Test Waveforms

Radar Type	Pulse Width (µsec)	Chirp Width (MHz)	PRI (µsec)	Number of Pulses per Burst	Number of Bursts	Minimum Percentage of Successful Detection	Minimum Trials
5	50-100	5-20	1000-2000	1-3	8-20	80%	30

The parameters for this waveform are randomly chosen. Thirty unique waveforms are required for the Long Pulse radar test signal. If more than 30 waveforms are used for the Long Pulse radar test signal, then each additional waveform must also be unique and not repeated from the previous waveforms.

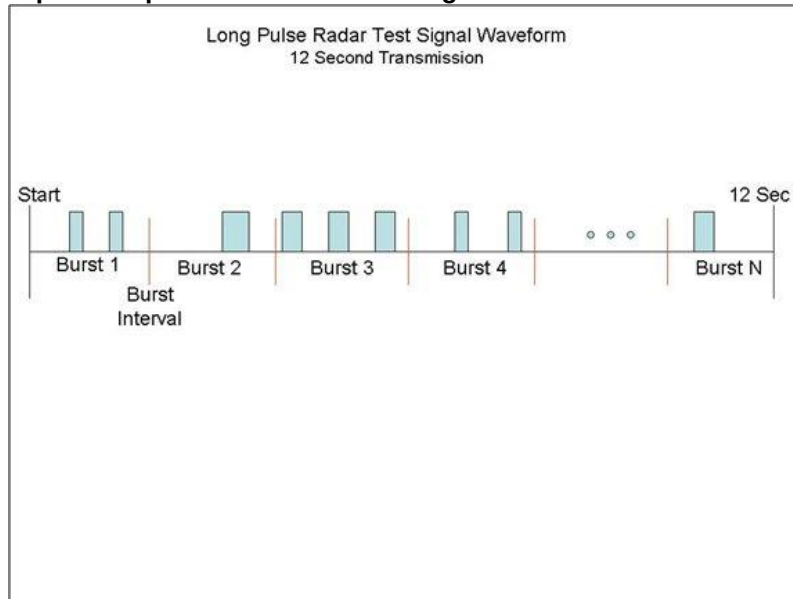
Each waveform is defined as follows:

1. The transmission period for the Long Pulse Radar test signal is 12 seconds.
2. There are a total of 8 to 20 Bursts in the 12 second period, with the number of Bursts being randomly chosen. This number is Burst Count.
3. Each Burst consists of 1 to 3 pulses, with the number of pulses being randomly chosen. Each Burst within the 12 second sequence may have a different number of pulses.
4. The pulse width is between 50 and 100 microseconds, with the pulse width being randomly chosen. Each pulse within a Burst will have the same pulse width. Pulses in different Bursts may have different pulse widths.
5. Each pulse has a linear FM chirp between 5 and 20 MHz, with the chirp width being randomly chosen. Each pulse within a Burst will have the same chirp width. Pulses in different Bursts may have different chirp widths. The chirp is centered on the pulse. For example, with a radar frequency of 5300 MHz and a 20 MHz chirped signal, the chirp starts at 5290 MHz and ends at 5310 MHz.
6. If more than one pulse is present in a Burst, the time between the pulses will be between 1000 and 2000 microseconds, with the time being randomly chosen. If three pulses are present in a Burst, the time between the first and second pulses is chosen independently of the time between the second and third pulses.
7. The 12 second transmission period is divided into even intervals. The number of intervals is equal to Burst_Count. Each interval is of length $(12,000,000 / \text{Burst_Count})$ microseconds. Each interval contains one Burst. The start time for the Burst, relative to the beginning of the interval, is between 1 and $[(12,000,000 / \text{Burst_Count}) - (\text{Total Burst Length}) + (\text{One Random PRI Interval})]$ microseconds, with the start time being randomly chosen. The step interval for the start time is 1 microsecond. The start time for each Burst is chosen independently.

A representative example of a Long Pulse radar test waveform:

1. The total test signal length is 12 seconds.
2. 8 Bursts are randomly generated for the Burst_Count
3. Burst 1 has 2 randomly generated pulses.
4. The pulse width (for both pulses) is randomly selected to be 75 microseconds.
5. The PRI is randomly selected to be at 1213 microseconds.
6. Bursts 2 through 8 are generated using steps 3 – 5.
7. Each Burst is contained in even intervals of 1,500,000 microseconds. The starting location for Pulse 1, Burst 1 is randomly generated (1 to 1,500,000 minus the total Burst 1 length + 1 random PRI interval) at the 325,001 microsecond step. Bursts 2 through 8 randomly fall in successive 1,500,000 microsecond intervals (i.e. Burst 2 falls in the 1,500,001 – 3,000,000 microsecond range).

Graphical representation of the Long Pulse Radar Test Waveform.





8.4.3. Frequency Hopping Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Pulses per Hop	Hopping Rate (kHz)	Hopping Sequence Length (msec)	Minimum Percentage of Successful Detection	Minimum Trials
6	1	333	9	.333	300	70%	30

For the Frequency Hopping Radar Type, the same Burst parameters are used for each waveform. The hopping sequence is different for each waveform and a 100-length segment is selected from the hopping sequence defined by the following algorithm:

The first frequency in a hopping sequence is selected randomly from the group of 475 integer frequencies from 5250 – 5724 MHz. Next, the frequency that was just chosen is removed from the group and a frequency is randomly selected from the remaining 474 frequencies in the group. This process continues until all 475 frequencies are chosen for the set. For selection of a random frequency, the frequencies remaining within the group are always treated as equally likely.

8.5. Radar Waveform Calibration

The following equipment setup was used to calibrate the Radar Waveform. A spectrum analyzer was used to establish the test signal level for each radar type. During this process there were no transmissions by either the Master or Client Device. The spectrum analyzer was switched to the zero span (Time Domain) mode at the frequency of the Radar Waveform generator. Peak detection was utilized. The spectrum analyzer resolution bandwidth (RBW) and video bandwidth (VBW) were set to 3 MHz.

The signal generator amplitude was set so that the power level measured at the spectrum analyzer was equal to the DFS detection threshold +1dB (Ref Section 9.2).



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8.6. Test Program Details

EUT Type: Master with radar detection

Frequency band(s): 5,250 - 5,350 MHz and 5,470 – 5,725 MHz

Uniform Loading: For the above frequency band(s) the manufacturer declared that the device provides an aggregate uniform loading of the spectrum across all devices by selecting an operating channel among the available channels using a random algorithm.

Test Environment: Ambient

Antenna Gain used for Testing: 4.0 dBi

Radio parameters: Transmit Power: Max Data Rate: 18 Mbit/s Duty Cycle: 35%

Number of Antenna Chains: 3

Test Communication Throughput Methodology

The requisite MPEG video file ("TestFile.mpg" available on the NTIA website at the following link <http://ntiacsd.ntia.doc.gov/dfs/>) is used during this video stream.

EUT Software Version: 3.1.7.R

EUT Build number: unknown

Test Environmental Conditions - Ambient:

Temperature: 17 to 23 °C

Relative humidity: 31 to 57%

Pressure: 999 to 1012 mbar

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9. DFS TEST RESULTS

9.1. Data Ports

9.1.1. Channel Availability Check

9.1.1.1. Power-On CAC

This test verifies that the EUT does not emit pulse, control, or data signals on the test Channel until the power-up sequence has been completed and the U-NII device checks for Radar Waveforms for one minute on the test Channel. This test does not use any Radar Waveforms.

-

The EUT is instructed to power up at the appropriate center frequency. The spectrum analyzer is set on zero span with a 1 MHz resolution bandwidth and 260 second sweep time to monitor the RF output of the EUT during power up. The analyzer's sweep will be started the same time power is applied to the U-NII device.

The EUT should not transmit any pulse or data transmissions until at least 1 minute after the completion of the power-on cycle.

The first red vertical line shown on the following plot denotes the instant when the EUT starts its power-up sequence i.e. T0 (as defined within the FCC's KDB 905462 D02 Section 4.1). The power-up reference T0 is determined by the time it takes for the EUT to start "beaconing" i.e. initial beacon – 60 secs = end of power-up.

The Channel Availability Check Time commences at instant T0 and will end no sooner than T0 + 60 seconds. T0 + 60 is indicated on the plot by the second vertical line.



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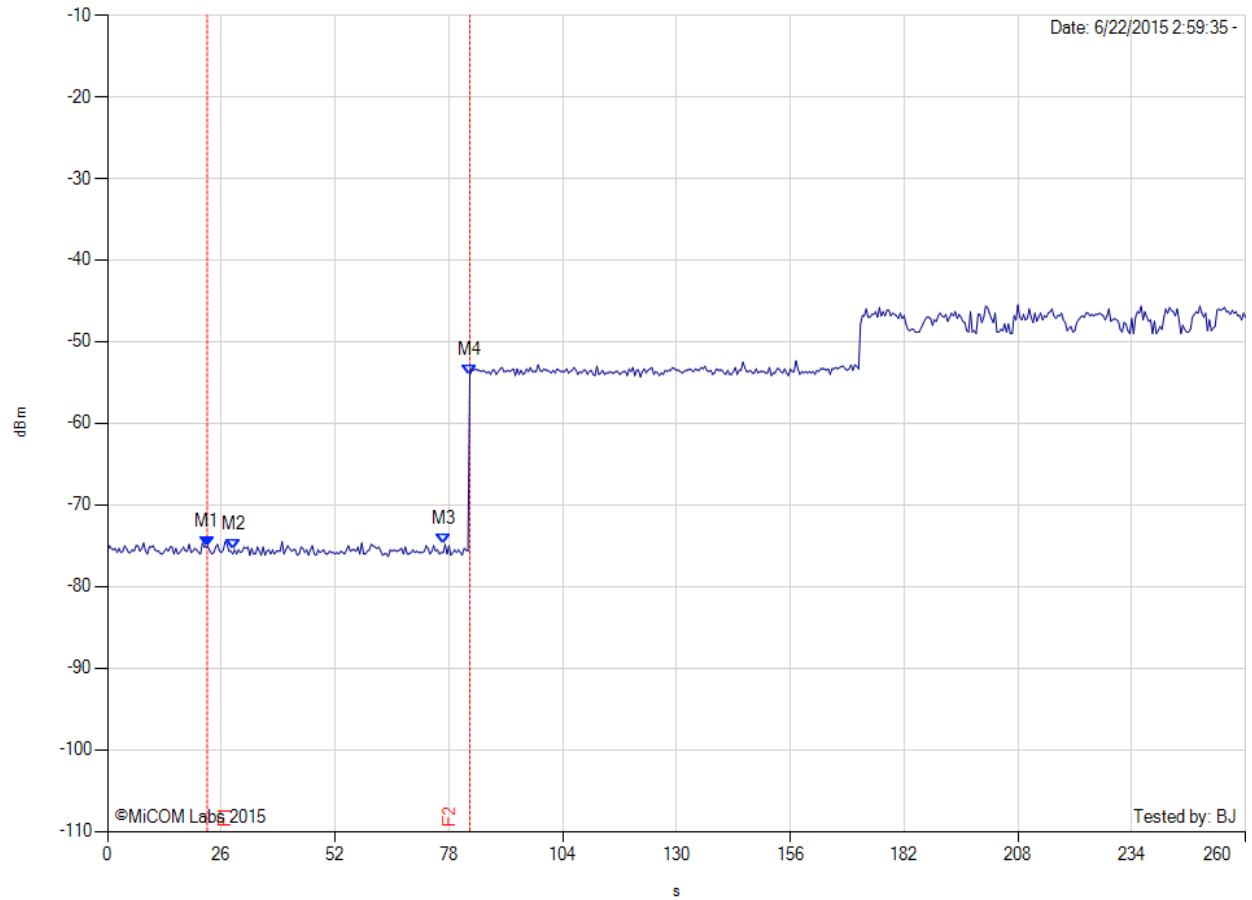
POWER-ON CAC

Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 22.770 s : -75.160 dBm M2(5495.00 MHz) : 28.770 s : -75.500 dBm M3(5495.00 MHz) : 76.770 s : -74.830 dBm M4(5495.00 MHz) : 82.770 s : -54.160 dBm	Channel Frequency: 5500.00 MHz

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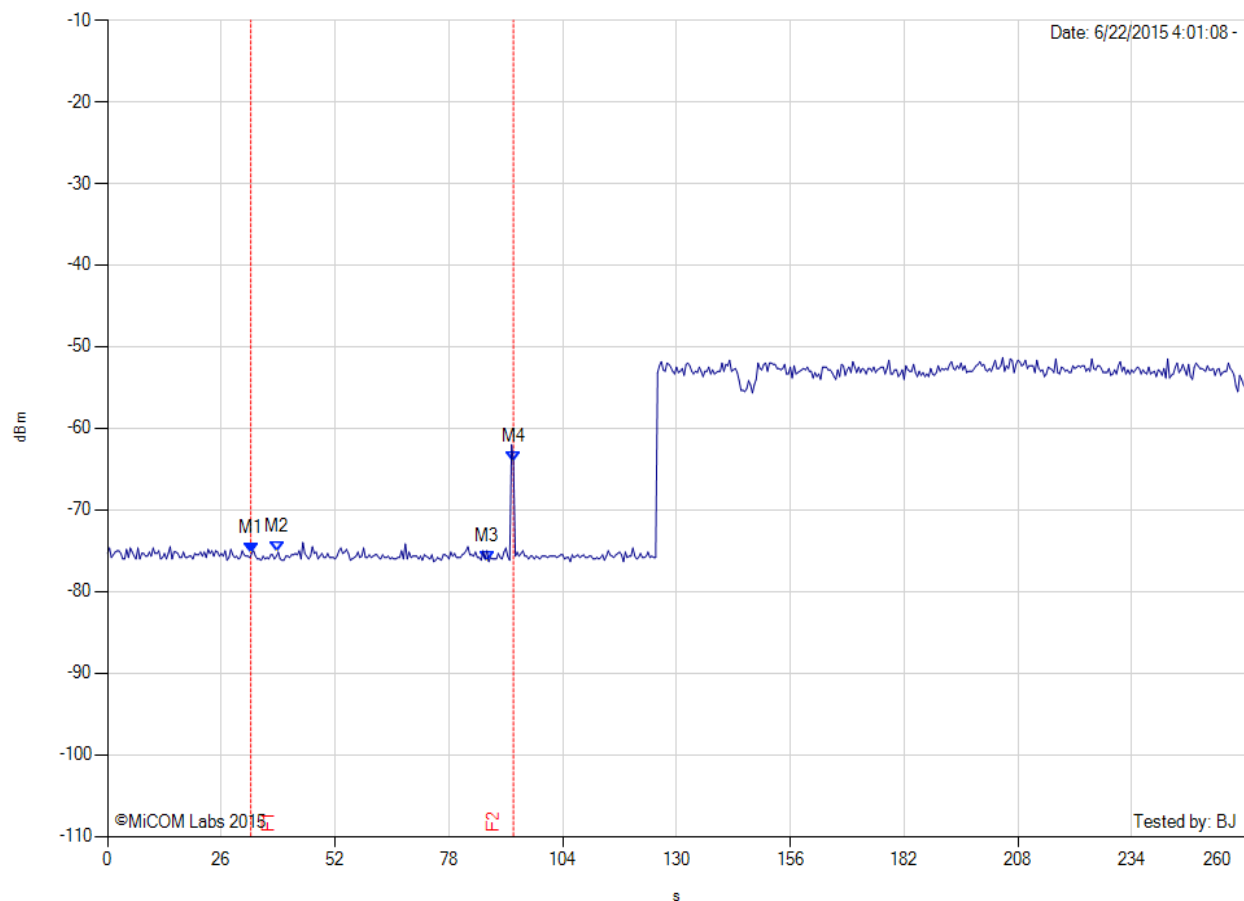
POWER-ON CAC

Variant: 802.11ac 80, Channel: 5530.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5525.00 MHz) : 32.730 s : -75.330 dBm M2(5525.00 MHz) : 38.730 s : -75.160 dBm M3(5525.00 MHz) : 86.730 s : -76.330 dBm M4(5525.00 MHz) : 92.730 s : -64.160 dBm	Channel Frequency: 5530.00 MHz

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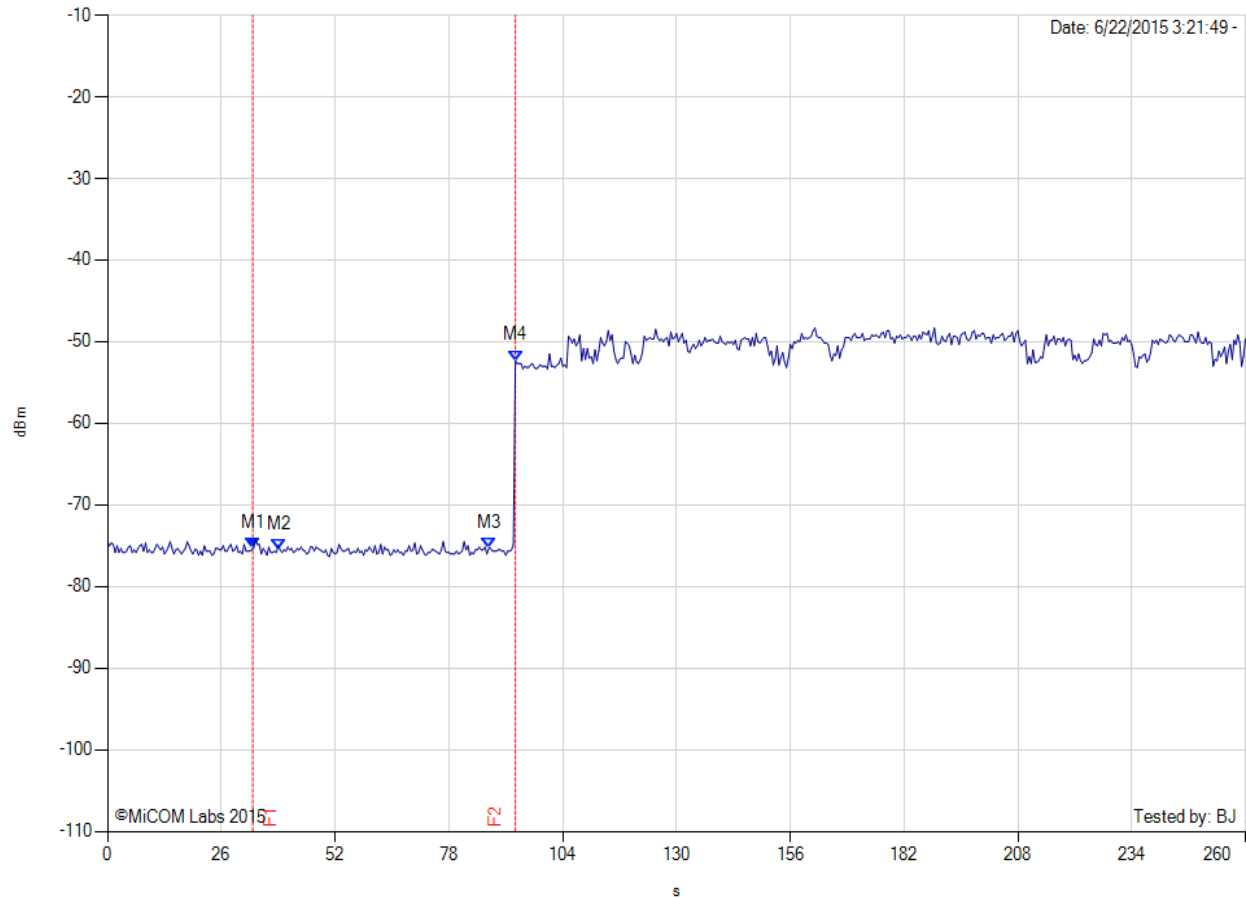
POWER-ON CAC

Variant: 802.11n HT40, Channel: 5510.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5505.00 MHz) : 33.170 s : -75.330 dBm M2(5505.00 MHz) : 39.170 s : -75.500 dBm M3(5505.00 MHz) : 87.170 s : -75.330 dBm M4(5505.00 MHz) : 93.170 s : -52.330 dBm	Channel Frequency: 5510.00 MHz

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9.1.1.2. Beginning CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold +1dB (Ref Section 9.2) occurs at the beginning of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at T0 (first red vertical marker line on the plot).

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

T0 + 60 is indicated on the plot by the second vertical line.



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BEGINNING CAC

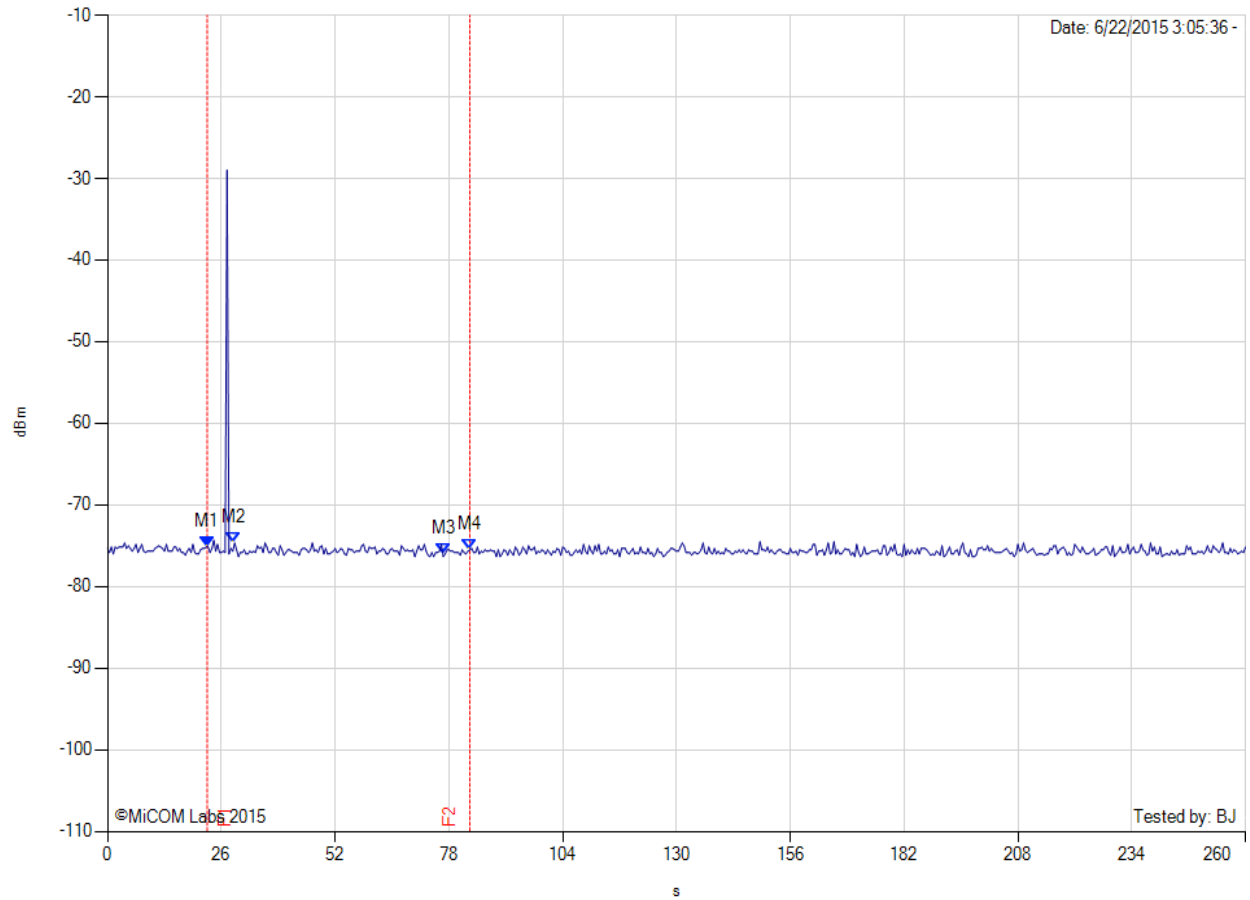


Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 22.770 s : -75.160 dBm M2(5495.00 MHz) : 28.770 s : -74.660 dBm M3(5495.00 MHz) : 76.770 s : -76.000 dBm M4(5495.00 MHz) : 82.770 s : -75.500 dBm	Channel Frequency: 5500.00 MHz

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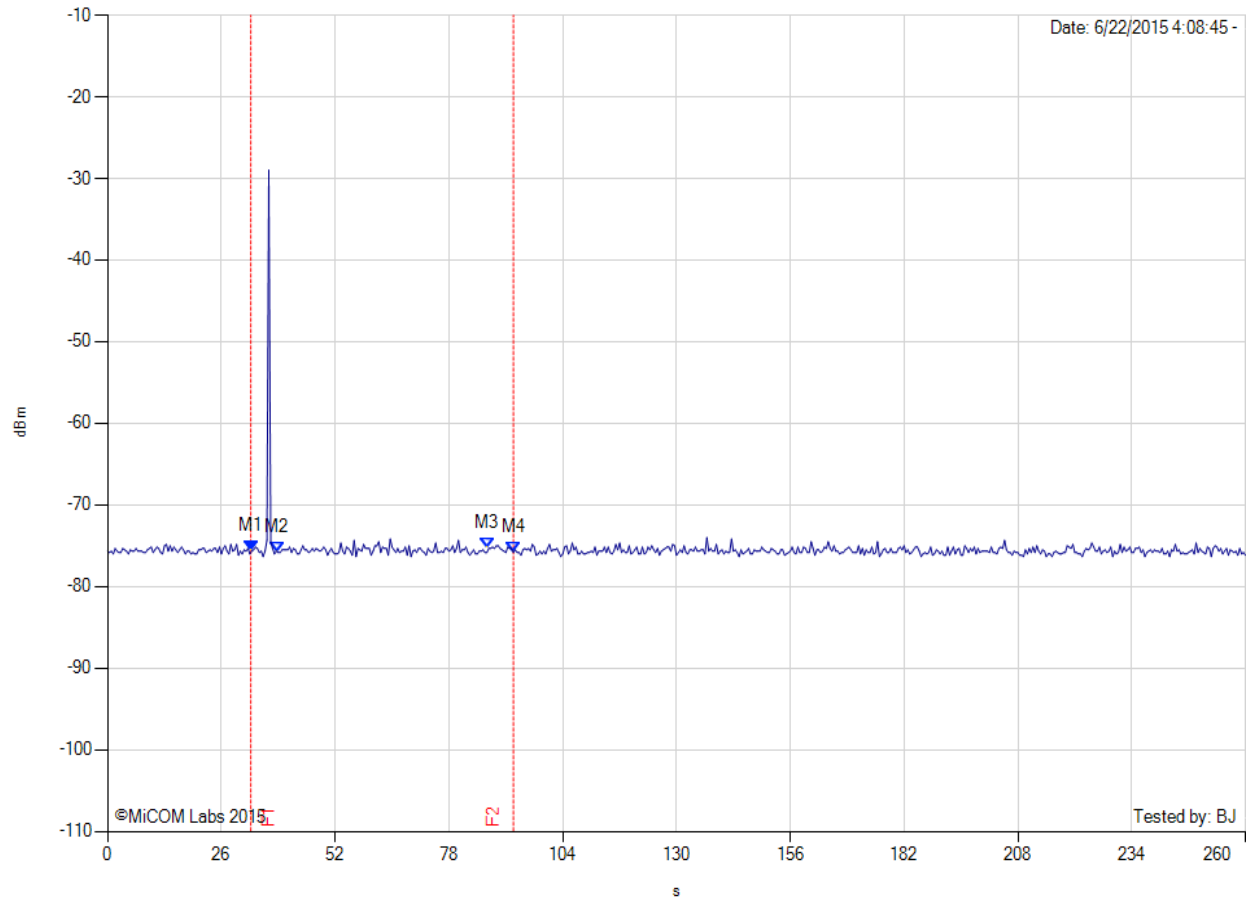


Variant: 802.11ac 80, Channel: 5530.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5525.00 MHz) : 32.730 s : -75.660 dBm M2(5525.00 MHz) : 38.730 s : -75.830 dBm M3(5525.00 MHz) : 86.730 s : -75.330 dBm M4(5525.00 MHz) : 92.730 s : -75.830 dBm	Channel Frequency: 5530.00 MHz

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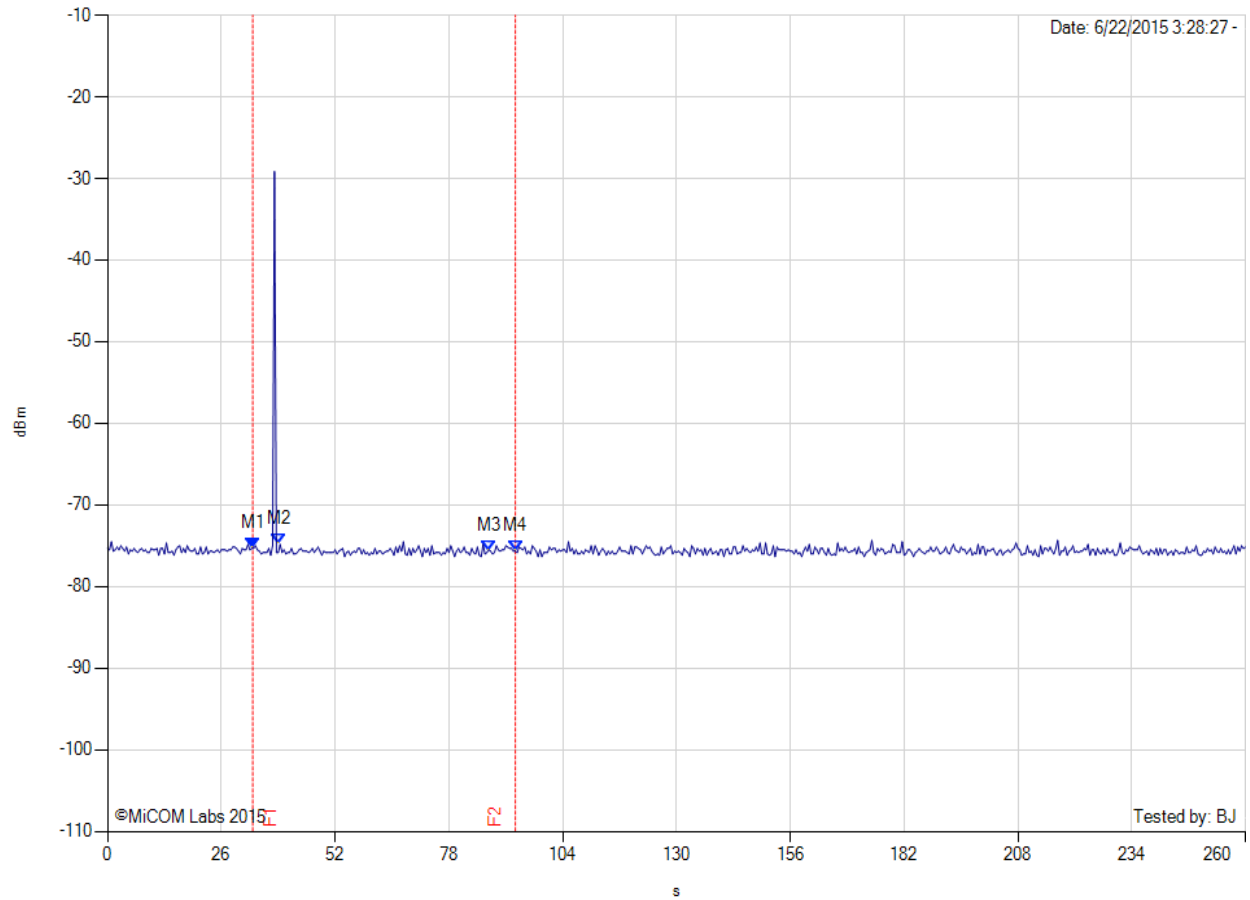


Variant: 802.11n HT40, Channel: 5510.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5505.00 MHz) : 33.170 s : -75.330 dBm M2(5505.00 MHz) : 39.170 s : -74.830 dBm M3(5505.00 MHz) : 87.170 s : -75.660 dBm M4(5505.00 MHz) : 93.170 s : -75.660 dBm	Channel Frequency: 5510.00 MHz

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9.1.1.3. End CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold occurs at the end of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at T0 + 54 seconds. The window will commence at marker 3 and end at the red time line T2 (T0 + 60 secs)

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

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END CAC

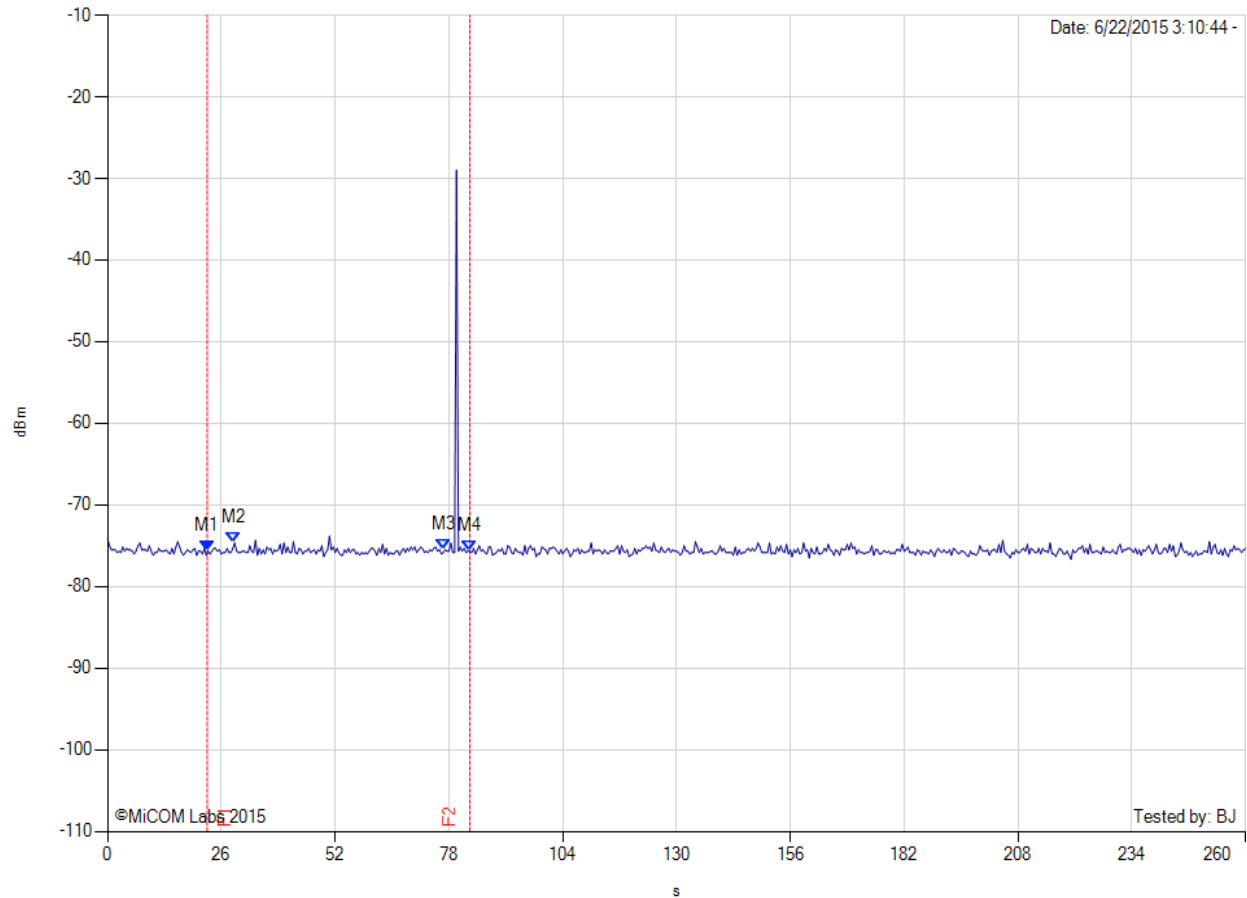


Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 22.770 s : -75.660 dBm M2(5495.00 MHz) : 28.770 s : -74.660 dBm M3(5495.00 MHz) : 76.770 s : -75.500 dBm M4(5495.00 MHz) : 82.770 s : -75.660 dBm	Channel Frequency: 5500.00 MHz

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END CAC

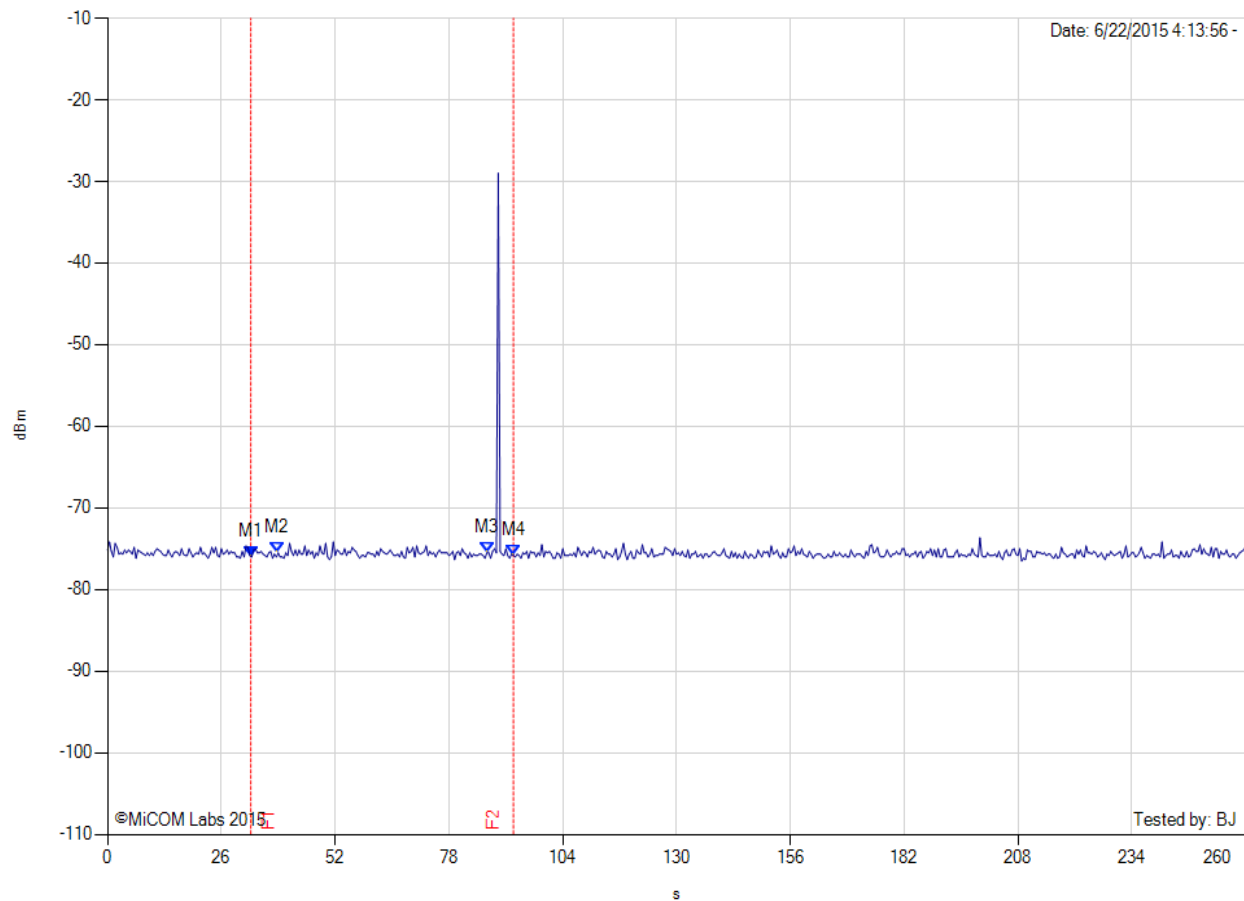


Variant: 802.11ac 80, Channel: 5530.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5525.00 MHz) : 32.730 s : -76.000 dBm M2(5525.00 MHz) : 38.730 s : -75.500 dBm M3(5525.00 MHz) : 86.730 s : -75.500 dBm M4(5525.00 MHz) : 92.730 s : -75.830 dBm	Channel Frequency: 5530.00 MHz

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END CAC

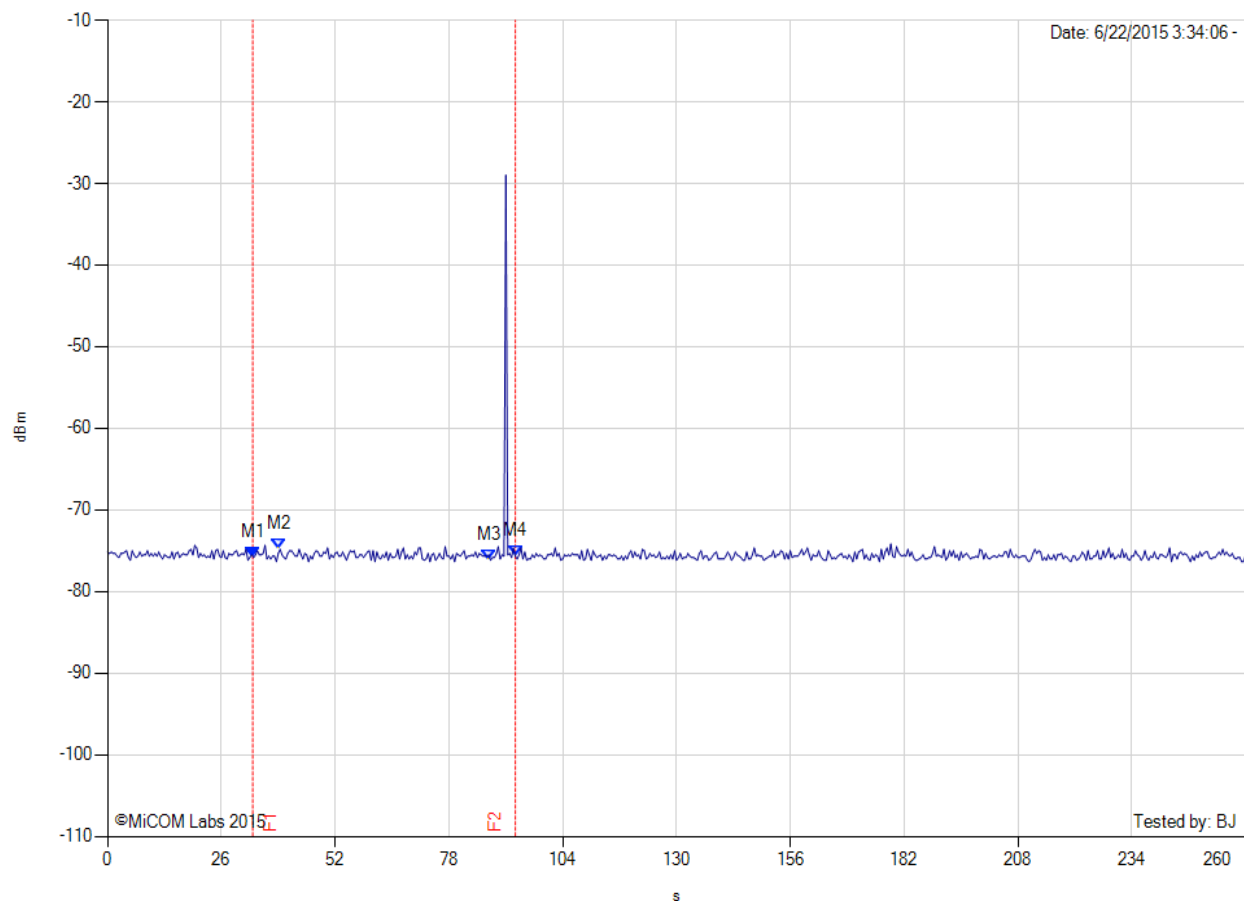


Variant: 802.11n HT40, Channel: 5510.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5505.00 MHz) : 33.170 s : -75.830 dBm M2(5505.00 MHz) : 39.170 s : -74.830 dBm M3(5505.00 MHz) : 87.170 s : -76.160 dBm M4(5505.00 MHz) : 93.170 s : -75.660 dBm	Channel Frequency: 5510.00 MHz

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9.1.2. Channel Close / Transmission Time

The steps below define the procedure to determine the above mentioned parameters when a radar Burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The EUT will be associated with a support U-NII device in order to setup an appropriate transmission media in accordance with the FCC requirements.

Channel Closing Transmission Time and Channel Move Time - Measurement

The test system was set-up to capture all transmission data for access point events above a threshold level of -50 dBm. The test equipment time stamps all captured events.

A Type 0 waveform was introduced to the EUT, from which a 12 second transmission record was digitally captured. The start of the Type 0 radar waveform is indicated in the test result plot as "Start Waveform", the end of the waveform is indicated as "End waveform".

Channel Closing Transmission Time, and the Channel Move Time start immediately after the last radar pulse is transmitted.

The aggregate of all pulses seen after the end of the radar injection are measured as the "Channel Closing Transmission time".

The last EUT activity after the end of the radar pulse is identified and used to determine the "Channel Move Time"



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Frequency 5500 MHz Channel 100

The PXI system measures and aggregates the pulses occurring after the end of the radar pulse to determine;-

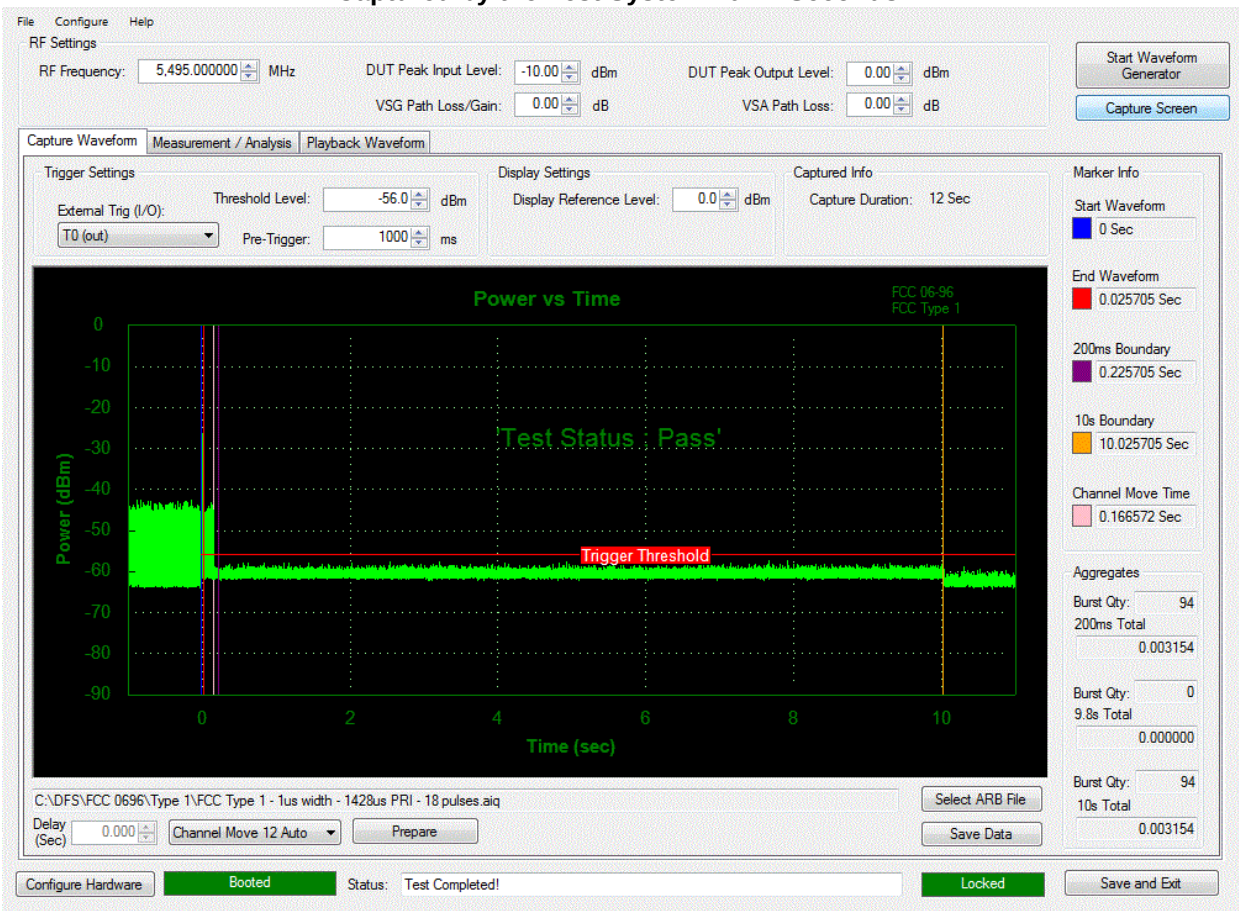
Channel Closing Transmission Time limit 1 second

Channel Move Time limit 10 seconds

1) Channel Closing Transmission Time = **3.154 mSecs (limit 250 mSec)**

2) Channel Move Time = **0.166572 Secs (limit is 10 seconds)**

Channel Move Time, Channel Closing Transmission Time for Type 1 Radar Captured by the Test System - 0-12 Seconds



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Frequency 5510 MHz Channel 102

The PXI system measures and aggregates the pulses occurring after the end of the radar pulse to determine;-

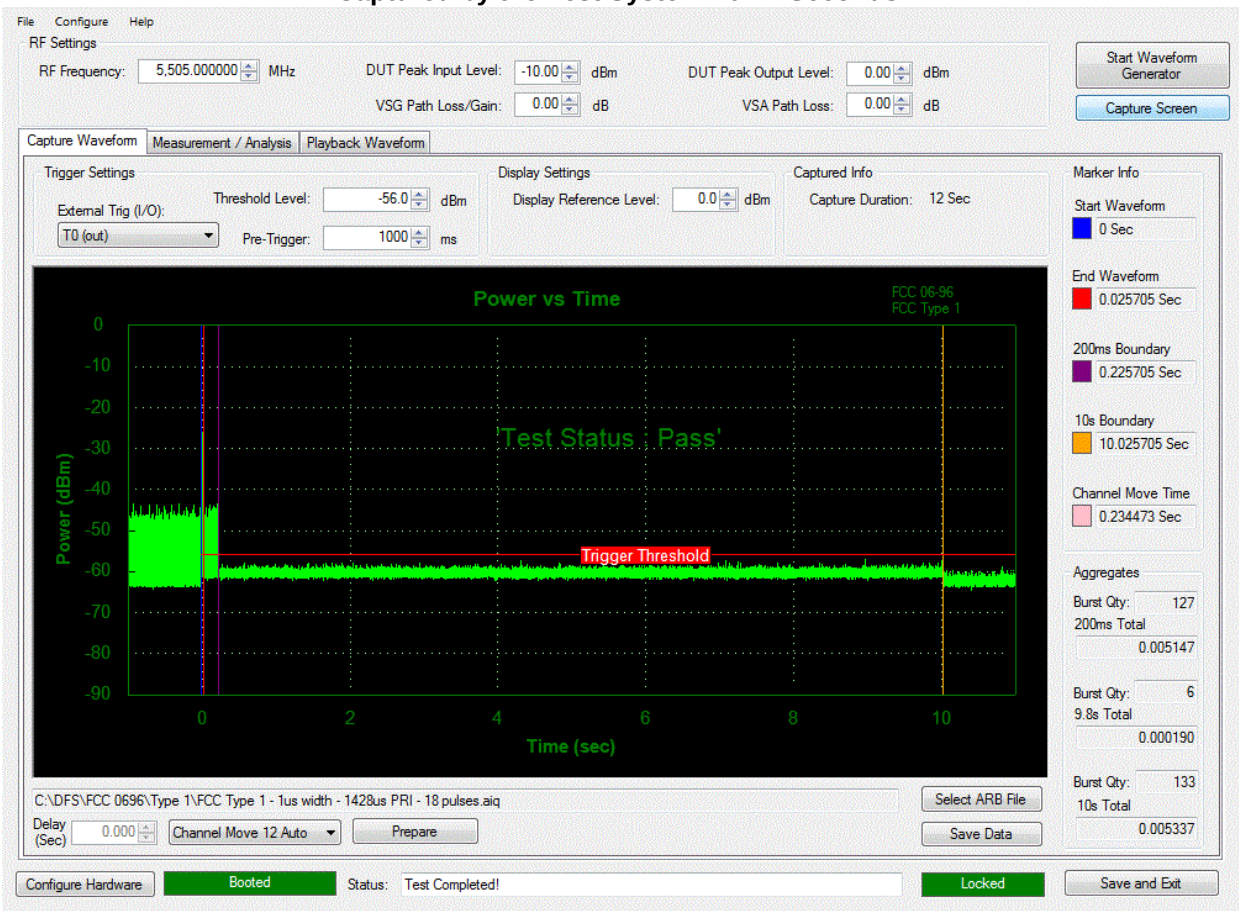
Channel Closing Transmission Time limit 1 second

Channel Move Time limit 10 seconds

1) Channel Closing Transmission Time = 5.337 mSecs (limit 250 mSec)

2) Channel Move Time = 0.2344 Secs (limit is 10 seconds)

Channel Move Time, Channel Closing Transmission Time for Type 1 Radar Captured by the Test System - 0-12 Seconds



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Frequency 5530 MHz Channel 103

The PXI system measures and aggregates the pulses occurring after the end of the radar pulse to determine;-

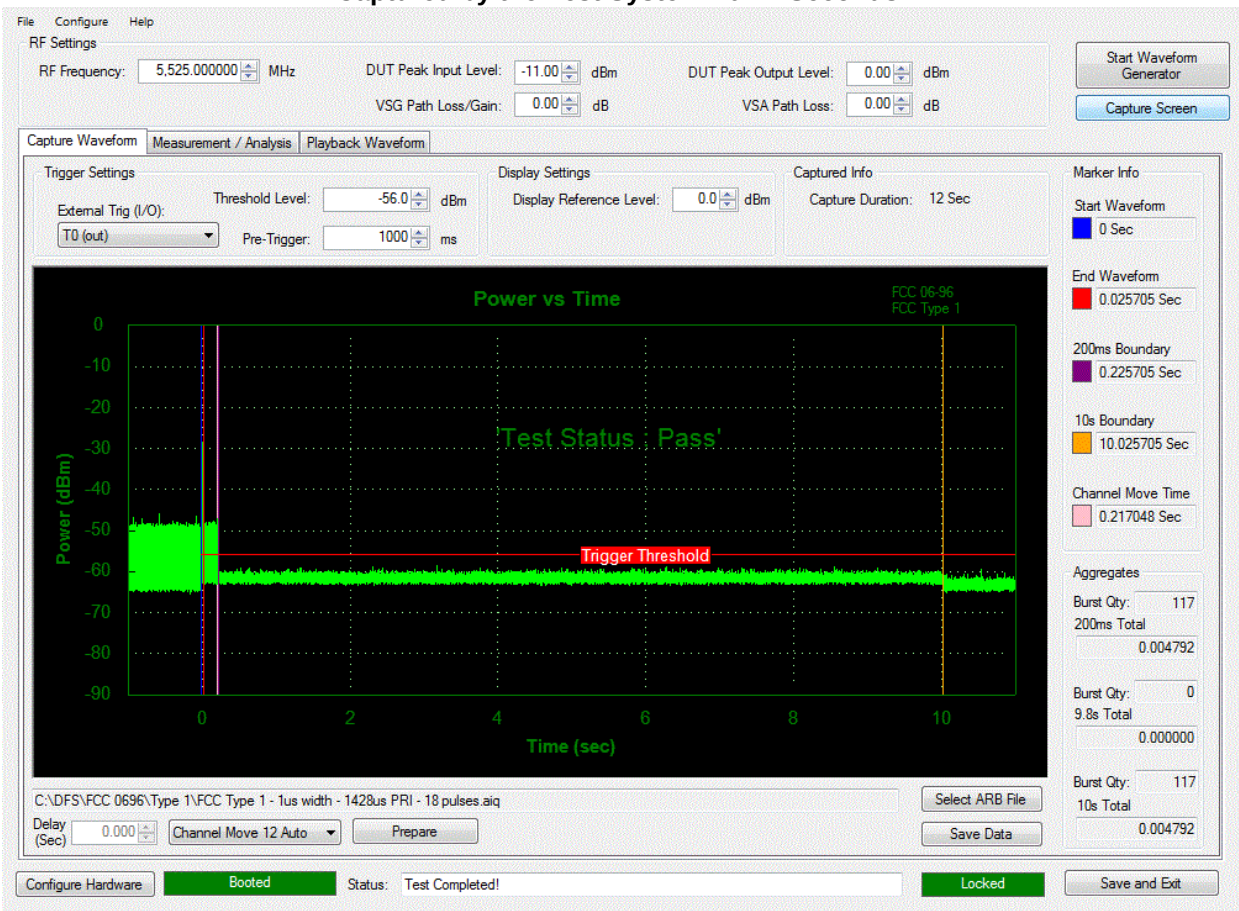
Channel Closing Transmission Time limit 1 second

Channel Move Time limit 10 seconds

1) Channel Closing Transmission Time = **4.792 mSecs (limit 250 mSec)**

2) Channel Move Time = **0.217048 Secs (limit is 10 seconds)**

Channel Move Time, Channel Closing Transmission Time for Type 1 Radar Captured by the Test System - 0-12 Seconds



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9.1.3. Non-Occupancy Period

The EUT is monitored for more than 30 minutes following the channel close/move time to verify no transmissions resume on this Channel. There should be no transmissions on the frequency of interest during the non-occupancy period.

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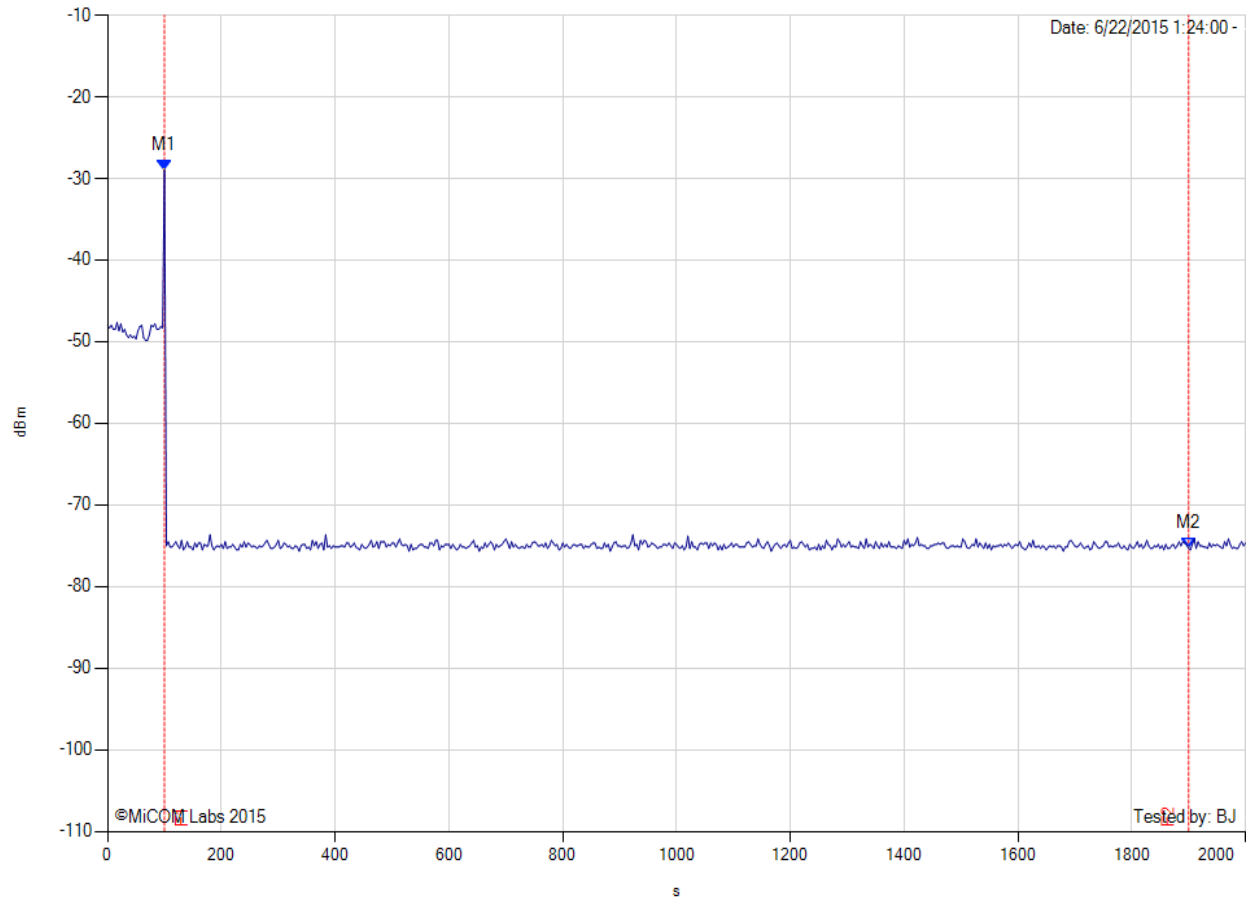
NON-OCCUPANCY PERIOD

Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 2000.0 s

RBW: 1 MHz
VBW: 1 MHz



Analysers Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 100.000 s : -29.000 dBm M2(5495.00 MHz) : 1900.000 s : -75.330 dBm	Channel Frequency: 5500.00 MHz

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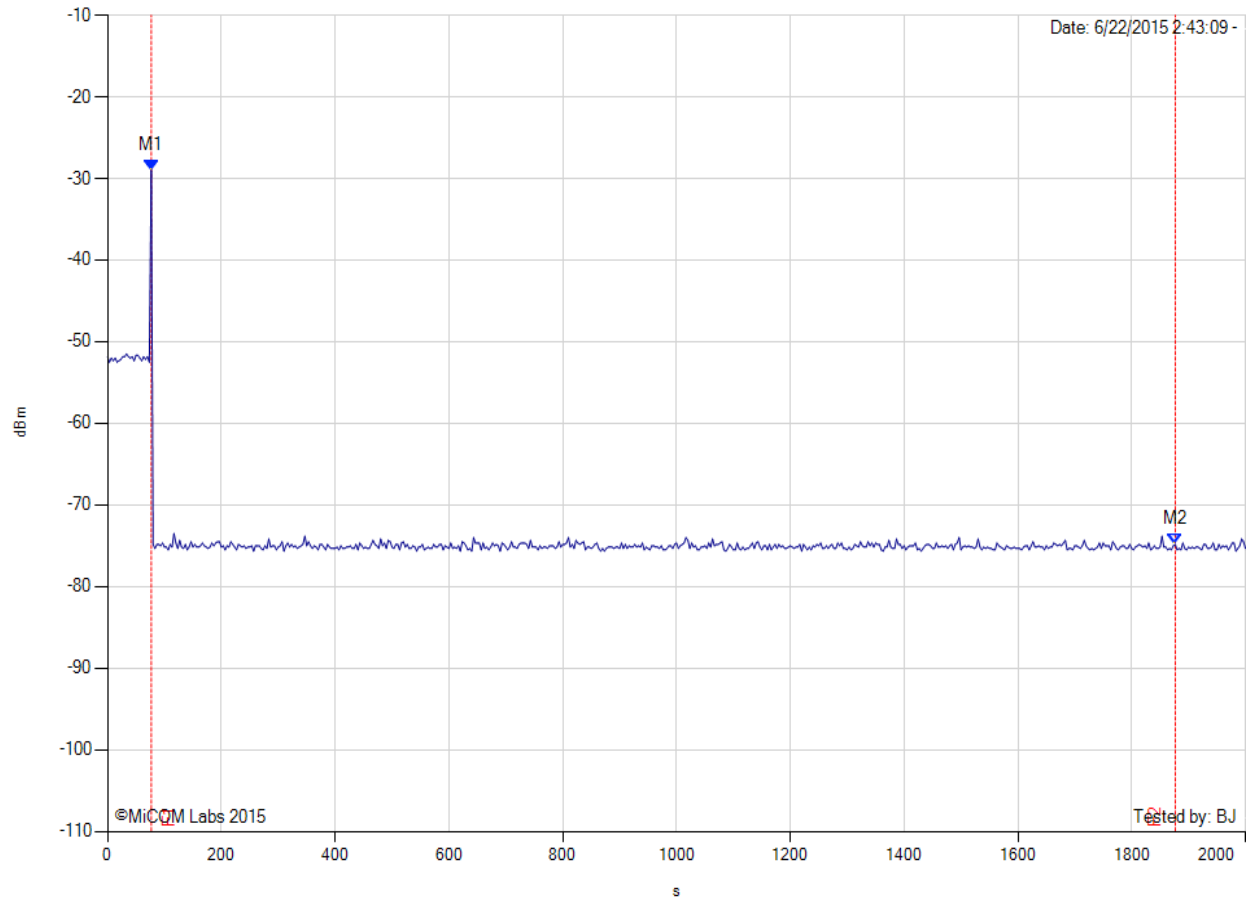
NON-OCCUPANCY PERIOD

Variant: 802.11ac 80, Channel: 5530.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 2000.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5525.00 MHz) : 76.670 s : -29.000 dBm M2(5525.00 MHz) : 1876.670 s : -74.830 dBm	Channel Frequency: 5530.00 MHz

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NON-OCCUPANCY PERIOD

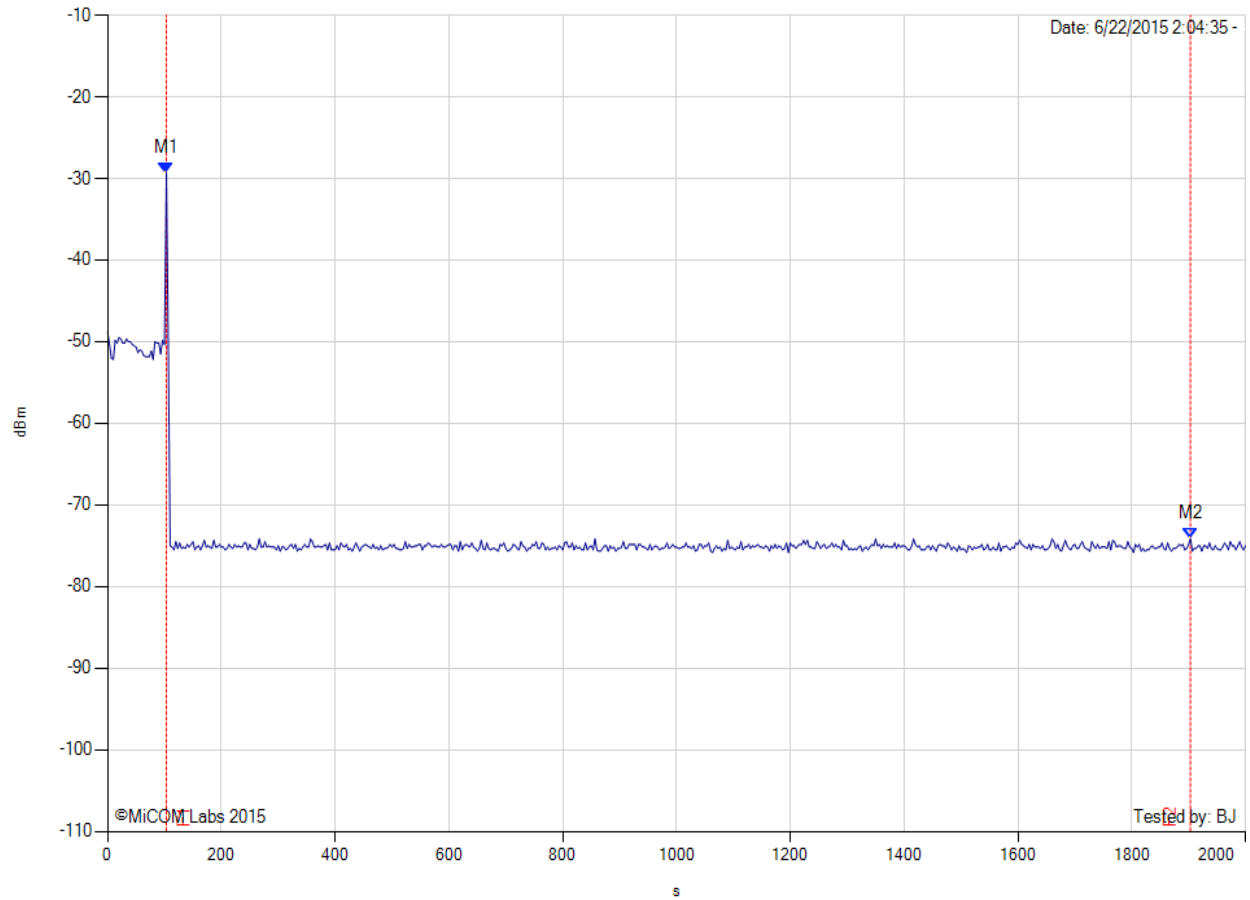


Variant: 802.11n HT40, Channel: 5510.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 2000.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5505.00 MHz) : 103.330 s : -29.330 dBm M2(5505.00 MHz) : 1903.330 s : -74.160 dBm	Channel Frequency: 5510.00 MHz

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9.1.4. Probability of Detection

The steps below define the procedure to determine the minimum percentage of detection when a radar burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The Radar Waveform generator sends the individual waveform for each of the radar Types 1-6. Statistical data will be gathered to determine the ability of the device to detect the radar test waveforms. The device can utilize a test mode to demonstrate when detection occurs to prevent the need to reset the device between trial runs. The percentage of successful detection is calculated by:

$$\text{Total \# of detections} \div \text{Total \# of Trials} \times 100 = \text{Probability of Detection}$$

The Minimum number of trails, minimum percentage of successful detection and the average minimum percentage of successful detection are found in the Radar Test Waveforms section.

The aggregate is the average of the percentage of successful detections of Short Pulse Radar Types 1-4. For example, the following table indicates how to compute the aggregate of percentage of successful detections;

Example - Calculation of Aggregate Percentage

Radar Type	Number of Trials	Number of Successful Detections	Minimum Percentage of Successful Detections
1	30	30	100%
2	30	30	100%
3	30	30	100%
4	30	30	100%
Aggregate (100% + 100% + 100% + 100%) / 4 = 100%			



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Equipment Configuration for Radar Type 0

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.0	700	1428	18	30	28	93.33%	--

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Equipment Configuration for Radar Type 1

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1114	898	59	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1089	918	58	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	1520	658	81	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1193	838	63	1	1	100.00%	DETECTED
1	1567	638	83	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	577	1732	31	1	1	100.00%	DETECTED
1	1111	900	59	1	1	100.00%	DETECTED
1	420	2381	23	1	1	100.00%	DETECTED
1	971	1030	52	1	1	100.00%	DETECTED
1	369	2707	20	1	1	100.00%	DETECTED
1	717	1395	38	1	1	100.00%	DETECTED
1	430	2328	23	1	1	100.00%	DETECTED
1	1250	800	66	1	1	100.00%	DETECTED
1	758	1319	41	1	1	100.00%	DETECTED
1	1484	674	79	1	1	100.00%	DETECTED
1	733	1365	39	1	1	100.00%	DETECTED
1	382	2621	21	1	1	100.00%	DETECTED
1	695	1438	37	1	1	100.00%	DETECTED
1	696	1437	37	1	1	100.00%	DETECTED
1	698	1433	37	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 2

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4405	227	25	1	1	100.00%	DETECTED
1.5	4367	229	25	1	1	100.00%	DETECTED
1.5	4651	215	24	1	1	100.00%	DETECTED
1.8	4608	217	26	1	1	100.00%	DETECTED
1.8	6135	163	29	1	1	100.00%	DETECTED
2.1	4630	216	28	1	1	100.00%	DETECTED
2.2	5435	184	25	1	1	100.00%	DETECTED
2.2	5780	173	23	1	1	100.00%	DETECTED
2.4	5650	177	28	1	1	100.00%	DETECTED
3.0	5714	175	29	1	1	100.00%	DETECTED
3.1	6173	162	27	1	1	100.00%	DETECTED
3.1	4673	214	25	1	1	100.00%	DETECTED
3.4	5263	190	25	1	1	100.00%	DETECTED
3.4	5263	190	27	1	1	100.00%	DETECTED
3.6	4854	206	28	1	1	100.00%	DETECTED
3.8	6024	166	29	1	1	100.00%	DETECTED
3.8	5714	175	23	1	1	100.00%	DETECTED
3.8	5525	181	27	1	1	100.00%	DETECTED
3.9	4464	224	24	1	1	100.00%	DETECTED
4.0	4367	229	24	1	1	100.00%	DETECTED
4.0	5747	174	23	1	1	100.00%	DETECTED
4.1	5025	199	27	1	1	100.00%	DETECTED
4.1	4425	226	24	1	1	100.00%	DETECTED
4.2	5587	179	25	1	1	100.00%	DETECTED
4.3	5102	196	28	1	1	100.00%	DETECTED
4.6	5882	170	25	1	1	100.00%	DETECTED
4.8	4444	225	28	1	1	100.00%	DETECTED
4.9	5556	180	28	1	1	100.00%	DETECTED
5.0	5128	195	23	1	1	100.00%	DETECTED
5.0	5650	177	28	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 3

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
10.0	2347	426	17	1	1	100.00%	DETECTED
10.0	2890	346	18	1	1	100.00%	DETECTED
6.0	2160	463	18	1	1	100.00%	DETECTED
6.1	2985	335	16	1	1	100.00%	DETECTED
6.2	2237	447	17	1	1	100.00%	DETECTED
6.3	2294	436	17	1	1	100.00%	DETECTED
6.3	4292	233	18	1	1	100.00%	DETECTED
6.3	2710	369	18	1	1	100.00%	DETECTED
6.5	2242	446	16	1	1	100.00%	DETECTED
6.6	2278	439	17	1	1	100.00%	DETECTED
6.6	2370	422	17	1	1	100.00%	DETECTED
6.7	3846	260	17	1	1	100.00%	DETECTED
6.9	2755	363	17	1	1	100.00%	DETECTED
7.0	3356	298	17	1	1	100.00%	DETECTED
7.2	3096	323	18	1	1	100.00%	DETECTED
7.5	2770	361	16	1	1	100.00%	DETECTED
7.6	3311	302	18	1	1	100.00%	DETECTED
7.6	2278	439	18	1	1	100.00%	DETECTED
7.6	2513	398	17	1	1	100.00%	DETECTED
8.3	2160	463	17	1	1	100.00%	DETECTED
8.4	3247	308	16	1	1	100.00%	DETECTED
8.5	2037	491	18	1	1	100.00%	DETECTED
8.5	3610	277	16	1	1	100.00%	DETECTED
8.7	4831	207	16	1	1	100.00%	DETECTED
9.0	2132	469	18	1	1	100.00%	DETECTED
9.1	2278	439	18	1	1	100.00%	DETECTED
9.5	2347	426	16	1	1	100.00%	DETECTED
9.7	2188	457	16	1	1	100.00%	DETECTED
9.7	2924	342	18	1	1	100.00%	DETECTED
9.9	2309	433	17	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 4

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
12.1	4739	211	15	1	1	100.00%	DETECTED
12.2	2183	458	12	1	1	100.00%	DETECTED
12.2	2110	474	12	1	1	100.00%	DETECTED
12.4	2451	408	14	1	1	100.00%	DETECTED
12.7	2481	403	14	1	1	100.00%	DETECTED
12.9	3135	319	12	1	1	100.00%	DETECTED
13.0	2049	488	13	1	1	100.00%	DETECTED
13.1	2222	450	13	1	1	100.00%	DETECTED
13.3	3268	306	16	1	1	100.00%	DETECTED
14.0	3472	288	16	1	1	100.00%	DETECTED
14.2	3356	298	16	1	1	100.00%	DETECTED
14.3	2353	425	15	1	1	100.00%	DETECTED
14.6	2169	461	14	1	1	100.00%	DETECTED
15.5	2674	374	13	1	1	100.00%	DETECTED
15.8	2457	407	15	1	1	100.00%	DETECTED
16.4	2262	442	12	1	1	100.00%	DETECTED
16.5	2967	337	15	1	1	100.00%	DETECTED
16.6	2008	498	13	1	1	100.00%	DETECTED
16.8	2865	349	15	1	1	100.00%	DETECTED
16.9	2137	468	14	1	1	100.00%	DETECTED
17.5	4167	240	16	1	1	100.00%	DETECTED
17.5	2985	335	13	1	1	100.00%	DETECTED
18.2	3704	270	14	1	1	100.00%	DETECTED
18.4	2967	337	16	1	1	100.00%	DETECTED
18.8	4032	248	13	1	1	100.00%	DETECTED
18.9	3759	266	12	1	1	100.00%	DETECTED
19.2	2532	395	12	1	1	100.00%	DETECTED
19.5	2315	432	12	1	1	100.00%	DETECTED
19.6	3509	285	16	1	1	100.00%	DETECTED
19.7	2513	398	13	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 5

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1	1	1	100.00%	DETECTED
Type 5 #2	1	1	100.00%	DETECTED
Type 5 #3	1	1	100.00%	DETECTED
Type 5 #4	1	0	0.00%	NOT DETECTED
Type 5 #5	1	1	100.00%	DETECTED
Type 5 #6	1	1	100.00%	DETECTED
Type 5 #7	1	1	100.00%	DETECTED
Type 5 #8	1	0	0.00%	NOT DETECTED
Type 5 #9	1	1	100.00%	DETECTED
Type 5 #10	1	1	100.00%	DETECTED
Type 5 #11	1	1	100.00%	DETECTED
Type 5 #12	1	1	100.00%	DETECTED
Type 5 #13	1	1	100.00%	DETECTED
Type 5 #14	1	1	100.00%	DETECTED
Type 5 #15	1	1	100.00%	DETECTED
Type 5 #16	1	1	100.00%	DETECTED
Type 5 #17	1	1	100.00%	DETECTED
Type 5 #18	1	1	100.00%	DETECTED
Type 5 #19	1	1	100.00%	DETECTED
Type 5 #20	1	1	100.00%	DETECTED
Type 5 #21	1	1	100.00%	DETECTED
Type 5 #22	1	1	100.00%	DETECTED
Type 5 #23	1	1	100.00%	DETECTED
Type 5 #24	1	1	100.00%	DETECTED
Type 5 #25	1	1	100.00%	DETECTED
Type 5 #26	1	1	100.00%	DETECTED
Type 5 #27	1	1	100.00%	DETECTED
Type 5 #28	1	1	100.00%	DETECTED
Type 5 #29	1	1	100.00%	DETECTED
Type 5 #30	1	1	100.00%	DETECTED

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Equipment Configuration for Radar Type 6

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	0	0.00%	NOT DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	1	100.00%	DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	0	0.00%	NOT DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED

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Equipment Configuration for Radar Type 0

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	700	1428	18	30	30	100.00%	See Agg.
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 1

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1114	898	59	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1089	918	58	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	1520	658	81	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1193	838	63	1	1	100.00%	DETECTED
1	1567	638	83	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	577	1732	31	1	1	100.00%	DETECTED
1	1111	900	59	1	1	100.00%	DETECTED
1	420	2381	23	1	1	100.00%	DETECTED
1	971	1030	52	1	1	100.00%	DETECTED
1	369	2707	20	1	1	100.00%	DETECTED
1	717	1395	38	1	1	100.00%	DETECTED
1	430	2328	23	1	1	100.00%	DETECTED
1	1250	800	66	1	1	100.00%	DETECTED
1	758	1319	41	1	1	100.00%	DETECTED
1	1484	674	79	1	1	100.00%	DETECTED
1	733	1365	39	1	1	100.00%	DETECTED
1	382	2621	21	1	1	100.00%	DETECTED
1	695	1438	37	1	1	100.00%	DETECTED
1	696	1437	37	1	1	100.00%	DETECTED
1	698	1433	37	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 2

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4405	227	25	1	1	100.00%	DETECTED
1.5	4367	229	25	1	1	100.00%	DETECTED
1.5	4651	215	24	1	1	100.00%	DETECTED
1.8	4608	217	26	1	1	100.00%	DETECTED
1.8	6135	163	29	1	1	100.00%	DETECTED
2.1	4630	216	28	1	1	100.00%	DETECTED
2.2	5435	184	25	1	1	100.00%	DETECTED
2.2	5780	173	23	1	1	100.00%	DETECTED
2.4	5650	177	28	1	1	100.00%	DETECTED
3.0	5714	175	29	1	1	100.00%	DETECTED
3.1	6173	162	27	1	1	100.00%	DETECTED
3.1	4673	214	25	1	1	100.00%	DETECTED
3.4	5263	190	25	1	1	100.00%	DETECTED
3.4	5263	190	27	1	1	100.00%	DETECTED
3.6	4854	206	28	1	1	100.00%	DETECTED
3.8	6024	166	29	1	1	100.00%	DETECTED
3.8	5714	175	23	1	1	100.00%	DETECTED
3.8	5525	181	27	1	1	100.00%	DETECTED
3.9	4464	224	24	1	1	100.00%	DETECTED
4.0	4367	229	24	1	1	100.00%	DETECTED
4.0	5747	174	23	1	1	100.00%	DETECTED
4.1	5025	199	27	1	1	100.00%	DETECTED
4.1	4425	226	24	1	1	100.00%	DETECTED
4.2	5587	179	25	1	1	100.00%	DETECTED
4.3	5102	196	28	1	1	100.00%	DETECTED
4.6	5882	170	25	1	1	100.00%	DETECTED
4.8	4444	225	28	1	1	100.00%	DETECTED
4.9	5556	180	28	1	1	100.00%	DETECTED
5.0	5128	195	23	1	1	100.00%	DETECTED
5.0	5650	177	28	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 3

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
10.0	2347	426	17	1	1	100.00%	DETECTED
10.0	2890	346	18	1	1	100.00%	DETECTED
6.0	2160	463	18	1	1	100.00%	DETECTED
6.1	2985	335	16	1	1	100.00%	DETECTED
6.2	2237	447	17	1	1	100.00%	DETECTED
6.3	2294	436	17	1	1	100.00%	DETECTED
6.3	4292	233	18	1	1	100.00%	DETECTED
6.3	2710	369	18	1	1	100.00%	DETECTED
6.5	2242	446	16	1	1	100.00%	DETECTED
6.6	2278	439	17	1	1	100.00%	DETECTED
6.6	2370	422	17	1	1	100.00%	DETECTED
6.7	3846	260	17	1	1	100.00%	DETECTED
6.9	2755	363	17	1	1	100.00%	DETECTED
7.0	3356	298	17	1	1	100.00%	DETECTED
7.2	3096	323	18	1	1	100.00%	DETECTED
7.5	2770	361	16	1	1	100.00%	DETECTED
7.6	3311	302	18	1	1	100.00%	DETECTED
7.6	2278	439	18	1	1	100.00%	DETECTED
7.6	2513	398	17	1	1	100.00%	DETECTED
8.3	2160	463	17	1	1	100.00%	DETECTED
8.4	3247	308	16	1	1	100.00%	DETECTED
8.5	2037	491	18	1	1	100.00%	DETECTED
8.5	3610	277	16	1	1	100.00%	DETECTED
8.7	4831	207	16	1	1	100.00%	DETECTED
9.0	2132	469	18	1	1	100.00%	DETECTED
9.1	2278	439	18	1	1	100.00%	DETECTED
9.5	2347	426	16	1	1	100.00%	DETECTED
9.7	2188	457	16	1	1	100.00%	DETECTED
9.7	2924	342	18	1	1	100.00%	DETECTED
9.9	2309	433	17	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 4

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
12.1	4739	211	15	1	1	100.00%	DETECTED
12.2	2183	458	12	1	1	100.00%	DETECTED
12.2	2110	474	12	1	1	100.00%	DETECTED
12.4	2451	408	14	1	1	100.00%	DETECTED
12.7	2481	403	14	1	1	100.00%	DETECTED
12.9	3135	319	12	1	1	100.00%	DETECTED
13.0	2049	488	13	1	1	100.00%	DETECTED
13.1	2222	450	13	1	1	100.00%	DETECTED
13.3	3268	306	16	1	1	100.00%	DETECTED
14.0	3472	288	16	1	1	100.00%	DETECTED
14.2	3356	298	16	1	1	100.00%	DETECTED
14.3	2353	425	15	1	1	100.00%	DETECTED
14.6	2169	461	14	1	1	100.00%	DETECTED
15.5	2674	374	13	1	1	100.00%	DETECTED
15.8	2457	407	15	1	1	100.00%	DETECTED
16.4	2262	442	12	1	1	100.00%	DETECTED
16.5	2967	337	15	1	1	100.00%	DETECTED
16.6	2008	498	13	1	1	100.00%	DETECTED
16.8	2865	349	15	1	1	100.00%	DETECTED
16.9	2137	468	14	1	1	100.00%	DETECTED
17.5	4167	240	16	1	1	100.00%	DETECTED
17.5	2985	335	13	1	1	100.00%	DETECTED
18.2	3704	270	14	1	1	100.00%	DETECTED
18.4	2967	337	16	1	1	100.00%	DETECTED
18.8	4032	248	13	1	1	100.00%	DETECTED
18.9	3759	266	12	1	1	100.00%	DETECTED
19.2	2532	395	12	1	1	100.00%	DETECTED
19.5	2315	432	12	1	1	100.00%	DETECTED
19.6	3509	285	16	1	1	100.00%	DETECTED
19.7	2513	398	13	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 5

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1	1	1	100.00%	DETECTED
Type 5 #2	1	1	100.00%	DETECTED
Type 5 #3	1	0	0.00%	NOT DETECTED
Type 5 #4	1	1	100.00%	DETECTED
Type 5 #5	1	1	100.00%	DETECTED
Type 5 #6	1	1	100.00%	DETECTED
Type 5 #7	1	1	100.00%	DETECTED
Type 5 #8	1	1	100.00%	DETECTED
Type 5 #9	1	1	100.00%	DETECTED
Type 5 #10	1	1	100.00%	DETECTED
Type 5 #11	1	1	100.00%	DETECTED
Type 5 #12	1	1	100.00%	DETECTED
Type 5 #13	1	1	100.00%	DETECTED
Type 5 #14	1	1	100.00%	DETECTED
Type 5 #15	1	1	100.00%	DETECTED
Type 5 #16	1	1	100.00%	DETECTED
Type 5 #17	1	1	100.00%	DETECTED
Type 5 #18	1	0	0.00%	NOT DETECTED
Type 5 #19	1	1	100.00%	DETECTED
Type 5 #20	1	1	100.00%	DETECTED
Type 5 #21	1	1	100.00%	DETECTED
Type 5 #22	1	1	100.00%	DETECTED
Type 5 #23	1	1	100.00%	DETECTED
Type 5 #24	1	1	100.00%	DETECTED
Type 5 #25	1	1	100.00%	DETECTED
Type 5 #26	1	1	100.00%	DETECTED
Type 5 #27	1	1	100.00%	DETECTED
Type 5 #28	1	1	100.00%	DETECTED
Type 5 #29	1	1	100.00%	DETECTED
Type 5 #30	1	0	0.00%	NOT DETECTED

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Equipment Configuration for Radar Type 6

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	1	100.00%	DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	1	100.00%	DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	1	100.00%	DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED

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Equipment Configuration for Radar Type 0

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	700	1428	18	30	30	100.00%	See Agg.
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 1

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1114	898	59	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1089	918	58	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	1520	658	81	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1193	838	63	1	1	100.00%	DETECTED
1	1567	638	83	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	577	1732	31	1	1	100.00%	DETECTED
1	1111	900	59	1	1	100.00%	DETECTED
1	420	2381	23	1	1	100.00%	DETECTED
1	971	1030	52	1	1	100.00%	DETECTED
1	369	2707	20	1	1	100.00%	DETECTED
1	717	1395	38	1	1	100.00%	DETECTED
1	430	2328	23	1	1	100.00%	DETECTED
1	1250	800	66	1	1	100.00%	DETECTED
1	758	1319	41	1	1	100.00%	DETECTED
1	1484	674	79	1	1	100.00%	DETECTED
1	733	1365	39	1	1	100.00%	DETECTED
1	382	2621	21	1	1	100.00%	DETECTED
1	695	1438	37	1	1	100.00%	DETECTED
1	696	1437	37	1	1	100.00%	DETECTED
1	698	1433	37	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 2

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4405	227	25	1	1	100.00%	DETECTED
1.5	4367	229	25	1	1	100.00%	DETECTED
1.5	4651	215	24	1	1	100.00%	DETECTED
1.8	4608	217	26	1	1	100.00%	DETECTED
1.8	6135	163	29	1	1	100.00%	DETECTED
2.1	4630	216	28	1	1	100.00%	DETECTED
2.2	5435	184	25	1	1	100.00%	DETECTED
2.2	5780	173	23	1	1	100.00%	DETECTED
2.4	5650	177	28	1	1	100.00%	DETECTED
3.0	5714	175	29	1	1	100.00%	DETECTED
3.1	6173	162	27	1	1	100.00%	DETECTED
3.1	4673	214	25	1	1	100.00%	DETECTED
3.4	5263	190	25	1	1	100.00%	DETECTED
3.4	5263	190	27	1	1	100.00%	DETECTED
3.6	4854	206	28	1	1	100.00%	DETECTED
3.8	6024	166	29	1	1	100.00%	DETECTED
3.8	5714	175	23	1	1	100.00%	DETECTED
3.8	5525	181	27	1	1	100.00%	DETECTED
3.9	4464	224	24	1	1	100.00%	DETECTED
4.0	4367	229	24	1	1	100.00%	DETECTED
4.0	5747	174	23	1	1	100.00%	DETECTED
4.1	5025	199	27	1	1	100.00%	DETECTED
4.1	4425	226	24	1	1	100.00%	DETECTED
4.2	5587	179	25	1	1	100.00%	DETECTED
4.3	5102	196	28	1	1	100.00%	DETECTED
4.6	5882	170	25	1	1	100.00%	DETECTED
4.8	4444	225	28	1	1	100.00%	DETECTED
4.9	5556	180	28	1	1	100.00%	DETECTED
5.0	5128	195	23	1	1	100.00%	DETECTED
5.0	5650	177	28	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 3

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
10.0	2347	426	17	1	1	100.00%	DETECTED
10.0	2890	346	18	1	1	100.00%	DETECTED
6.0	2160	463	18	1	1	100.00%	DETECTED
6.1	2985	335	16	1	1	100.00%	DETECTED
6.2	2237	447	17	1	1	100.00%	DETECTED
6.3	2294	436	17	1	1	100.00%	DETECTED
6.3	4292	233	18	1	1	100.00%	DETECTED
6.3	2710	369	18	1	1	100.00%	DETECTED
6.5	2242	446	16	1	1	100.00%	DETECTED
6.6	2278	439	17	1	1	100.00%	DETECTED
6.6	2370	422	17	1	1	100.00%	DETECTED
6.7	3846	260	17	1	1	100.00%	DETECTED
6.9	2755	363	17	1	1	100.00%	DETECTED
7.0	3356	298	17	1	1	100.00%	DETECTED
7.2	3096	323	18	1	1	100.00%	DETECTED
7.5	2770	361	16	1	1	100.00%	DETECTED
7.6	3311	302	18	1	1	100.00%	DETECTED
7.6	2278	439	18	1	1	100.00%	DETECTED
7.6	2513	398	17	1	1	100.00%	DETECTED
8.3	2160	463	17	1	1	100.00%	DETECTED
8.4	3247	308	16	1	1	100.00%	DETECTED
8.5	2037	491	18	1	1	100.00%	DETECTED
8.5	3610	277	16	1	1	100.00%	DETECTED
8.7	4831	207	16	1	1	100.00%	DETECTED
9.0	2132	469	18	1	1	100.00%	DETECTED
9.1	2278	439	18	1	1	100.00%	DETECTED
9.5	2347	426	16	1	1	100.00%	DETECTED
9.7	2188	457	16	1	1	100.00%	DETECTED
9.7	2924	342	18	1	1	100.00%	DETECTED
9.9	2309	433	17	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 4

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
12.1	4739	211	15	1	1	100.00%	DETECTED
12.2	2183	458	12	1	1	100.00%	DETECTED
12.2	2110	474	12	1	1	100.00%	DETECTED
12.4	2451	408	14	1	1	100.00%	DETECTED
12.7	2481	403	14	1	1	100.00%	DETECTED
12.9	3135	319	12	1	1	100.00%	DETECTED
13.0	2049	488	13	1	1	100.00%	DETECTED
13.1	2222	450	13	1	1	100.00%	DETECTED
13.3	3268	306	16	1	1	100.00%	DETECTED
14.0	3472	288	16	1	1	100.00%	DETECTED
14.2	3356	298	16	1	1	100.00%	DETECTED
14.3	2353	425	15	1	1	100.00%	DETECTED
14.6	2169	461	14	1	1	100.00%	DETECTED
15.5	2674	374	13	1	1	100.00%	DETECTED
15.8	2457	407	15	1	1	100.00%	DETECTED
16.4	2262	442	12	1	1	100.00%	DETECTED
16.5	2967	337	15	1	1	100.00%	DETECTED
16.6	2008	498	13	1	1	100.00%	DETECTED
16.8	2865	349	15	1	1	100.00%	DETECTED
16.9	2137	468	14	1	1	100.00%	DETECTED
17.5	4167	240	16	1	1	100.00%	DETECTED
17.5	2985	335	13	1	1	100.00%	DETECTED
18.2	3704	270	14	1	1	100.00%	DETECTED
18.4	2967	337	16	1	1	100.00%	DETECTED
18.8	4032	248	13	1	1	100.00%	DETECTED
18.9	3759	266	12	1	1	100.00%	DETECTED
19.2	2532	395	12	1	1	100.00%	DETECTED
19.5	2315	432	12	1	1	100.00%	DETECTED
19.6	3509	285	16	1	1	100.00%	DETECTED
19.7	2513	398	13	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 5

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injectons	Detections	Detection Rate	Result
Type 5 #1	1	1	100.00%	DETECTED
Type 5 #2	1	1	100.00%	DETECTED
Type 5 #3	1	1	100.00%	DETECTED
Type 5 #4	1	0	0.00%	NOT DETECTED
Type 5 #5	1	1	100.00%	DETECTED
Type 5 #6	1	1	100.00%	DETECTED
Type 5 #7	1	1	100.00%	DETECTED
Type 5 #8	1	1	100.00%	DETECTED
Type 5 #9	1	1	100.00%	DETECTED
Type 5 #10	1	1	100.00%	DETECTED
Type 5 #11	1	1	100.00%	DETECTED
Type 5 #12	1	1	100.00%	DETECTED
Type 5 #13	1	1	100.00%	DETECTED
Type 5 #14	1	1	100.00%	DETECTED
Type 5 #15	1	1	100.00%	DETECTED
Type 5 #16	1	1	100.00%	DETECTED
Type 5 #17	1	1	100.00%	DETECTED
Type 5 #18	1	1	100.00%	DETECTED
Type 5 #19	1	1	100.00%	DETECTED
Type 5 #20	1	1	100.00%	DETECTED
Type 5 #21	1	1	100.00%	DETECTED
Type 5 #22	1	1	100.00%	DETECTED
Type 5 #23	1	1	100.00%	DETECTED
Type 5 #24	1	1	100.00%	DETECTED
Type 5 #25	1	0	0.00%	NOT DETECTED
Type 5 #26	1	1	100.00%	DETECTED
Type 5 #27	1	0	0.00%	NOT DETECTED
Type 5 #28	1	1	100.00%	DETECTED
Type 5 #29	1	1	100.00%	DETECTED
Type 5 #30	1	1	100.00%	DETECTED

Click on the link to view the injected radar signature profile

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Equipment Configuration for Radar Type 6

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	1	100.00%	DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	0	0.00%	NOT DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	1	100.00%	DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED

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9.1.5. Detection Bandwidth

To determine the equipment Detection Bandwidth for each applicable operational mode a single burst of the short pulse radar Type 0 was produced at the appropriate power level. The EUT was set up as a standalone device (no associated Client or Master, as appropriate) and no traffic. Frame based systems will be set to a talk/listen ratio reflecting the worst case (maximum) that is user configurable during this test.

To determine the actual receiver bandwidth a single radar burst is generated for a minimum of 10 trials and the response of the EUT noted. The EUT must detect the Radar Waveform until it fails to detect, at this point testing is stopped and the frequency noted.

Starting from the actual channel center frequency the radar frequency is increased in 1 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The highest frequency at which detection is greater than or equal to 90% is denoted as FH. Note for the higher bandwidths ac-80 etc the 1 MHz step size can be increased.

The radar frequency is decreased in 1 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The lowest frequency at which detection is greater than or equal to 90% is denoted as FL.

The U-NII Detection Bandwidth is calculated as follows:
$$\text{U-NII Detection Bandwidth} = \text{FH} - \text{FL}$$

The U-NII Detection Bandwidth must meet the U-NII Detection Bandwidth criterion specified. Otherwise, the UUT does not comply with DFS requirements. This is essential to ensure that the UUT is capable of detecting Radar Waveforms across the same frequency spectrum that contains the significant energy from the system. In the case that the U-NII Detection Bandwidth is greater than or equal to the 99% power bandwidth for the measured FH and FL, the test can be truncated and the U-NII Detection Bandwidth can be reported as the measured FH and FL



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Equipment Configuration for Detection Bandwidth

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:		Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5489 MHz				
5490 MHz				
5491 MHz	10	0		
5492 MHz	10	10	100.00%	Pass
5493 MHz	10	10	100.00%	Pass
5494 MHz	10	10	100.00%	Pass
5495 MHz	10	10	100.00%	Pass
5496 MHz	10	10	100.00%	Pass
5497 MHz	10	10	100.00%	Pass
5498 MHz	10	10	100.00%	Pass
5499 MHz	10	10	100.00%	Pass
5500	10	10	100.00%	Pass
5501 MHz	10	10	100.00%	Pass
5502 MHz	10	10	100.00%	Pass
5503 MHz	10	10	100.00%	Pass
5504 MHz	10	10	100.00%	Pass
5505 MHz	10	10	100.00%	Pass
5506 MHz	10	10	100.00%	Pass
5507 MHz	10	10	100.00%	Pass
5508 MHz	10	10	100.00%	Pass
5509 MHz	10	0		
5510 MHz				
5511 MHz				

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Equipment Configuration for Detection Bandwidth

Variant:	802.11ac 80	Duty Cycle (%):	35.00
Data Rate:	29.30	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:		Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5489 MHz				
5490 MHz				
5491 MHz	10	0		
5492 MHz	10	10	100.00%	Pass
5493 MHz	10	10	100.00%	Pass
5494 MHz	10	10	100.00%	Pass
5495 MHz	10	10	100.00%	Pass
5496 MHz	10	10	100.00%	Pass
5497 MHz	10	10	100.00%	Pass
5498 MHz	10	10	100.00%	Pass
5499 MHz	10	10	100.00%	Pass
5500 MHz	10	10	100.00%	Pass
5501 MHz	10	10	100.00%	Pass
5502 MHz	10	10	100.00%	Pass
5503 MHz	10	10	100.00%	Pass
5504 MHz	10	10	100.00%	Pass
5505 MHz	10	10	100.00%	Pass
5506 MHz	10	10	100.00%	Pass
5507 MHz	10	10	100.00%	Pass
5508 MHz	10	10	100.00%	Pass
5509 MHz	10	10	100.00%	Pass
5510 MHz	10	10	100.00%	Pass
5511 MHz	10	10	100.00%	Pass
5512 MHz	10	10	100.00%	Pass
5513 MHz	10	10	100.00%	Pass
5514 MHz	10	10	100.00%	Pass
5515 MHz	10	10	100.00%	Pass
5516 MHz	10	10	100.00%	Pass
5517 MHz	10	10	100.00%	Pass
5518 MHz	10	10	100.00%	Pass
5519 MHz	10	10	100.00%	Pass
5520 MHz	10	10	100.00%	Pass
5521 MHz	10	10	100.00%	Pass

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5522 MHz	10	10	100.00%	Pass
5523 MHz	10	10	100.00%	Pass
5524 MHz	10	10	100.00%	Pass
5525 MHz	10	10	100.00%	Pass
5526 MHz	10	10	100.00%	Pass
5527 MHz	10	10	100.00%	Pass
5528 MHz	10	10	100.00%	Pass
5529 MHz	10	10	100.00%	Pass
5530	10	10	100.00%	Pass
5531 MHz	10	10	100.00%	Pass
5532 MHz	10	10	100.00%	Pass
5533 MHz	10	10	100.00%	Pass
5534 MHz	10	10	100.00%	Pass
5535 MHz	10	10	100.00%	Pass
5536 MHz	10	10	100.00%	Pass
5537 MHz	10	10	100.00%	Pass
5538 MHz	10	10	100.00%	Pass
5539 MHz	10	10	100.00%	Pass
5540 MHz	10	10	100.00%	Pass
5541 MHz	10	10	100.00%	Pass
5542 MHz	10	10	100.00%	Pass
5543 MHz	10	10	100.00%	Pass
5544 MHz	10	10	100.00%	Pass
5545 MHz	10	10	100.00%	Pass
5546 MHz	10	10	100.00%	Pass
5547 MHz	10	10	100.00%	Pass
5548 MHz	10	10	100.00%	Pass
5549 MHz	10	10	100.00%	Pass
5550 MHz	10	10	100.00%	Pass
5551 MHz	10	10	100.00%	Pass
5552 MHz	10	10	100.00%	Pass
5553 MHz	10	10	100.00%	Pass
5554 MHz	10	10	100.00%	Pass
5555 MHz	10	10	100.00%	Pass
5556 MHz	10	10	100.00%	Pass
5557 MHz	10	10	100.00%	Pass
5558 MHz	10	10	100.00%	Pass
5559 MHz	10	10	100.00%	Pass
5560 MHz	10	10	100.00%	Pass
5561 MHz	10	10	100.00%	Pass
5562 MHz	10	10	100.00%	Pass
5563 MHz	10	10	100.00%	Pass
5564 MHz	10	10	100.00%	Pass
5565 MHz	10	10	100.00%	Pass

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5566 MHz	10	10	100.00%	Pass
5567 MHz	10	10	100.00%	Pass
5568 MHz	10	10	100.00%	Pass
5569 MHz	10	0		
5570 MHz				
5571 MHz				

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Equipment Configuration for Detection Bandwidth

Variant:	802.11n HT40	Duty Cycle (%):	35.00
Data Rate:	13.5	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:		Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5488 MHz				
5489 MHz				
5490 MHz				
5491 MHz	10	0		
5492 MHz	10	10	100.00%	Pass
5493 MHz	10	10	100.00%	Pass
5494 MHz	10	10	100.00%	Pass
5495 MHz	10	10	100.00%	Pass
5496 MHz	10	10	100.00%	Pass
5497 MHz	10	10	100.00%	Pass
5498 MHz	10	10	100.00%	Pass
5499 MHz	10	10	100.00%	Pass
5500 MHz	10	10	100.00%	Pass
5501 MHz	10	10	100.00%	Pass
5502 MHz	10	10	100.00%	Pass
5503 MHz	10	10	100.00%	Pass
5504 MHz	10	10	100.00%	Pass
5505 MHz	10	10	100.00%	Pass
5506 MHz	10	10	100.00%	Pass
5507 MHz	10	10	100.00%	Pass
5508 MHz	10	10	100.00%	Pass
5509 MHz	10	10	100.00%	Pass
5510	10	0		
5511 MHz	10	10	100.00%	Pass
5512 MHz	10	10	100.00%	Pass
5513 MHz	10	10	100.00%	Pass
5514 MHz	10	10	100.00%	Pass
5515 MHz	10	10	100.00%	Pass
5516 MHz	10	10	100.00%	Pass
5517 MHz	10	10	100.00%	Pass
5518 MHz	10	10	100.00%	Pass
5519 MHz	10	10	100.00%	Pass
5520 MHz	10	10	100.00%	Pass

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5521 MHz	10	10	100.00%	Pass
5522 MHz	10	10	100.00%	Pass
5523 MHz	10	10	100.00%	Pass
5524 MHz	10	10	100.00%	Pass
5525 MHz	10	10	100.00%	Pass
5526 MHz	10	10	100.00%	Pass
5527 MHz	10	10	100.00%	Pass
5528 MHz	10	10	100.00%	Pass
5529 MHz	10	0		
5530 MHz				
5531 MHz				

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9.2. Monitor Ports

9.2.1. Channel Availability Check

9.2.1.4. Power-On CAC

This test verifies that the EUT does not emit pulse, control, or data signals on the test Channel until the power-up sequence has been completed and the U-NII device checks for Radar Waveforms for one minute on the test Channel. This test does not use any Radar Waveforms.

The EUT is instructed to power up at the appropriate center frequency. The spectrum analyzer is set on zero span with a 1 MHz resolution bandwidth and 260 second sweep time to monitor the RF output of the EUT during power up. The analyzer's sweep will be started the same time power is applied to the U-NII device.

The EUT should not transmit any pulse or data transmissions until at least 1 minute after the completion of the power-on cycle.

The first red vertical line shown on the following plot denotes the instant when the EUT starts its power-up sequence i.e. T0 (as defined within the FCC's KDB 905462 D02 Section 4.1). The power-up reference T0 is determined by the time it takes for the EUT to start "beaconing" i.e. initial beacon – 60 secs = end of power-up.

The Channel Availability Check Time commences at instant T0 and will end no sooner than T0 + 60 seconds. T0 + 60 is indicated on the plot by the second vertical line.



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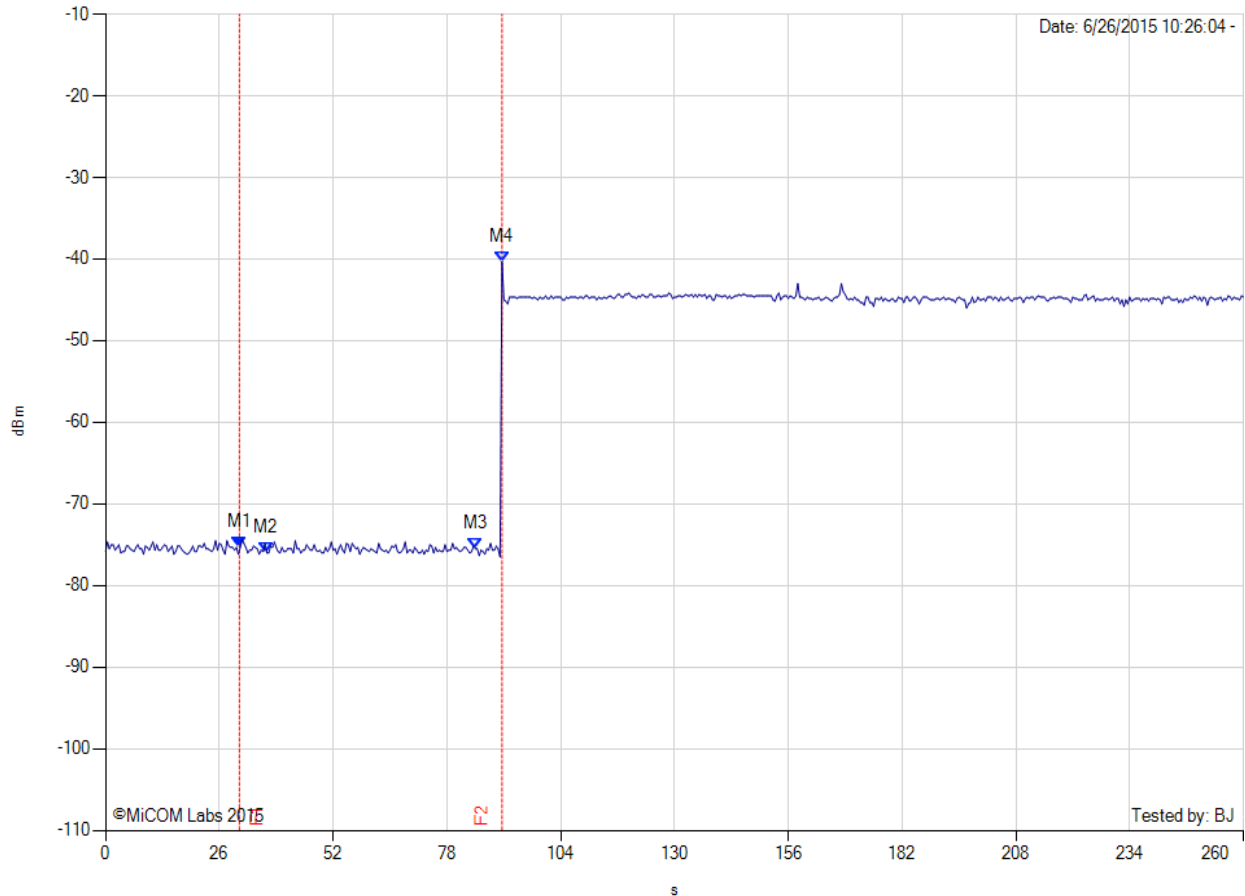
POWER-ON CAC

Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 30.570 s : -75.330 dBm M2(5495.00 MHz) : 36.570 s : -76.000 dBm M3(5495.00 MHz) : 84.570 s : -75.500 dBm M4(5495.00 MHz) : 90.570 s : -40.330 dBm	Channel Frequency: 5500.00 MHz

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9.2.1.5. Beginning CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold +1dB (Ref Section 9.2) occurs at the beginning of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at T0 (first red vertical marker line on the plot).

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

T0 + 60 is indicated on the plot by the second vertical line.



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BEGINNING CAC

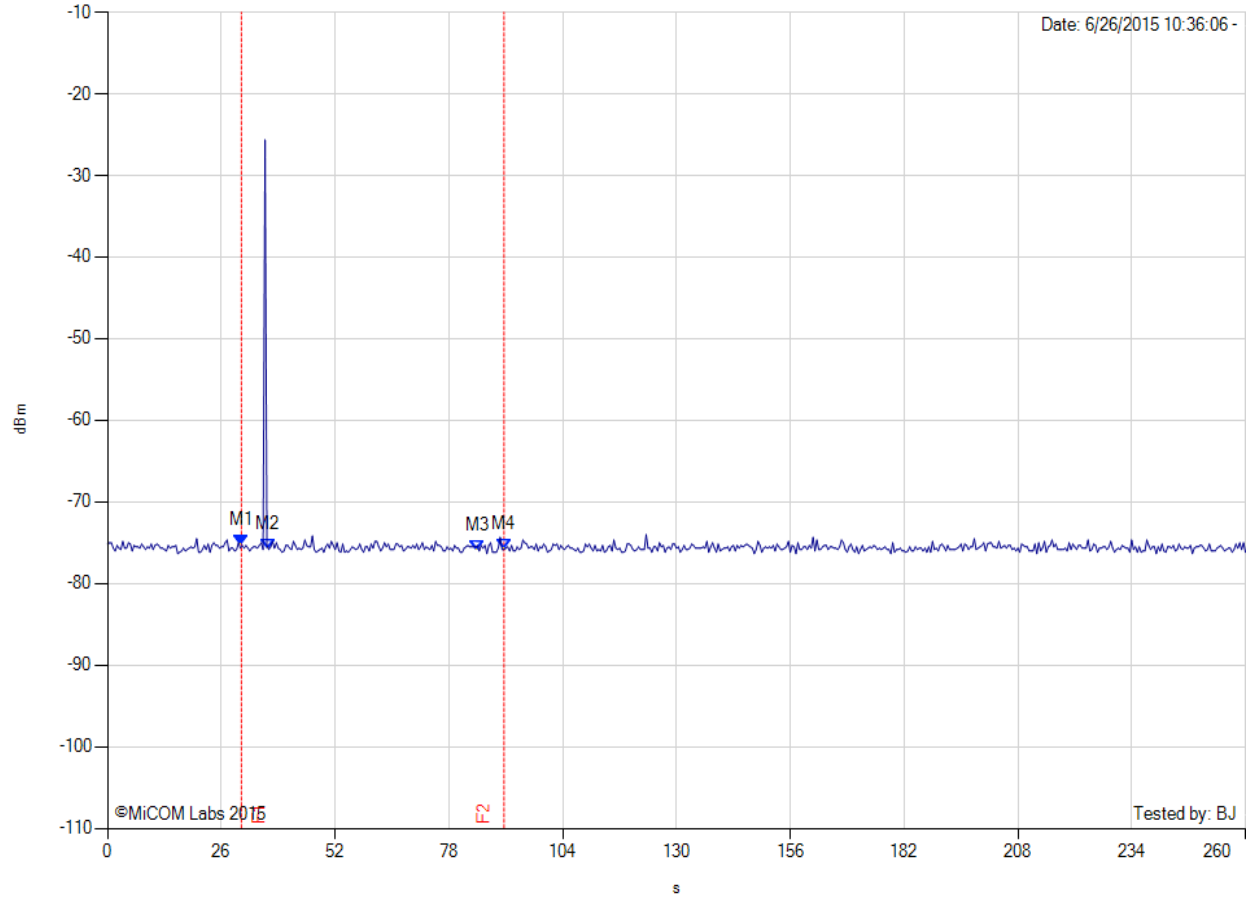


Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 30.570 s : -75.330 dBm M2(5495.00 MHz) : 36.570 s : -75.830 dBm M3(5495.00 MHz) : 84.570 s : -76.000 dBm M4(5495.00 MHz) : 90.570 s : -75.830 dBm	Channel Frequency: 5500.00 MHz

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9.2.1.6. End CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold occurs at the end of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at T0 + 54 seconds. The window will commence at marker 3 and end at the red time line T2 (T0 + 60 secs)

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

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END CAC

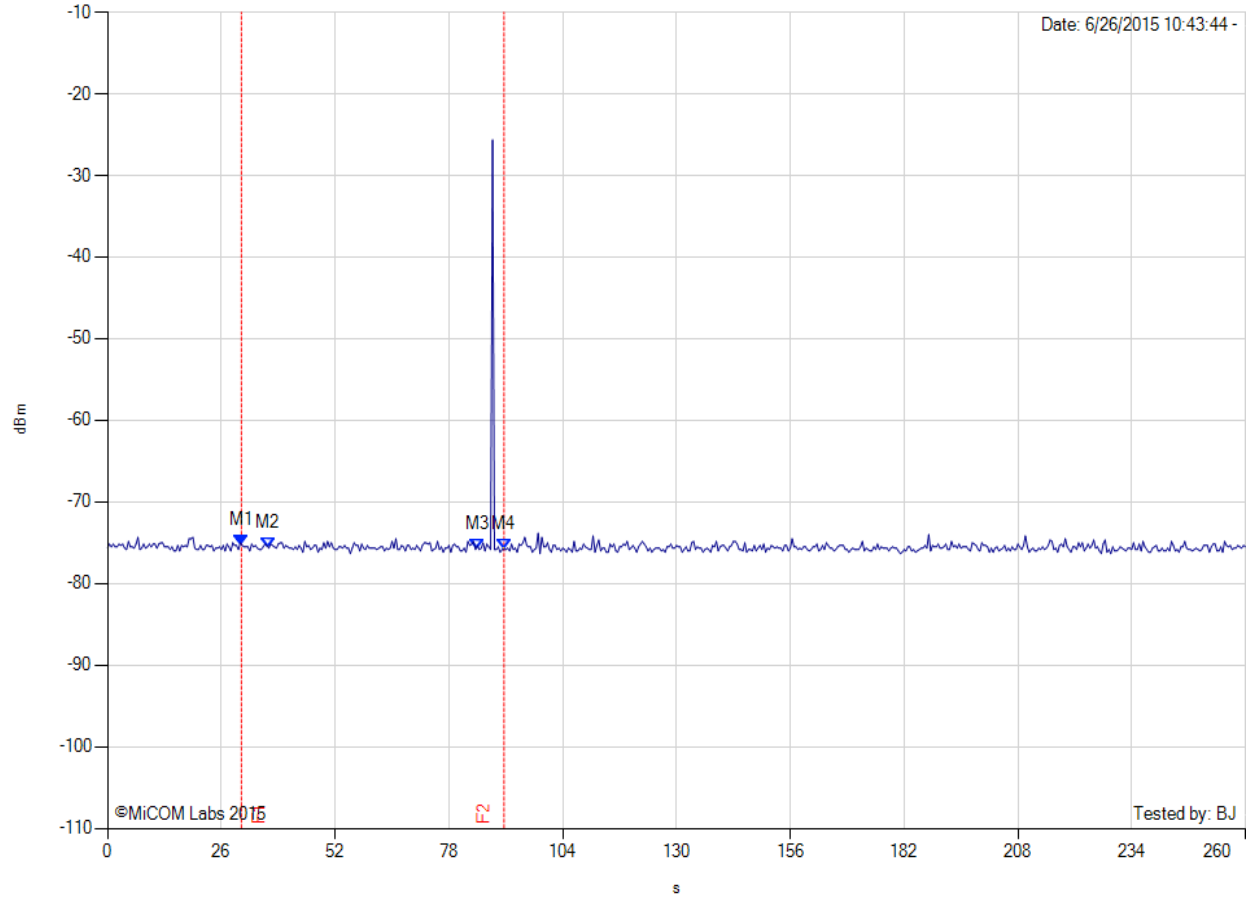


Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 260.0 s

RBW: 1 MHz
VBW: 1 MHz



Analyser Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 30.570 s : -75.330 dBm M2(5495.00 MHz) : 36.570 s : -75.660 dBm M3(5495.00 MHz) : 84.570 s : -75.830 dBm M4(5495.00 MHz) : 90.570 s : -75.830 dBm	Channel Frequency: 5500.00 MHz

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9.2.2. Channel Close / Transmission Time

The steps below define the procedure to determine the above mentioned parameters when a radar Burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The EUT will be associated with a support U-NII device in order to setup an appropriate transmission media in accordance with the FCC requirements.

Channel Closing Transmission Time and Channel Move Time - Measurement

The test system was set-up to capture all transmission data for access point events above a threshold level of -50 dBm. The test equipment time stamps all captured events.

A Type 0 waveform was introduced to the EUT, from which a 12 second transmission record was digitally captured. The start of the Type 0 radar waveform is indicated in the test result plot as "Start Waveform", the end of the waveform is indicated as "End waveform".

Channel Closing Transmission Time, and the Channel Move Time start immediately after the last radar pulse is transmitted.

The aggregate of all pulses seen after the end of the radar injection are measured as the "Channel Closing Transmission time".

The last EUT activity after the end of the radar pulse is identified and used to determine the "Channel Move Time"



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Frequency 5500 MHz Channel 100

The PXI system measures and aggregates the pulses occurring after the end of the radar pulse to determine:-

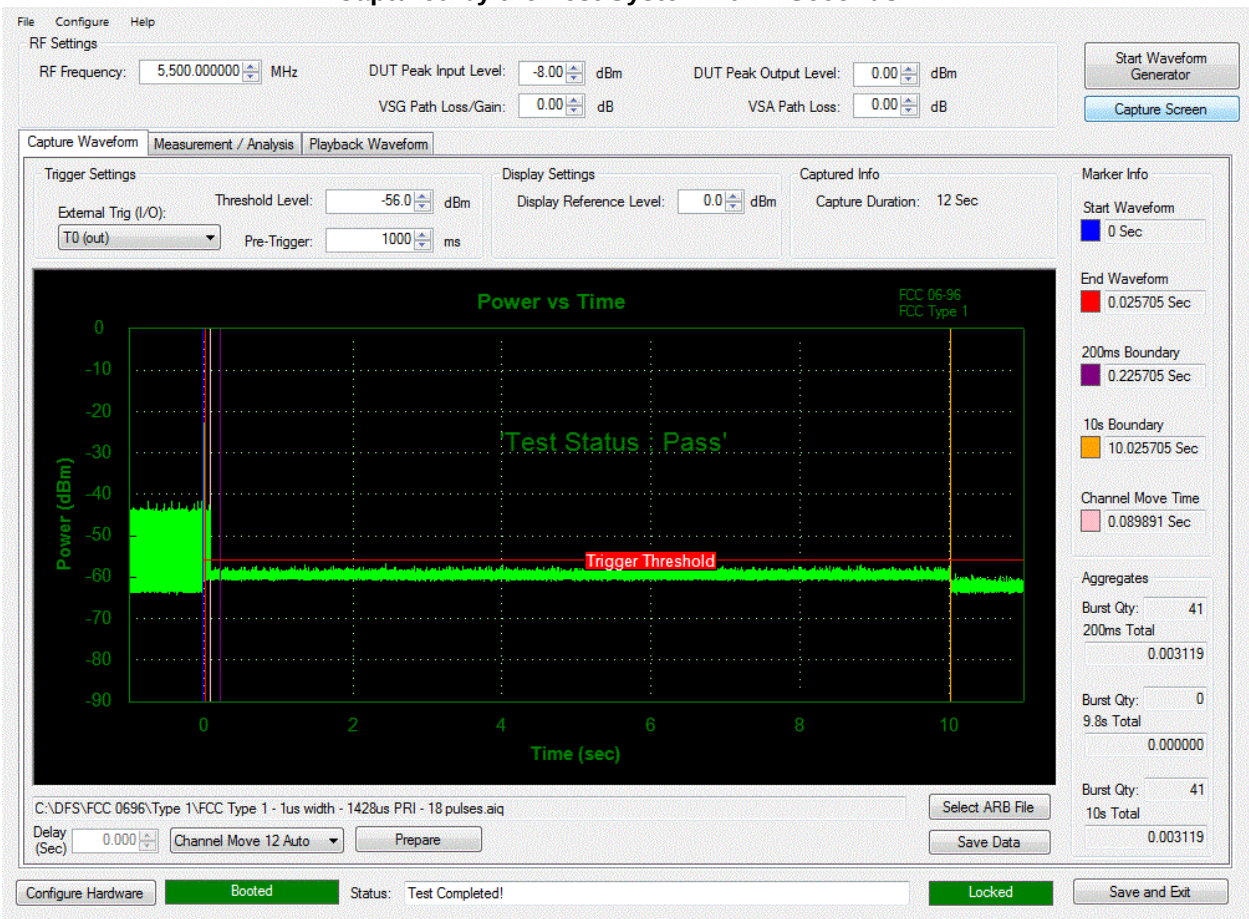
Channel Closing Transmission Time limit 1 second

Channel Move Time limit 10 seconds

1) Channel Closing Transmission Time = 0.3119 mSecs (limit 250 mSec)

2) Channel Move Time = 0.89891 Secs (limit is 10 seconds)

Channel Move Time, Channel Closing Transmission Time for Type 1 Radar Captured by the Test System - 0-12 Seconds



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9.2.3. Non-Occupancy Period

The EUT is monitored for more than 30 minutes following the channel close/move time to verify no transmissions resume on this Channel. There should be no transmissions on the frequency of interest during the non-occupancy period.

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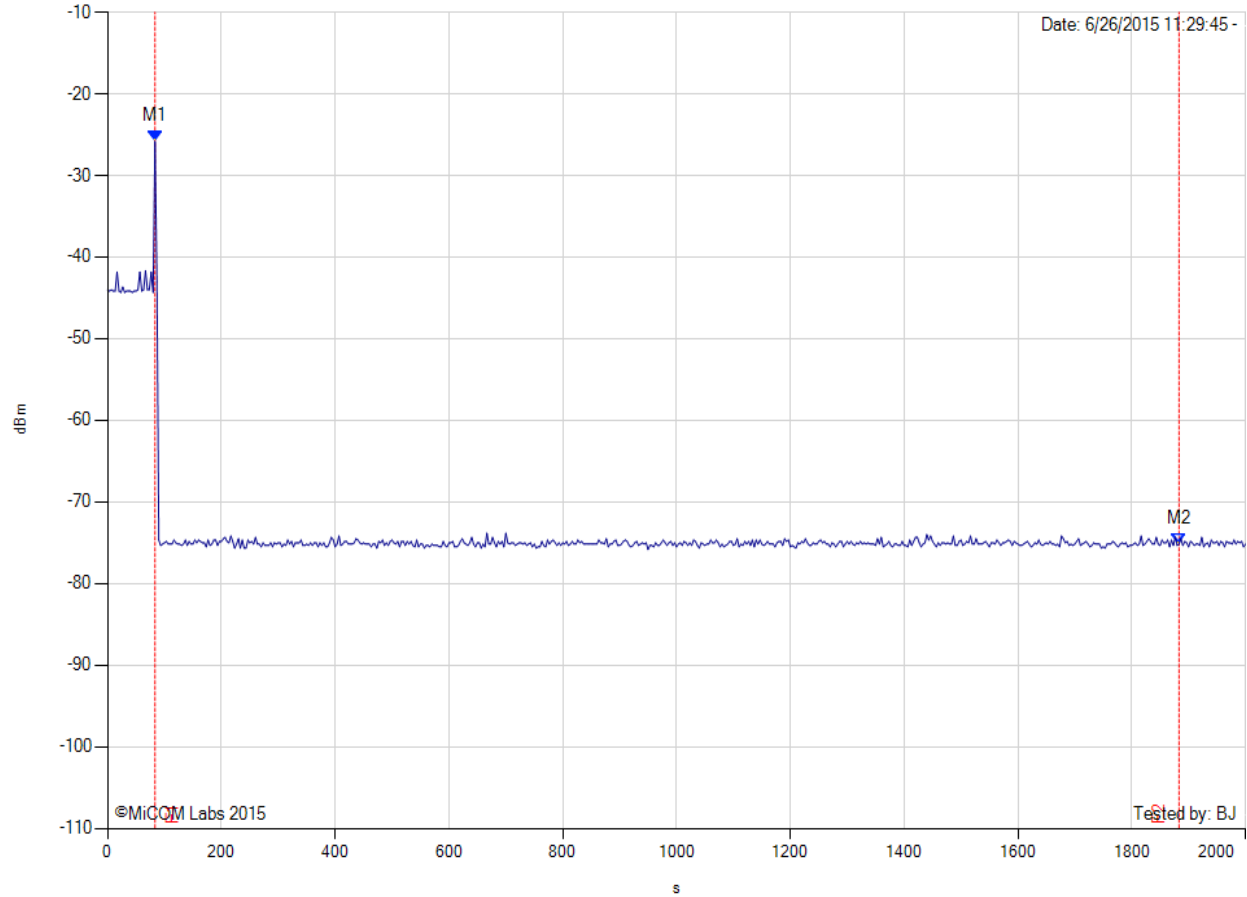
NON-OCCUPANCY PERIOD

Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 18, Duty Cycle : 35.00%, Antenna Gain: 4.00 dBi

Ref Level: -10.00 DBM
0.0 dB Offset

Sweep Time: 2000.0 s

RBW: 1 MHz
VBW: 1 MHz



Analysers Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1(5495.00 MHz) : 83.330 s : -25.830 dBm M2(5495.00 MHz) : 1883.330 s : -75.160 dBm	Channel Frequency: 5500.00 MHz

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9.2.4. Probability of Detection

The steps below define the procedure to determine the minimum percentage of detection when a radar burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The Radar Waveform generator sends the individual waveform for each of the radar Types 1-6. Statistical data will be gathered to determine the ability of the device to detect the radar test waveforms. The device can utilize a test mode to demonstrate when detection occurs to prevent the need to reset the device between trial runs. The percentage of successful detection is calculated by:

$\text{Total \# of detections} \div \text{Total \# of Trials} \times 100 = \text{Probability of Detection}$

The Minimum number of trails, minimum percentage of successful detection and the average minimum percentage of successful detection are found in the Radar Test Waveforms section.

The aggregate is the average of the percentage of successful detections of Short Pulse Radar Types 1-4. For example, the following table indicates how to compute the aggregate of percentage of successful detections;

Example - Calculation of Aggregate Percentage

Radar Type	Number of Trials	Number of Successful Detections	Minimum Percentage of Successful Detections
1	30	30	100%
2	30	30	100%
3	30	29	96.7%
4	30	30	100%
Aggregate (100% + 100% + 96.7% +100%) / 4 = 99.2%			



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Equipment Configuration for Radar Type 0

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	700	1428	18	30	30	100.00%	--.

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Equipment Configuration for Radar Type 1

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1114	898	59	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1089	918	58	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	1520	658	81	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1193	838	63	1	1	100.00%	DETECTED
1	1567	638	83	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	577	1732	31	1	1	100.00%	DETECTED
1	1111	900	59	1	1	100.00%	DETECTED
1	420	2381	23	1	1	100.00%	DETECTED
1	971	1030	52	1	1	100.00%	DETECTED
1	369	2707	20	1	1	100.00%	DETECTED
1	717	1395	38	1	1	100.00%	DETECTED
1	430	2328	23	1	1	100.00%	DETECTED
1	1250	800	66	1	1	100.00%	DETECTED
1	758	1319	41	1	1	100.00%	DETECTED
1	1484	674	79	1	1	100.00%	DETECTED
1	733	1365	39	1	1	100.00%	DETECTED
1	382	2621	21	1	1	100.00%	DETECTED
1	695	1438	37	1	1	100.00%	DETECTED
1	696	1437	37	1	1	100.00%	DETECTED
1	698	1433	37	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 2

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4405	227	25	1	1	100.00%	DETECTED
1.5	4367	229	25	1	1	100.00%	DETECTED
1.5	4651	215	24	1	1	100.00%	DETECTED
1.8	4608	217	26	1	1	100.00%	DETECTED
1.8	6135	163	29	1	1	100.00%	DETECTED
2.1	4630	216	28	1	1	100.00%	DETECTED
2.2	5435	184	25	1	1	100.00%	DETECTED
2.2	5780	173	23	1	1	100.00%	DETECTED
2.4	5650	177	28	1	1	100.00%	DETECTED
3.0	5714	175	29	1	1	100.00%	DETECTED
3.1	6173	162	27	1	1	100.00%	DETECTED
3.1	4673	214	25	1	1	100.00%	DETECTED
3.4	5263	190	25	1	1	100.00%	DETECTED
3.4	5263	190	27	1	1	100.00%	DETECTED
3.6	4854	206	28	1	1	100.00%	DETECTED
3.8	6024	166	29	1	1	100.00%	DETECTED
3.8	5714	175	23	1	1	100.00%	DETECTED
3.8	5525	181	27	1	1	100.00%	DETECTED
3.9	4464	224	24	1	1	100.00%	DETECTED
4.0	4367	229	24	1	1	100.00%	DETECTED
4.0	5747	174	23	1	1	100.00%	DETECTED
4.1	5025	199	27	1	1	100.00%	DETECTED
4.1	4425	226	24	1	1	100.00%	DETECTED
4.2	5587	179	25	1	1	100.00%	DETECTED
4.3	5102	196	28	1	1	100.00%	DETECTED
4.6	5882	170	25	1	1	100.00%	DETECTED
4.8	4444	225	28	1	1	100.00%	DETECTED
4.9	5556	180	28	1	1	100.00%	DETECTED
5.0	5128	195	23	1	1	100.00%	DETECTED
5.0	5650	177	28	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 3

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
10	2347	426	17	1	1	100.00%	DETECTED
10	2890	346	18	1	1	100.00%	DETECTED
6.0	2160	463	18	1	1	100.00%	DETECTED
6.1	2985	335	16	1	1	100.00%	DETECTED
6.2	2237	447	17	1	1	100.00%	DETECTED
6.3	2294	436	17	1	1	100.00%	DETECTED
6.3	4292	233	18	1	1	100.00%	DETECTED
6.3	2710	369	18	1	1	100.00%	DETECTED
6.5	2242	446	16	1	1	100.00%	DETECTED
6.6	2278	439	17	1	1	100.00%	DETECTED
6.6	2370	422	17	1	1	100.00%	DETECTED
6.7	3846	260	17	1	1	100.00%	DETECTED
6.9	2755	363	17	1	1	100.00%	DETECTED
7	3356	298	17	1	1	100.00%	DETECTED
7.2	3096	323	18	1	1	100.00%	DETECTED
7.5	2770	361	16	1	1	100.00%	DETECTED
7.6	3311	302	18	1	0	0.00%	NOT DETECTED
7.6	2278	439	18	1	1	100.00%	DETECTED
7.6	2513	398	17	1	1	100.00%	DETECTED
8.3	2160	463	17	1	1	100.00%	DETECTED
8.4	3247	308	16	1	1	100.00%	DETECTED
8.5	2037	491	18	1	1	100.00%	DETECTED
8.5	3610	277	16	1	1	100.00%	DETECTED
8.7	4831	207	16	1	1	100.00%	DETECTED
9.0	2132	469	18	1	1	100.00%	DETECTED
9.1	2278	439	18	1	1	100.00%	DETECTED
9.5	2347	426	16	1	1	100.00%	DETECTED
9.7	2188	457	16	1	1	100.00%	DETECTED
9.7	2924	342	18	1	1	100.00%	DETECTED
9.9	2309	433	17	1	1	100.00%	DETECTED
Aggregate:				30	29	96.67%	Complies

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Equipment Configuration for Radar Type 4

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
12.1	4739	211	15	1	1	100.00%	DETECTED
12.2	2183	458	12	1	1	100.00%	DETECTED
12.2	2110	474	12	1	1	100.00%	DETECTED
12.4	2451	408	14	1	1	100.00%	DETECTED
12.7	2481	403	14	1	1	100.00%	DETECTED
12.9	3135	319	12	1	1	100.00%	DETECTED
13.0	2049	488	13	1	1	100.00%	DETECTED
13.1	2222	450	13	1	1	100.00%	DETECTED
13.3	3268	306	16	1	1	100.00%	DETECTED
14.0	3472	288	16	1	1	100.00%	DETECTED
14.2	3356	298	16	1	1	100.00%	DETECTED
14.3	2353	425	15	1	1	100.00%	DETECTED
14.6	2169	461	14	1	1	100.00%	DETECTED
15.5	2674	374	13	1	1	100.00%	DETECTED
15.8	2457	407	15	1	1	100.00%	DETECTED
16.4	2262	442	12	1	1	100.00%	DETECTED
16.5	2967	337	15	1	1	100.00%	DETECTED
16.6	2008	498	13	1	1	100.00%	DETECTED
16.8	2865	349	15	1	1	100.00%	DETECTED
16.9	2137	468	14	1	1	100.00%	DETECTED
17.5	4167	240	16	1	1	100.00%	DETECTED
17.5	2985	335	13	1	1	100.00%	DETECTED
18.2	3704	270	14	1	1	100.00%	DETECTED
18.4	2967	337	16	1	1	100.00%	DETECTED
18.8	4032	248	13	1	1	100.00%	DETECTED
18.9	3759	266	12	1	1	100.00%	DETECTED
19.2	2532	395	12	1	1	100.00%	DETECTED
19.5	2315	432	12	1	1	100.00%	DETECTED
19.6	3509	285	16	1	1	100.00%	DETECTED
19.7	2513	398	13	1	1	100.00%	DETECTED
Aggregate:				30	30	100.00%	Complies

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Equipment Configuration for Radar Type 5

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1	1	1	100.00%	DETECTED
Type 5 #2	1	1	100.00%	DETECTED
Type 5 #3	1	0	0.00%	NOT DETECTED
Type 5 #4	1	0	0.00%	NOT DETECTED
Type 5 #5	1	1	100.00%	DETECTED
Type 5 #6	1	0	0.00%	NOT DETECTED
Type 5 #7	1	1	100.00%	DETECTED
Type 5 #8	1	1	100.00%	DETECTED
Type 5 #9	1	1	100.00%	DETECTED
Type 5 #10	1	1	100.00%	DETECTED
Type 5 #11	1	1	100.00%	DETECTED
Type 5 #12	1	1	100.00%	DETECTED
Type 5 #13	1	1	100.00%	DETECTED
Type 5 #14	1	1	100.00%	DETECTED
Type 5 #15	1	1	100.00%	DETECTED
Type 5 #16	1	1	100.00%	DETECTED
Type 5 #17	1	1	100.00%	DETECTED
Type 5 #18	1	0	0.00%	NOT DETECTED
Type 5 #19	1	1	100.00%	DETECTED
Type 5 #20	1	1	100.00%	DETECTED
Type 5 #21	1	1	100.00%	DETECTED
Type 5 #22	1	1	100.00%	DETECTED
Type 5 #23	1	1	100.00%	DETECTED
Type 5 #24	1	1	100.00%	DETECTED
Type 5 #25	1	1	100.00%	DETECTED
Type 5 #26	1	0	0.00%	NOT DETECTED
Type 5 #27	1	1	100.00%	DETECTED
Type 5 #28	1	1	100.00%	DETECTED
Type 5 #29	1	1	100.00%	DETECTED
Type 5 #30	1	1	100.00%	DETECTED

Click on the link to view the injected radar signature profile

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Equipment Configuration for Radar Type 6

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	1	100.00%	DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	1	100.00%	DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	1	100.00%	DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED

Click on the link to view the injected radar signature profile

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9.2.5. Detection Bandwidth

To determine the equipment Detection Bandwidth for each applicable operational mode a single burst of the short pulse radar Type 0 was produced at the appropriate power level. The EUT was set up as a standalone device (no associated Client or Master, as appropriate) and no traffic. Frame based systems will be set to a talk/listen ratio reflecting the worst case (maximum) that is user configurable during this test.

To determine the actual receiver bandwidth a single radar burst is generated for a minimum of 10 trials and the response of the EUT noted. The EUT must detect the Radar Waveform until it fails to detect, at this point testing is stopped and the frequency noted.

Starting from the actual channel center frequency the radar frequency is increased in 1 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The highest frequency at which detection is greater than or equal to 90% is denoted as FH. Note for the higher bandwidths ac-80 etc the 1 MHz step size can be increased.

The radar frequency is decreased in 1 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The lowest frequency at which detection is greater than or equal to 90% is denoted as FL.

The U-NII Detection Bandwidth is calculated as follows:
$$\text{U-NII Detection Bandwidth} = \text{FH} - \text{FL}$$

The U-NII Detection Bandwidth must meet the U-NII Detection Bandwidth criterion specified. Otherwise, the UUT does not comply with DFS requirements. This is essential to ensure that the UUT is capable of detecting Radar Waveforms across the same frequency spectrum that contains the significant energy from the system. In the case that the U-NII Detection Bandwidth is greater than or equal to the 99% power bandwidth for the measured FH and FL, the test can be truncated and the U-NII Detection Bandwidth can be reported as the measured FH and FL



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Equipment Configuration for Detection Bandwidth

Variant:	802.11a	Duty Cycle (%):	35.00
Data Rate:	18	Antenna Gain (dBi):	4.00
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
TPC:	Maximum Power	Tested By:	BJ
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5489 MHz				
5490 MHz				
5491 MHz	10	0		
5492 MHz	10	10	100.00%	Pass
5493 MHz	10	10	100.00%	Pass
5494 MHz	10	10	100.00%	Pass
5495 MHz	10	10	100.00%	Pass
5496 MHz	10	10	100.00%	Pass
5497 MHz	10	10	100.00%	Pass
5498 MHz	10	10	100.00%	Pass
5499 MHz	10	10	100.00%	Pass
5500	10	10	100.00%	Pass
5501 MHz	10	10	100.00%	Pass
5502 MHz	10	10	100.00%	Pass
5503 MHz	10	10	100.00%	Pass
5504 MHz	10	10	100.00%	Pass
5505 MHz	10	10	100.00%	Pass
5506 MHz	10	10	100.00%	Pass
5507 MHz	10	10	100.00%	Pass
5508 MHz	10	10	100.00%	Pass
5509 MHz	10	0		
5510 MHz				
5511 MHz				

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A. APPENDIX - GRAPHICAL IMAGES

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A.1. Dynamic Frequency Selection (DFS)

A.1.1. Probability of Detection

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	687560	77	0	0	62363	750000
2	3	12	396475	89	1616	1876	349766	750000
3	2	10	221272	67	1455	0	527139	750000
4	3	17	134197	51	1931	1390	612329	750000
5	2	12	156369	84	1854	0	591609	750000
6	3	7	46483	85	1603	1392	700267	750000
7	2	7	130433	60	1583	0	617864	750000
8	2	7	385559	52	1280	0	363057	750000
9	1	18	20909	56	0	0	729035	750000
10	2	8	566775	57	1866	0	181245	750000
11	2	17	489473	73	1496	0	258885	750000
12	3	6	590944	58	1690	1025	156167	750000
13	2	7	567012	63	1391	0	181471	750000
14	1	16	486902	64	0	0	263034	750000
15	2	17	497695	88	1110	0	251019	750000
16	1	14	619528	77	0	0	130395	750000

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Type 5 #2 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	658537	73	1845	0	6138	666666
2	2	16	472549	89	1516	0	192423	666666
3	1	10	85438	74	0	0	581154	666666
4	2	17	317887	52	1988	0	346687	666666
5	1	18	348702	65	0	0	317899	666666
6	1	15	458978	63	0	0	207625	666666
7	3	10	157064	92	1330	1551	506445	666666
8	3	10	98660	71	1193	1428	565172	666666
9	3	11	422966	99	1769	1002	240632	666666
10	1	15	414547	70	0	0	252049	666666
11	2	13	369814	75	1132	0	295570	666666
12	2	20	389880	87	1062	0	275550	666666
13	2	6	117809	96	1872	0	546793	666666
14	2	8	469297	73	1447	0	195776	666666
15	1	11	559349	93	0	0	107224	666666
16	3	19	384220	65	1100	1521	279630	666666
17	1	5	46837	61	0	0	619768	666666
18	1	17	279056	92	0	0	387518	666666

Type 5 #3 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	630495	85	1131	0	118204	750000
2	3	19	464539	95	1547	1591	282038	750000
3	1	20	707486	89	0	0	42425	750000
4	2	7	336130	89	1715	0	411977	750000
5	1	15	315502	79	0	0	434419	750000
6	2	6	15836	67	1869	0	732161	750000
7	2	14	419282	67	1041	0	329543	750000
8	1	17	538616	50	0	0	211334	750000
9	2	17	255632	52	1414	0	492850	750000
10	2	11	204255	95	1458	0	544097	750000
11	1	11	530154	81	0	0	219765	750000
12	1	11	641611	99	0	0	108290	750000
13	1	15	370534	99	0	0	379367	750000
14	3	18	14022	50	1886	1246	732696	750000
15	1	20	695105	61	0	0	54834	750000
16	3	14	631253	52	1671	1653	115267	750000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	971265	76	0	0	119568	1090909
2	3	11	588912	89	1225	1638	498867	1090909
3	1	7	1047526	57	0	0	43326	1090909
4	3	5	600865	53	1369	1778	486738	1090909
5	2	19	258510	63	1267	0	831006	1090909
6	1	19	417912	58	0	0	672939	1090909
7	1	10	628226	69	0	0	462614	1090909
8	2	12	657543	97	1566	0	431606	1090909
9	3	12	519139	62	1661	1609	568314	1090909
10	1	17	1054420	54	0	0	36435	1090909
11	3	13	318756	100	1301	1875	768677	1090909

Type 5 #5 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	400108	82	1653	1526	263133	666666
2	2	13	503015	92	1150	0	162317	666666
3	2	5	335565	77	1371	0	329576	666666
4	2	13	529618	77	1101	0	135793	666666
5	2	8	348932	70	1155	0	316439	666666
6	1	11	384882	53	0	0	281731	666666
7	1	9	552420	72	0	0	114174	666666
8	1	17	633650	90	0	0	32926	666666
9	1	20	545697	82	0	0	120887	666666
10	1	9	346253	66	0	0	320347	666666
11	1	12	319344	97	0	0	347225	666666
12	1	10	127712	88	0	0	538866	666666
13	3	8	1072	60	1610	1498	662306	666666
14	2	12	40447	71	1941	0	624136	666666
15	1	16	636378	64	0	0	30224	666666
16	2	12	591517	88	1244	0	73729	666666
17	1	14	50185	99	0	0	616382	666666
18	3	9	610796	82	1263	1562	52799	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	719407	55	0	0	137680	857142
2	3	7	206784	78	1453	1298	647373	857142
3	2	7	848944	69	1266	0	6794	857142
4	1	20	794051	78	0	0	63013	857142
5	3	13	10319	81	1454	1059	844067	857142
6	2	16	629787	58	1862	0	225377	857142
7	1	13	398397	93	0	0	458652	857142
8	3	8	10280	60	1871	1087	843724	857142
9	2	20	500888	51	1647	0	354505	857142
10	2	17	338785	71	1906	0	516309	857142
11	3	15	697951	64	1194	1864	155941	857142
12	2	18	337700	51	1224	0	518116	857142
13	2	13	587350	80	1104	0	268528	857142
14	3	13	579663	84	1777	1051	274399	857142

Type 5 #7 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	14	297439	55	1569	1807	330598	631578
2	2	10	293219	61	1807	0	336430	631578
3	1	8	206613	93	0	0	424872	631578
4	2	14	27293	96	1156	0	602937	631578
5	3	7	340881	81	1446	1384	287624	631578
6	3	16	216988	88	1272	1129	411925	631578
7	1	16	51235	69	0	0	580274	631578
8	1	18	352656	62	0	0	278860	631578
9	2	5	78879	100	1622	0	550877	631578
10	2	12	53394	62	1527	0	576533	631578
11	2	19	20826	60	1636	0	608996	631578
12	1	7	116562	97	0	0	514919	631578
13	1	15	317105	79	0	0	314394	631578
14	1	6	621037	84	0	0	10457	631578
15	2	8	417825	75	1311	0	212292	631578
16	3	15	352861	80	1869	1579	275029	631578
17	1	9	276917	92	0	0	354569	631578
18	1	15	583278	82	0	0	48218	631578
19	2	10	95492	70	1424	0	534522	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	901180	79	0	0	298741	1200000
2	2	20	668567	98	1004	0	530233	1200000
3	3	9	566404	98	1774	1962	629566	1200000
4	1	7	862040	50	0	0	337910	1200000
5	2	10	162637	91	1968	0	1035213	1200000
6	2	11	803082	93	1754	0	394978	1200000
7	2	6	178861	56	1094	0	1019933	1200000
8	2	14	450770	58	1877	0	747237	1200000
9	2	10	631564	81	1285	0	566989	1200000
10	2	18	539215	97	1686	0	658905	1200000

Type 5 #9 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	472953	59	1784	0	858478	1333333
2	3	18	690611	80	1305	1633	639544	1333333
3	1	20	855527	67	0	0	477739	1333333
4	3	14	908256	59	1363	1315	422222	1333333
5	1	6	1000560	90	0	0	332683	1333333
6	2	12	677698	52	1653	0	653878	1333333
7	3	9	1254470	88	1517	1188	75894	1333333
8	2	17	734866	65	1877	0	596460	1333333
9	3	16	1307020	79	1104	1426	23546	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	134206	80	1244	1322	862988	1000000
2	2	11	33462	63	1610	0	964802	1000000
3	3	7	640394	83	1195	1796	356366	1000000
4	3	18	497409	95	1788	1699	498819	1000000
5	3	12	558260	92	1764	1917	437783	1000000
6	1	10	507758	100	0	0	492142	1000000
7	3	5	426387	78	1759	1746	569874	1000000
8	1	19	546091	52	0	0	453857	1000000
9	3	19	568927	64	1210	1387	428284	1000000
10	3	10	519707	55	1538	1164	477426	1000000
11	1	18	413992	55	0	0	585953	1000000
12	3	13	617114	68	1701	1352	379629	1000000

Type 5 #11 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	14	26265	96	1149	0	678276	705882
2	3	16	107137	67	1773	1862	594909	705882
3	3	19	243628	80	1276	1377	459361	705882
4	3	15	159065	98	1788	1343	543392	705882
5	2	19	417039	97	1332	0	287317	705882
6	3	8	399668	75	1194	1146	303649	705882
7	2	17	520064	64	1421	0	184269	705882
8	1	18	276922	100	0	0	428860	705882
9	2	10	360994	51	1274	0	343512	705882
10	2	8	287210	100	1917	0	416555	705882
11	3	5	148639	96	1692	1240	554023	705882
12	1	16	650467	78	0	0	55337	705882
13	1	20	414560	82	0	0	291240	705882
14	1	20	422900	66	0	0	282916	705882
15	3	16	667586	52	1661	1969	34510	705882
16	2	14	577169	67	1610	0	126969	705882
17	1	9	218063	90	0	0	487729	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	13	400454	82	0	0	266130	666666
2	2	14	163729	60	1640	0	501177	666666
3	3	5	161494	55	1075	1787	502145	666666
4	1	11	188115	79	0	0	478472	666666
5	3	9	82944	84	1953	1063	580454	666666
6	3	13	78469	83	1745	1716	584487	666666
7	3	7	512734	66	1404	1384	150946	666666
8	2	16	66238	53	1461	0	598861	666666
9	2	18	172874	53	1543	0	492143	666666
10	3	15	1177	68	1456	1408	662421	666666
11	2	19	328595	55	1694	0	336267	666666
12	2	13	595893	82	1042	0	69567	666666
13	2	6	600074	89	1697	0	64717	666666
14	2	11	221840	93	1193	0	443447	666666
15	2	14	585125	70	1889	0	79512	666666
16	1	15	581289	79	0	0	85298	666666
17	1	9	473573	55	0	0	193038	666666
18	3	5	184580	95	1524	1690	478587	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	557513	57	1204	0	72747	631578
2	1	18	225635	86	0	0	405857	631578
3	2	8	46944	75	1263	0	583221	631578
4	2	13	512283	51	1993	0	117200	631578
5	1	20	435386	95	0	0	196097	631578
6	3	9	508618	90	1067	1119	120504	631578
7	3	7	568546	93	1131	1286	60336	631578
8	2	10	369712	100	1003	0	260663	631578
9	2	9	421007	87	1478	0	208919	631578
10	3	15	318095	100	1560	1858	309765	631578
11	2	5	278534	94	1013	0	351843	631578
12	2	11	142305	78	1615	0	487502	631578
13	2	13	213592	51	1535	0	416349	631578
14	1	7	14103	99	0	0	617376	631578
15	1	20	143557	59	0	0	487962	631578
16	3	16	571364	58	1211	1198	57631	631578
17	1	13	600142	72	0	0	31364	631578
18	2	9	171700	66	1123	0	458623	631578
19	2	12	244814	98	1949	0	384619	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	781000	85	1943	1329	215473	1000000
2	1	13	819289	73	0	0	180638	1000000
3	1	15	237220	77	0	0	762703	1000000
4	3	9	340555	87	1352	1508	656324	1000000
5	3	6	46708	52	1169	1209	950758	1000000
6	3	16	234414	85	1074	1599	762658	1000000
7	2	19	920685	94	1460	0	77667	1000000
8	1	6	253128	94	0	0	746778	1000000
9	3	7	641230	51	1018	1783	355816	1000000
10	3	16	439853	71	1695	1087	557152	1000000
11	1	18	609972	78	0	0	389950	1000000
12	2	9	314495	87	1811	0	683520	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	550621	61	1945	0	153194	705882
2	2	18	340208	70	1986	0	363548	705882
3	2	18	674203	54	1023	0	30548	705882
4	1	11	61013	71	0	0	644798	705882
5	1	11	360783	100	0	0	344999	705882
6	3	9	220371	78	1026	1851	482400	705882
7	2	10	147270	79	1938	0	556516	705882
8	2	19	605871	96	1838	0	97981	705882
9	2	19	425310	51	1710	0	278760	705882
10	1	16	583300	98	0	0	122484	705882
11	2	9	510089	73	1879	0	193768	705882
12	1	6	500759	89	0	0	205034	705882
13	1	12	235946	69	0	0	469867	705882
14	2	12	48928	75	1897	0	654907	705882
15	1	12	32711	81	0	0	673090	705882
16	1	13	396156	80	0	0	309646	705882
17	1	15	640263	54	0	0	65565	705882

Type 5 #16 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	8	603089	78	1197	0	101440	705882
2	1	14	642799	86	0	0	62997	705882
3	2	8	314058	74	1637	0	390039	705882
4	2	12	182091	59	1394	0	522279	705882
5	3	17	426797	100	1121	1362	276302	705882
6	1	10	115342	86	0	0	590454	705882
7	3	11	560854	84	1803	1558	141415	705882
8	3	10	132613	56	1650	1223	570228	705882
9	2	7	595060	62	1991	0	108707	705882
10	2	7	555837	57	1370	0	148561	705882
11	3	8	308980	70	1747	1785	393160	705882
12	3	14	298911	80	1510	1372	403849	705882
13	1	5	281204	88	0	0	424590	705882
14	1	12	40126	83	0	0	665673	705882
15	1	5	366111	87	0	0	339684	705882
16	2	20	536355	79	1372	0	167997	705882
17	2	7	684305	79	1793	0	19626	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	8207	80	0	0	591713	600000
2	2	17	426696	65	1030	0	172144	600000
3	3	6	266700	52	1420	1930	329794	600000
4	2	16	394974	75	1313	0	203563	600000
5	3	15	297075	69	1239	1216	300263	600000
6	2	20	119914	92	1936	0	477966	600000
7	2	17	476511	59	1057	0	122314	600000
8	1	20	456625	82	0	0	143293	600000
9	2	10	270654	86	1702	0	327472	600000
10	2	12	88143	76	1314	0	510391	600000
11	1	12	187310	73	0	0	412617	600000
12	1	19	343040	81	0	0	256879	600000
13	3	18	463378	100	1930	1064	133328	600000
14	2	19	521931	71	1651	0	76276	600000
15	2	18	330427	62	1731	0	267718	600000
16	1	5	587222	62	0	0	12716	600000
17	3	20	489211	87	1024	1514	107990	600000
18	3	7	256686	87	1866	1729	339458	600000
19	3	18	263380	85	1993	1932	332440	600000
20	2	6	338814	77	1029	0	260003	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	462842	83	1217	0	167353	631578
2	3	17	493019	51	1574	1943	134889	631578
3	1	17	262227	50	0	0	369301	631578
4	1	19	170623	96	0	0	460859	631578
5	1	12	490865	97	0	0	140616	631578
6	2	16	533156	51	1621	0	96699	631578
7	2	19	108223	75	1757	0	521448	631578
8	1	18	574489	73	0	0	57016	631578
9	2	8	581623	50	1842	0	48013	631578
10	3	19	79836	97	1777	1984	547690	631578
11	1	15	130089	70	0	0	501419	631578
12	3	20	230926	76	1127	1886	397411	631578
13	1	9	111916	100	0	0	519562	631578
14	1	5	17657	53	0	0	613868	631578
15	3	10	175524	96	1564	1335	452867	631578
16	3	8	531254	52	1999	1585	96584	631578
17	2	17	516349	62	1493	0	113612	631578
18	1	15	630218	94	0	0	1266	631578
19	2	10	341311	57	1966	0	288187	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	650931	96	0	0	272049	923076
2	3	19	715305	94	1889	1078	204522	923076
3	2	10	658881	53	1327	0	262762	923076
4	1	13	36475	98	0	0	886503	923076
5	3	8	32641	98	1814	1357	886970	923076
6	1	5	216239	68	0	0	706769	923076
7	3	14	803754	51	1794	1831	115544	923076
8	1	9	734850	77	0	0	188149	923076
9	3	10	328188	88	1676	1716	591232	923076
10	1	10	261299	77	0	0	661700	923076
11	2	17	742285	60	1926	0	178745	923076
12	2	6	617243	88	1306	0	304351	923076
13	2	18	301951	76	1654	0	619319	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	13	541306	63	1453	1590	161344	705882
2	2	6	409483	88	1988	0	294235	705882
3	2	5	461891	54	1921	0	241962	705882
4	1	19	385379	88	0	0	320415	705882
5	1	20	228848	84	0	0	476950	705882
6	1	8	440240	50	0	0	265592	705882
7	1	19	498387	72	0	0	207423	705882
8	2	12	10366	98	1841	0	693479	705882
9	3	14	598770	85	1548	1039	104270	705882
10	3	8	527037	97	1008	1306	176240	705882
11	3	6	364449	76	1762	1782	337661	705882
12	1	8	240166	64	0	0	465652	705882
13	2	5	440881	77	1551	0	263296	705882
14	1	8	97144	94	0	0	608644	705882
15	2	15	37838	54	1097	0	666839	705882
16	1	8	579520	100	0	0	126262	705882
17	1	19	7284	70	0	0	698528	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	19	337420	62	1790	1945	258659	600000
2	2	13	338755	65	1822	0	259293	600000
3	1	13	292933	51	0	0	307016	600000
4	1	5	584976	87	0	0	14937	600000
5	3	15	31167	90	1303	1415	565845	600000
6	2	10	70384	89	1370	0	528068	600000
7	3	13	179629	71	1606	1158	417394	600000
8	3	19	122843	65	1654	1697	473611	600000
9	2	13	170971	91	1932	0	426915	600000
10	2	14	210054	86	1443	0	388331	600000
11	3	7	310089	57	1204	1947	286589	600000
12	3	17	260275	75	1119	1932	336449	600000
13	1	13	257727	57	0	0	342216	600000
14	2	13	70360	59	1424	0	528098	600000
15	1	14	86327	58	0	0	513615	600000
16	2	6	180030	95	1153	0	418627	600000
17	2	15	286861	89	1442	0	311519	600000
18	2	20	102489	74	1354	0	496009	600000
19	2	18	164134	71	1578	0	434146	600000
20	1	11	222128	90	0	0	377782	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	12026	76	0	0	619476	631578
2	1	20	339895	81	0	0	291602	631578
3	1	15	389671	73	0	0	241834	631578
4	2	13	480067	74	1157	0	150206	631578
5	2	7	253310	83	1954	0	376148	631578
6	3	18	374735	68	1691	1451	253497	631578
7	1	16	314171	52	0	0	317355	631578
8	3	7	412001	65	1091	1714	216577	631578
9	1	12	591902	93	0	0	39583	631578
10	3	13	244624	95	1948	1075	383646	631578
11	1	10	128817	55	0	0	502706	631578
12	3	19	437982	61	1724	1689	190000	631578
13	1	7	232900	77	0	0	398601	631578
14	1	17	87037	50	0	0	544491	631578
15	3	9	66773	52	1415	1443	561791	631578
16	2	15	320899	91	1016	0	309481	631578
17	3	19	330175	92	1616	1061	298450	631578
18	1	12	489606	87	0	0	141885	631578
19	2	12	10272	70	1403	0	619763	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	758525	85	1717	0	96730	857142
2	1	6	18464	70	0	0	838608	857142
3	1	15	190080	83	0	0	666979	857142
4	3	13	637030	96	1886	1215	216723	857142
5	3	19	16567	62	1109	1844	837436	857142
6	1	10	297103	64	0	0	559975	857142
7	2	5	522064	93	1427	0	333465	857142
8	3	14	701284	56	1299	1622	152769	857142
9	2	14	743227	92	1980	0	111751	857142
10	2	15	832699	75	1860	0	22433	857142
11	2	15	212898	61	1146	0	642976	857142
12	3	8	717118	79	1698	1607	136482	857142
13	1	10	192513	87	0	0	664542	857142
14	2	14	682077	62	1114	0	173827	857142

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	248807	80	1441	0	349592	600000
2	1	20	295603	56	0	0	304341	600000
3	3	13	371603	81	1373	1149	225632	600000
4	2	10	322883	64	1972	0	275017	600000
5	2	5	235386	80	1981	0	362473	600000
6	1	17	135564	61	0	0	464375	600000
7	1	13	37657	95	0	0	562248	600000
8	1	15	438848	97	0	0	161055	600000
9	3	11	122417	92	1449	1269	474589	600000
10	3	13	359789	61	1361	1214	237453	600000
11	1	9	85420	99	0	0	514481	600000
12	1	20	346353	80	0	0	253567	600000
13	3	10	447020	52	1100	1375	150349	600000
14	1	6	263991	95	0	0	335914	600000
15	2	20	343964	61	1625	0	254289	600000
16	2	6	237547	78	1083	0	361214	600000
17	1	18	441674	88	0	0	158238	600000
18	1	20	187836	57	0	0	412107	600000
19	2	17	561970	70	1428	0	36462	600000
20	1	15	308707	90	0	0	291203	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	947638	76	0	0	52286	1000000
2	1	5	987980	54	0	0	11966	1000000
3	2	11	578477	83	1722	0	419635	1000000
4	1	14	392500	76	0	0	607424	1000000
5	1	14	82203	59	0	0	917738	1000000
6	1	19	240245	91	0	0	759664	1000000
7	2	19	913754	82	1286	0	84796	1000000
8	3	5	561153	96	1254	1016	436289	1000000
9	2	14	722372	62	1768	0	275736	1000000
10	1	9	921487	77	0	0	78436	1000000
11	3	15	669985	92	1915	1351	326473	1000000
12	2	19	850578	74	1226	0	148048	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	12	323667	86	0	0	382129	705882
2	1	16	582820	85	0	0	122977	705882
3	2	10	669515	86	1149	0	35046	705882
4	1	14	294925	57	0	0	410900	705882
5	3	16	224059	52	1534	1979	478154	705882
6	3	5	164985	100	1936	1242	537419	705882
7	2	5	599728	54	1165	0	104881	705882
8	1	6	218507	77	0	0	487298	705882
9	2	18	314266	66	1450	0	390034	705882
10	1	12	680796	75	0	0	25011	705882
11	1	5	38754	76	0	0	667052	705882
12	1	7	125443	58	0	0	580381	705882
13	1	15	327789	69	0	0	378024	705882
14	1	12	417037	89	0	0	288756	705882
15	1	9	694571	81	0	0	11230	705882
16	1	15	330934	94	0	0	374854	705882
17	1	16	613998	61	0	0	91823	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	55450	55	1503	0	1276270	1333333
2	3	8	1135712	87	1388	1007	194965	1333333
3	1	8	188365	84	0	0	1144884	1333333
4	2	13	476641	93	1562	0	854944	1333333
5	3	14	1151409	71	1204	1507	179000	1333333
6	1	13	1262107	95	0	0	71131	1333333
7	3	9	376298	72	1094	1581	954144	1333333
8	1	5	1332805	99	0	0	429	1333333
9	3	15	1301207	69	1619	1444	28856	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	148805	74	1263	1679	771107	923076
2	2	6	118118	61	1518	0	803318	923076
3	3	12	406270	58	1835	1661	513136	923076
4	1	16	534662	70	0	0	388344	923076
5	2	7	463609	93	1884	0	457397	923076
6	2	12	892253	81	1771	0	28890	923076
7	3	12	493815	76	1629	1407	425997	923076
8	3	9	425669	58	1778	1870	493585	923076
9	3	20	831426	60	1868	1532	88070	923076
10	3	12	779211	60	1041	1262	141382	923076
11	1	19	349841	81	0	0	573154	923076
12	1	19	685119	80	0	0	237877	923076
13	2	10	678568	78	1468	0	242884	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	17	76566	56	1991	0	587997	666666
2	3	7	609960	86	1093	1929	53426	666666
3	2	16	378550	51	1766	0	286248	666666
4	2	9	383886	86	1593	0	281015	666666
5	3	9	586202	83	1994	1689	76532	666666
6	1	8	553003	55	0	0	113608	666666
7	2	16	393553	56	1476	0	271525	666666
8	2	19	91161	73	1323	0	574036	666666
9	3	20	377339	77	1460	1540	286096	666666
10	1	17	26731	99	0	0	639836	666666
11	2	7	430720	60	1261	0	234565	666666
12	2	20	36272	73	1426	0	628822	666666
13	2	19	281429	52	1099	0	384034	666666
14	2	8	83999	67	1174	0	581359	666666
15	1	20	304163	90	0	0	362413	666666
16	3	16	79812	62	1845	1453	583370	666666
17	3	10	196013	57	1175	1179	468128	666666
18	3	18	312287	72	1115	1990	351058	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	18	560244	78	0	0	296820	857142
2	3	5	684896	51	1232	1940	168921	857142
3	2	18	587648	100	1257	0	268037	857142
4	2	17	465771	70	1609	0	389622	857142
5	1	11	600994	67	0	0	256081	857142
6	3	7	349786	96	1517	1905	503646	857142
7	1	14	251178	56	0	0	605908	857142
8	3	18	689842	95	1595	1828	163592	857142
9	2	17	587737	95	1349	0	267866	857142
10	1	5	258166	66	0	0	598910	857142
11	3	10	165533	71	1380	1927	688089	857142
12	3	7	775356	56	1951	1942	77725	857142
13	2	13	440076	66	1744	0	415190	857142
14	2	14	645607	78	1786	0	209593	857142

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5632	#02-5706	#03-5630	#04-5309	#05-5448	#06-5525	#07-5288	#08-5256	#09-5500	#10-5533
#11-5292	#12-5352	#13-5274	#14-5715	#15-5597	#16-5609	#17-5555	#18-5297	#19-5608	#20-5618
#21-5568	#22-5556	#23-5670	#24-5677	#25-5516	#26-5362	#27-5537	#28-5331	#29-5604	#30-5466
#31-5494	#32-5296	#33-5546	#34-5424	#35-5411	#36-5270	#37-5316	#38-5450	#39-5413	#40-5638
#41-5393	#42-5381	#43-5510	#44-5610	#45-5622	#46-5470	#47-5642	#48-5254	#49-5290	#50-5326
#51-5285	#52-5678	#53-5357	#54-5657	#55-5412	#56-5476	#57-5649	#58-5620	#59-5551	#60-5582
#61-5703	#62-5418	#63-5422	#64-5333	#65-5650	#66-5403	#67-5447	#68-5598	#69-5501	#70-5355
#71-5507	#72-5385	#73-5576	#74-5531	#75-5446	#76-5388	#77-5548	#78-5490	#79-5255	#80-5572
#81-5522	#82-5686	#83-5723	#84-5519	#85-5392	#86-5554	#87-5489	#88-5337	#89-5536	#90-5342
#91-5558	#92-5526	#93-5697	#94-5317	#95-5445	#96-5514	#97-5695	#98-5502	#99-5639	#100-5560

Type 6 #2 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5669	#02-5453	#03-5639	#04-5510	#05-5252	#06-5342	#07-5697	#08-5672	#09-5283	#10-5486
#11-5378	#12-5441	#13-5449	#14-5328	#15-5359	#16-5525	#17-5268	#18-5676	#19-5722	#20-5706
#21-5484	#22-5698	#23-5645	#24-5259	#25-5321	#26-5353	#27-5466	#28-5500	#29-5611	#30-5657
#31-5699	#32-5414	#33-5412	#34-5575	#35-5663	#36-5640	#37-5703	#38-5334	#39-5443	#40-5430
#41-5394	#42-5524	#43-5290	#44-5568	#45-5601	#46-5720	#47-5302	#48-5405	#49-5419	#50-5688
#51-5550	#52-5540	#53-5326	#54-5696	#55-5532	#56-5629	#57-5439	#58-5624	#59-5708	#60-5480
#61-5422	#62-5397	#63-5553	#64-5403	#65-5276	#66-5287	#67-5478	#68-5420	#69-5609	#70-5289
#71-5591	#72-5529	#73-5526	#74-5340	#75-5423	#76-5604	#77-5415	#78-5444	#79-5357	#80-5306
#81-5311	#82-5330	#83-5376	#84-5694	#85-5398	#86-5599	#87-5335	#88-5603	#89-5380	#90-5261
#91-5514	#92-5435	#93-5460	#94-5675	#95-5461	#96-5574	#97-5683	#98-5549	#99-5709	#100-5534

Type 6 #3 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5444	#02-5347	#03-5271	#04-5263	#05-5711	#06-5522	#07-5652	#08-5463	#09-5719	#10-5516
#11-5651	#12-5419	#13-5341	#14-5270	#15-5584	#16-5255	#17-5402	#18-5676	#19-5599	#20-5289
#21-5598	#22-5499	#23-5406	#24-5318	#25-5575	#26-5367	#27-5297	#28-5393	#29-5251	#30-5595
#31-5398	#32-5482	#33-5326	#34-5520	#35-5657	#36-5597	#37-5377	#38-5585	#39-5349	#40-5331
#41-5452	#42-5523	#43-5643	#44-5533	#45-5506	#46-5605	#47-5355	#48-5602	#49-5409	#50-5422
#51-5257	#52-5674	#53-5670	#54-5661	#55-5669	#56-5665	#57-5677	#58-5413	#59-5593	#60-5475
#61-5509	#62-5462	#63-5373	#64-5368	#65-5342	#66-5546	#67-5338	#68-5541	#69-5576	#70-5518
#71-5561	#72-5325	#73-5704	#74-5488	#75-5319	#76-5487	#77-5666	#78-5515	#79-5566	#80-5423
#81-5390	#82-5532	#83-5380	#84-5712	#85-5656	#86-5424	#87-5481	#88-5581	#89-5667	#90-5310
#91-5396	#92-5524	#93-5364	#94-5309	#95-5266	#96-5616	#97-5405	#98-5359	#99-5586	#100-5690

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Type 6 #4 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5426	#02-5417	#03-5343	#04-5355	#05-5533	#06-5719	#07-5621	#08-5675	#09-5702	#10-5611
#11-5686	#12-5687	#13-5351	#14-5305	#15-5427	#16-5368	#17-5344	#18-5662	#19-5618	#20-5264
#21-5557	#22-5688	#23-5395	#24-5631	#25-5428	#26-5649	#27-5624	#28-5283	#29-5542	#30-5709
#31-5376	#32-5271	#33-5722	#34-5272	#35-5479	#36-5257	#37-5328	#38-5375	#39-5297	#40-5673
#41-5414	#42-5446	#43-5547	#44-5477	#45-5451	#46-5347	#47-5640	#48-5560	#49-5354	#50-5487
#51-5312	#52-5468	#53-5465	#54-5572	#55-5382	#56-5463	#57-5437	#58-5652	#59-5608	#60-5345
#61-5587	#62-5383	#63-5717	#64-5484	#65-5664	#66-5689	#67-5550	#68-5420	#69-5289	#70-5693
#71-5614	#72-5670	#73-5574	#74-5361	#75-5390	#76-5643	#77-5429	#78-5331	#79-5259	#80-5313
#81-5654	#82-5647	#83-5633	#84-5531	#85-5400	#86-5266	#87-5616	#88-5448	#89-5577	#90-5552
#91-5554	#92-5511	#93-5562	#94-5260	#95-5659	#96-5447	#97-5579	#98-5520	#99-5322	#100-5353

Type 6 #5 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5257	#02-5571	#03-5599	#04-5282	#05-5657	#06-5327	#07-5320	#08-5576	#09-5383	#10-5539
#11-5438	#12-5533	#13-5435	#14-5398	#15-5495	#16-5450	#17-5342	#18-5271	#19-5297	#20-5561
#21-5650	#22-5643	#23-5673	#24-5422	#25-5302	#26-5719	#27-5583	#28-5553	#29-5303	#30-5261
#31-5402	#32-5593	#33-5668	#34-5606	#35-5609	#36-5602	#37-5544	#38-5619	#39-5710	#40-5483
#41-5390	#42-5377	#43-5568	#44-5373	#45-5451	#46-5474	#47-5298	#48-5573	#49-5379	#50-5427
#51-5701	#52-5698	#53-5486	#54-5339	#55-5622	#56-5704	#57-5663	#58-5469	#59-5492	#60-5522
#61-5372	#62-5386	#63-5570	#64-5590	#65-5554	#66-5513	#67-5617	#68-5636	#69-5523	#70-5376
#71-5312	#72-5510	#73-5515	#74-5354	#75-5534	#76-5649	#77-5559	#78-5426	#79-5432	#80-5428
#81-5519	#82-5361	#83-5565	#84-5681	#85-5490	#86-5716	#87-5592	#88-5255	#89-5527	#90-5586
#91-5644	#92-5680	#93-5468	#94-5629	#95-5574	#96-5408	#97-5642	#98-5549	#99-5518	#100-5378

Type 6 #6 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5378	#02-5417	#03-5660	#04-5512	#05-5598	#06-5538	#07-5685	#08-5675	#09-5407	#10-5375
#11-5719	#12-5638	#13-5524	#14-5683	#15-5419	#16-5546	#17-5335	#18-5642	#19-5509	#20-5647
#21-5496	#22-5714	#23-5575	#24-5274	#25-5431	#26-5654	#27-5576	#28-5708	#29-5510	#30-5695
#31-5436	#32-5707	#33-5513	#34-5555	#35-5454	#36-5442	#37-5472	#38-5429	#39-5519	#40-5515
#41-5291	#42-5668	#43-5671	#44-5404	#45-5339	#46-5322	#47-5250	#48-5289	#49-5595	#50-5607
#51-5389	#52-5567	#53-5636	#54-5487	#55-5416	#56-5608	#57-5358	#58-5692	#59-5383	#60-5590
#61-5273	#62-5452	#63-5541	#64-5631	#65-5716	#66-5606	#67-5317	#68-5425	#69-5644	#70-5535
#71-5306	#72-5483	#73-5421	#74-5618	#75-5676	#76-5655	#77-5565	#78-5350	#79-5296	#80-5643
#81-5691	#82-5552	#83-5558	#84-5363	#85-5609	#86-5295	#87-5653	#88-5492	#89-5563	#90-5376
#91-5424	#92-5498	#93-5348	#94-5441	#95-5327	#96-5697	#97-5688	#98-5578	#99-5403	#100-5505

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Type 6 #7 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5653	#02-5624	#03-5661	#04-5323	#05-5432	#06-5330	#07-5342	#08-5612	#09-5441	#10-5450
#11-5684	#12-5322	#13-5639	#14-5345	#15-5483	#16-5312	#17-5284	#18-5489	#19-5377	#20-5715
#21-5393	#22-5361	#23-5534	#24-5648	#25-5520	#26-5484	#27-5431	#28-5683	#29-5396	#30-5386
#31-5442	#32-5411	#33-5490	#34-5436	#35-5623	#36-5659	#37-5427	#38-5536	#39-5588	#40-5572
#41-5399	#42-5676	#43-5699	#44-5539	#45-5275	#46-5526	#47-5707	#48-5463	#49-5357	#50-5339
#51-5382	#52-5412	#53-5542	#54-5263	#55-5527	#56-5672	#57-5383	#58-5465	#59-5305	#60-5257
#61-5523	#62-5557	#63-5453	#64-5446	#65-5548	#66-5609	#67-5473	#68-5625	#69-5530	#70-5566
#71-5426	#72-5560	#73-5359	#74-5495	#75-5449	#76-5469	#77-5289	#78-5457	#79-5353	#80-5278
#81-5328	#82-5324	#83-5569	#84-5414	#85-5259	#86-5641	#87-5673	#88-5265	#89-5460	#90-5604
#91-5691	#92-5266	#93-5511	#94-5472	#95-5430	#96-5438	#97-5577	#98-5571	#99-5644	#100-5366

Type 6 #8 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5504	#02-5629	#03-5282	#04-5714	#05-5424	#06-5638	#07-5426	#08-5572	#09-5628	#10-5494
#11-5479	#12-5379	#13-5365	#14-5704	#15-5445	#16-5464	#17-5709	#18-5581	#19-5550	#20-5706
#21-5546	#22-5593	#23-5342	#24-5302	#25-5610	#26-5663	#27-5555	#28-5541	#29-5276	#30-5640
#31-5425	#32-5481	#33-5405	#34-5689	#35-5315	#36-5509	#37-5701	#38-5652	#39-5499	#40-5351
#41-5284	#42-5313	#43-5496	#44-5688	#45-5668	#46-5395	#47-5660	#48-5691	#49-5453	#50-5721
#51-5270	#52-5662	#53-5545	#54-5635	#55-5536	#56-5353	#57-5486	#58-5333	#59-5713	#60-5318
#61-5722	#62-5698	#63-5401	#64-5661	#65-5487	#66-5307	#67-5331	#68-5448	#69-5672	#70-5513
#71-5530	#72-5571	#73-5338	#74-5666	#75-5517	#76-5619	#77-5515	#78-5309	#79-5436	#80-5429
#81-5461	#82-5467	#83-5394	#84-5404	#85-5548	#86-5262	#87-5268	#88-5399	#89-5324	#90-5427
#91-5694	#92-5719	#93-5271	#94-5340	#95-5454	#96-5396	#97-5639	#98-5547	#99-5715	#100-5281

Type 6 #9 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5355	#02-5689	#03-5615	#04-5411	#05-5693	#06-5439	#07-5344	#08-5485	#09-5527	#10-5614
#11-5511	#12-5480	#13-5256	#14-5484	#15-5687	#16-5489	#17-5319	#18-5430	#19-5523	#20-5302
#21-5455	#22-5393	#23-5372	#24-5697	#25-5597	#26-5424	#27-5580	#28-5289	#29-5514	#30-5638
#31-5477	#32-5363	#33-5299	#34-5258	#35-5356	#36-5386	#37-5293	#38-5553	#39-5304	#40-5701
#41-5522	#42-5538	#43-5463	#44-5712	#45-5512	#46-5378	#47-5690	#48-5637	#49-5570	#50-5367
#51-5442	#52-5703	#53-5624	#54-5546	#55-5493	#56-5420	#57-5566	#58-5645	#59-5630	#60-5487
#61-5349	#62-5253	#63-5618	#64-5435	#65-5678	#66-5383	#67-5347	#68-5275	#69-5601	#70-5468
#71-5325	#72-5658	#73-5666	#74-5483	#75-5536	#76-5335	#77-5296	#78-5377	#79-5669	#80-5521
#81-5284	#82-5384	#83-5399	#84-5437	#85-5587	#86-5671	#87-5598	#88-5320	#89-5438	#90-5557
#91-5460	#92-5326	#93-5539	#94-5545	#95-5490	#96-5698	#97-5628	#98-5691	#99-5551	#100-5681

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Type 6 #10 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5609	#02-5480	#03-5598	#04-5265	#05-5360	#06-5405	#07-5326	#08-5694	#09-5484	#10-5285
#11-5490	#12-5520	#13-5400	#14-5401	#15-5613	#16-5334	#17-5255	#18-5624	#19-5391	#20-5358
#21-5272	#22-5441	#23-5258	#24-5596	#25-5307	#26-5562	#27-5373	#28-5280	#29-5310	#30-5481
#31-5433	#32-5471	#33-5715	#34-5714	#35-5510	#36-5305	#37-5649	#38-5282	#39-5491	#40-5585
#41-5291	#42-5658	#43-5286	#44-5389	#45-5393	#46-5602	#47-5614	#48-5623	#49-5316	#50-5549
#51-5442	#52-5417	#53-5251	#54-5682	#55-5522	#56-5281	#57-5295	#58-5633	#59-5252	#60-5576
#61-5269	#62-5410	#63-5412	#64-5381	#65-5674	#66-5700	#67-5506	#68-5581	#69-5692	#70-5662
#71-5271	#72-5423	#73-5705	#74-5403	#75-5421	#76-5583	#77-5367	#78-5647	#79-5568	#80-5306
#81-5546	#82-5260	#83-5508	#84-5347	#85-5376	#86-5435	#87-5582	#88-5439	#89-5639	#90-5527
#91-5703	#92-5470	#93-5315	#94-5673	#95-5340	#96-5440	#97-5565	#98-5402	#99-5560	#100-5503

Type 6 #11 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5313	#02-5661	#03-5348	#04-5301	#05-5617	#06-5461	#07-5394	#08-5459	#09-5347	#10-5641
#11-5354	#12-5590	#13-5371	#14-5290	#15-5576	#16-5573	#17-5357	#18-5416	#19-5648	#20-5724
#21-5503	#22-5273	#23-5468	#24-5445	#25-5250	#26-5657	#27-5356	#28-5634	#29-5276	#30-5456
#31-5252	#32-5629	#33-5711	#34-5481	#35-5411	#36-5278	#37-5675	#38-5543	#39-5437	#40-5704
#41-5542	#42-5611	#43-5599	#44-5364	#45-5275	#46-5346	#47-5492	#48-5333	#49-5399	#50-5478
#51-5560	#52-5442	#53-5628	#54-5300	#55-5684	#56-5484	#57-5432	#58-5616	#59-5638	#60-5449
#61-5604	#62-5615	#63-5569	#64-5415	#65-5545	#66-5407	#67-5597	#68-5527	#69-5536	#70-5523
#71-5455	#72-5582	#73-5570	#74-5610	#75-5559	#76-5331	#77-5538	#78-5509	#79-5372	#80-5577
#81-5401	#82-5400	#83-5480	#84-5404	#85-5694	#86-5375	#87-5624	#88-5583	#89-5267	#90-5678
#91-5522	#92-5651	#93-5697	#94-5485	#95-5458	#96-5430	#97-5655	#98-5672	#99-5526	#100-5452

Type 6 #12 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5559	#02-5584	#03-5307	#04-5415	#05-5375	#06-5272	#07-5670	#08-5648	#09-5493	#10-5311
#11-5298	#12-5453	#13-5384	#14-5414	#15-5446	#16-5419	#17-5507	#18-5264	#19-5510	#20-5583
#21-5251	#22-5529	#23-5610	#24-5420	#25-5374	#26-5351	#27-5626	#28-5607	#29-5561	#30-5301
#31-5450	#32-5377	#33-5278	#34-5570	#35-5359	#36-5317	#37-5458	#38-5719	#39-5257	#40-5598
#41-5407	#42-5636	#43-5282	#44-5323	#45-5265	#46-5459	#47-5502	#48-5393	#49-5512	#50-5279
#51-5699	#52-5611	#53-5290	#54-5274	#55-5371	#56-5312	#57-5336	#58-5297	#59-5260	#60-5573
#61-5325	#62-5355	#63-5569	#64-5337	#65-5352	#66-5299	#67-5530	#68-5515	#69-5576	#70-5378
#71-5319	#72-5342	#73-5277	#74-5398	#75-5309	#76-5302	#77-5513	#78-5284	#79-5687	#80-5552
#81-5540	#82-5431	#83-5417	#84-5434	#85-5669	#86-5511	#87-5360	#88-5625	#89-5503	#90-5681
#91-5692	#92-5421	#93-5372	#94-5400	#95-5344	#96-5706	#97-5624	#98-5563	#99-5322	#100-5633

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Type 6 #13 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5724	#02-5542	#03-5673	#04-5722	#05-5485	#06-5639	#07-5277	#08-5720	#09-5471	#10-5538
#11-5363	#12-5528	#13-5278	#14-5677	#15-5646	#16-5606	#17-5346	#18-5642	#19-5631	#20-5591
#21-5261	#22-5323	#23-5540	#24-5385	#25-5309	#26-5439	#27-5276	#28-5634	#29-5683	#30-5531
#31-5373	#32-5480	#33-5632	#34-5384	#35-5613	#36-5469	#37-5437	#38-5280	#39-5483	#40-5364
#41-5404	#42-5690	#43-5568	#44-5414	#45-5392	#46-5419	#47-5479	#48-5463	#49-5610	#50-5707
#51-5656	#52-5455	#53-5621	#54-5651	#55-5251	#56-5662	#57-5295	#58-5612	#59-5368	#60-5286
#61-5665	#62-5403	#63-5714	#64-5297	#65-5371	#66-5282	#67-5386	#68-5529	#69-5601	#70-5358
#71-5644	#72-5575	#73-5619	#74-5581	#75-5470	#76-5645	#77-5402	#78-5442	#79-5274	#80-5458
#81-5611	#82-5499	#83-5317	#84-5365	#85-5327	#86-5537	#87-5578	#88-5367	#89-5271	#90-5602
#91-5446	#92-5326	#93-5701	#94-5428	#95-5305	#96-5347	#97-5256	#98-5401	#99-5293	#100-5723

Type 6 #14 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5280	#02-5688	#03-5541	#04-5269	#05-5250	#06-5522	#07-5273	#08-5360	#09-5333	#10-5395
#11-5455	#12-5384	#13-5461	#14-5458	#15-5717	#16-5544	#17-5430	#18-5288	#19-5689	#20-5502
#21-5275	#22-5704	#23-5683	#24-5394	#25-5669	#26-5699	#27-5387	#28-5651	#29-5261	#30-5451
#31-5460	#32-5660	#33-5319	#34-5362	#35-5401	#36-5511	#37-5444	#38-5536	#39-5305	#40-5343
#41-5635	#42-5518	#43-5300	#44-5595	#45-5566	#46-5691	#47-5571	#48-5355	#49-5551	#50-5363
#51-5281	#52-5516	#53-5697	#54-5255	#55-5397	#56-5325	#57-5385	#58-5346	#59-5348	#60-5607
#61-5520	#62-5654	#63-5391	#64-5565	#65-5282	#66-5711	#67-5476	#68-5633	#69-5408	#70-5365
#71-5436	#72-5632	#73-5523	#74-5352	#75-5257	#76-5540	#77-5546	#78-5556	#79-5625	#80-5628
#81-5664	#82-5311	#83-5396	#84-5369	#85-5510	#86-5644	#87-5722	#88-5537	#89-5636	#90-5637
#91-5549	#92-5474	#93-5514	#94-5564	#95-5612	#96-5372	#97-5358	#98-5582	#99-5589	#100-5347

Type 6 #15 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5599	#02-5697	#03-5268	#04-5569	#05-5524	#06-5517	#07-5706	#08-5564	#09-5616	#10-5715
#11-5294	#12-5284	#13-5419	#14-5644	#15-5591	#16-5690	#17-5713	#18-5411	#19-5552	#20-5525
#21-5448	#22-5440	#23-5432	#24-5315	#25-5282	#26-5408	#27-5310	#28-5459	#29-5506	#30-5555
#31-5489	#32-5447	#33-5298	#34-5397	#35-5492	#36-5325	#37-5269	#38-5654	#39-5526	#40-5433
#41-5647	#42-5505	#43-5345	#44-5477	#45-5698	#46-5383	#47-5671	#48-5279	#49-5313	#50-5400
#51-5560	#52-5503	#53-5358	#54-5646	#55-5354	#56-5360	#57-5409	#58-5530	#59-5562	#60-5370
#61-5405	#62-5444	#63-5638	#64-5689	#65-5533	#66-5595	#67-5716	#68-5264	#69-5518	#70-5652
#71-5600	#72-5661	#73-5656	#74-5337	#75-5537	#76-5372	#77-5609	#78-5460	#79-5467	#80-5338
#81-5615	#82-5657	#83-5546	#84-5679	#85-5636	#86-5258	#87-5421	#88-5323	#89-5487	#90-5699
#91-5602	#92-5322	#93-5449	#94-5470	#95-5707	#96-5471	#97-5442	#98-5385	#99-5632	#100-5628

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5556	#02-5427	#03-5558	#04-5542	#05-5713	#06-5525	#07-5320	#08-5429	#09-5627	#10-5316
#11-5554	#12-5514	#13-5342	#14-5259	#15-5621	#16-5587	#17-5544	#18-5666	#19-5280	#20-5677
#21-5723	#22-5686	#23-5583	#24-5559	#25-5337	#26-5626	#27-5665	#28-5628	#29-5274	#30-5643
#31-5373	#32-5458	#33-5425	#34-5603	#35-5335	#36-5687	#37-5629	#38-5423	#39-5322	#40-5255
#41-5673	#42-5659	#43-5377	#44-5698	#45-5574	#46-5580	#47-5269	#48-5444	#49-5683	#50-5679
#51-5594	#52-5568	#53-5455	#54-5336	#55-5623	#56-5331	#57-5488	#58-5724	#59-5363	#60-5653
#61-5490	#62-5424	#63-5611	#64-5412	#65-5581	#66-5317	#67-5298	#68-5549	#69-5614	#70-5577
#71-5610	#72-5402	#73-5498	#74-5388	#75-5608	#76-5483	#77-5668	#78-5319	#79-5263	#80-5504
#81-5615	#82-5426	#83-5398	#84-5313	#85-5547	#86-5323	#87-5616	#88-5270	#89-5419	#90-5678
#91-5411	#92-5417	#93-5328	#94-5631	#95-5329	#96-5704	#97-5716	#98-5302	#99-5562	#100-5695

Type 6 #17 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5667	#02-5403	#03-5365	#04-5604	#05-5710	#06-5420	#07-5411	#08-5357	#09-5522	#10-5711
#11-5517	#12-5582	#13-5254	#14-5475	#15-5615	#16-5540	#17-5685	#18-5590	#19-5707	#20-5545
#21-5566	#22-5702	#23-5642	#24-5529	#25-5621	#26-5302	#27-5413	#28-5658	#29-5524	#30-5623
#31-5312	#32-5345	#33-5342	#34-5605	#35-5505	#36-5682	#37-5261	#38-5285	#39-5724	#40-5704
#41-5614	#42-5431	#43-5535	#44-5255	#45-5611	#46-5405	#47-5439	#48-5414	#49-5280	#50-5497
#51-5319	#52-5267	#53-5379	#54-5690	#55-5486	#56-5561	#57-5708	#58-5657	#59-5256	#60-5477
#61-5558	#62-5648	#63-5422	#64-5636	#65-5595	#66-5359	#67-5583	#68-5673	#69-5555	#70-5277
#71-5587	#72-5337	#73-5461	#74-5718	#75-5415	#76-5258	#77-5468	#78-5360	#79-5593	#80-5275
#81-5394	#82-5688	#83-5639	#84-5269	#85-5371	#86-5278	#87-5352	#88-5717	#89-5289	#90-5396
#91-5715	#92-5507	#93-5363	#94-5559	#95-5700	#96-5329	#97-5331	#98-5336	#99-5714	#100-5516

Type 6 #18 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5275	#03-5567	#04-5342	#05-5491	#06-5723	#07-5259	#08-5447	#09-5279	#10-5358
#11-5396	#12-5276	#13-5672	#14-5680	#15-5340	#16-5461	#17-5645	#18-5452	#19-5715	#20-5712
#21-5440	#22-5347	#23-5678	#24-5605	#25-5306	#26-5388	#27-5529	#28-5512	#29-5597	#30-5664
#31-5404	#32-5421	#33-5286	#34-5718	#35-5660	#36-5585	#37-5719	#38-5280	#39-5673	#40-5685
#41-5398	#42-5691	#43-5533	#44-5278	#45-5579	#46-5714	#47-5343	#48-5410	#49-5464	#50-5345
#51-5251	#52-5325	#53-5505	#54-5321	#55-5687	#56-5301	#57-5525	#58-5595	#59-5643	#60-5492
#61-5486	#62-5457	#63-5596	#64-5500	#65-5644	#66-5346	#67-5657	#68-5710	#69-5592	#70-5721
#71-5681	#72-5386	#73-5638	#74-5498	#75-5412	#76-5593	#77-5399	#78-5435	#79-5351	#80-5382
#81-5568	#82-5402	#83-5506	#84-5647	#85-5566	#86-5623	#87-5534	#88-5443	#89-5637	#90-5484
#91-5661	#92-5502	#93-5659	#94-5617	#95-5411	#96-5425	#97-5349	#98-5295	#99-5558	#100-5368

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5517	#02-5299	#03-5513	#04-5614	#05-5656	#06-5445	#07-5457	#08-5390	#09-5353	#10-5443
#11-5404	#12-5388	#13-5424	#14-5341	#15-5336	#16-5307	#17-5528	#18-5521	#19-5462	#20-5668
#21-5616	#22-5403	#23-5561	#24-5634	#25-5658	#26-5506	#27-5274	#28-5651	#29-5510	#30-5469
#31-5357	#32-5512	#33-5387	#34-5379	#35-5360	#36-5645	#37-5511	#38-5690	#39-5547	#40-5302
#41-5534	#42-5595	#43-5467	#44-5348	#45-5320	#46-5338	#47-5539	#48-5545	#49-5499	#50-5346
#51-5425	#52-5625	#53-5620	#54-5676	#55-5704	#56-5723	#57-5664	#58-5433	#59-5464	#60-5568
#61-5394	#62-5617	#63-5250	#64-5294	#65-5548	#66-5701	#67-5266	#68-5556	#69-5639	#70-5332
#71-5533	#72-5344	#73-5536	#74-5313	#75-5679	#76-5562	#77-5695	#78-5648	#79-5583	#80-5416
#81-5687	#82-5479	#83-5622	#84-5409	#85-5665	#86-5275	#87-5363	#88-5691	#89-5450	#90-5381
#91-5456	#92-5398	#93-5496	#94-5362	#95-5402	#96-5529	#97-5431	#98-5542	#99-5581	#100-5417

Type 6 #20 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5586	#02-5600	#03-5479	#04-5626	#05-5597	#06-5471	#07-5477	#08-5450	#09-5288	#10-5539
#11-5651	#12-5541	#13-5446	#14-5478	#15-5530	#16-5525	#17-5303	#18-5366	#19-5333	#20-5688
#21-5330	#22-5590	#23-5639	#24-5432	#25-5543	#26-5369	#27-5640	#28-5709	#29-5403	#30-5662
#31-5535	#32-5552	#33-5498	#34-5652	#35-5400	#36-5609	#37-5661	#38-5343	#39-5704	#40-5628
#41-5255	#42-5483	#43-5584	#44-5569	#45-5545	#46-5680	#47-5300	#48-5388	#49-5630	#50-5480
#51-5426	#52-5253	#53-5618	#54-5337	#55-5720	#56-5686	#57-5296	#58-5304	#59-5352	#60-5562
#61-5466	#62-5602	#63-5714	#64-5673	#65-5551	#66-5380	#67-5641	#68-5367	#69-5272	#70-5353
#71-5310	#72-5325	#73-5357	#74-5305	#75-5587	#76-5629	#77-5318	#78-5502	#79-5328	#80-5648
#81-5485	#82-5531	#83-5659	#84-5410	#85-5656	#86-5438	#87-5563	#88-5315	#89-5513	#90-5598
#91-5706	#92-5453	#93-5556	#94-5256	#95-5474	#96-5258	#97-5363	#98-5624	#99-5558	#100-5262

Type 6 #21 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5612	#02-5630	#03-5433	#04-5522	#05-5441	#06-5283	#07-5310	#08-5387	#09-5685	#10-5367
#11-5559	#12-5304	#13-5512	#14-5619	#15-5666	#16-5327	#17-5607	#18-5709	#19-5476	#20-5719
#21-5536	#22-5484	#23-5324	#24-5384	#25-5322	#26-5581	#27-5568	#28-5494	#29-5338	#30-5535
#31-5331	#32-5631	#33-5351	#34-5398	#35-5294	#36-5532	#37-5379	#38-5687	#39-5571	#40-5254
#41-5376	#42-5637	#43-5589	#44-5618	#45-5501	#46-5468	#47-5580	#48-5316	#49-5636	#50-5481
#51-5419	#52-5563	#53-5450	#54-5378	#55-5556	#56-5299	#57-5449	#58-5585	#59-5440	#60-5541
#61-5298	#62-5400	#63-5285	#64-5652	#65-5678	#66-5364	#67-5574	#68-5383	#69-5673	#70-5644
#71-5633	#72-5714	#73-5410	#74-5459	#75-5490	#76-5546	#77-5362	#78-5712	#79-5427	#80-5426
#81-5483	#82-5672	#83-5640	#84-5700	#85-5329	#86-5488	#87-5711	#88-5438	#89-5487	#90-5553
#91-5691	#92-5547	#93-5354	#94-5256	#95-5657	#96-5688	#97-5562	#98-5282	#99-5573	#100-5290

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5532	#02-5347	#03-5534	#04-5627	#05-5472	#06-5452	#07-5363	#08-5597	#09-5346	#10-5373
#11-5418	#12-5415	#13-5416	#14-5658	#15-5408	#16-5593	#17-5405	#18-5401	#19-5504	#20-5526
#21-5332	#22-5333	#23-5630	#24-5524	#25-5723	#26-5258	#27-5706	#28-5494	#29-5463	#30-5467
#31-5604	#32-5718	#33-5664	#34-5632	#35-5358	#36-5603	#37-5520	#38-5586	#39-5488	#40-5651
#41-5324	#42-5455	#43-5391	#44-5430	#45-5522	#46-5381	#47-5663	#48-5322	#49-5499	#50-5344
#51-5406	#52-5606	#53-5710	#54-5297	#55-5682	#56-5449	#57-5441	#58-5259	#59-5629	#60-5464
#61-5470	#62-5594	#63-5383	#64-5493	#65-5425	#66-5476	#67-5508	#68-5550	#69-5529	#70-5544
#71-5637	#72-5578	#73-5602	#74-5666	#75-5450	#76-5252	#77-5591	#78-5319	#79-5634	#80-5720
#81-5368	#82-5310	#83-5617	#84-5674	#85-5412	#86-5511	#87-5681	#88-5273	#89-5321	#90-5512
#91-5662	#92-5404	#93-5497	#94-5695	#95-5271	#96-5587	#97-5693	#98-5569	#99-5329	#100-5507

Type 6 #23 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5716	#02-5257	#03-5287	#04-5395	#05-5560	#06-5599	#07-5264	#08-5544	#09-5494	#10-5417
#11-5584	#12-5558	#13-5640	#14-5367	#15-5536	#16-5587	#17-5613	#18-5397	#19-5721	#20-5531
#21-5404	#22-5512	#23-5630	#24-5686	#25-5639	#26-5387	#27-5274	#28-5347	#29-5447	#30-5280
#31-5601	#32-5297	#33-5595	#34-5377	#35-5421	#36-5503	#37-5644	#38-5603	#39-5594	#40-5581
#41-5307	#42-5693	#43-5418	#44-5654	#45-5296	#46-5570	#47-5578	#48-5459	#49-5250	#50-5330
#51-5709	#52-5573	#53-5523	#54-5352	#55-5453	#56-5326	#57-5480	#58-5423	#59-5574	#60-5642
#61-5346	#62-5464	#63-5540	#64-5688	#65-5513	#66-5670	#67-5283	#68-5667	#69-5259	#70-5528
#71-5390	#72-5474	#73-5436	#74-5344	#75-5700	#76-5319	#77-5612	#78-5446	#79-5675	#80-5617
#81-5449	#82-5321	#83-5401	#84-5568	#85-5373	#86-5256	#87-5389	#88-5596	#89-5678	#90-5364
#91-5484	#92-5606	#93-5317	#94-5632	#95-5426	#96-5308	#97-5320	#98-5430	#99-5432	#100-5299

Type 6 #24 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5641	#02-5358	#03-5377	#04-5411	#05-5410	#06-5617	#07-5402	#08-5279	#09-5625	#10-5514
#11-5648	#12-5337	#13-5488	#14-5702	#15-5607	#16-5349	#17-5610	#18-5356	#19-5383	#20-5334
#21-5564	#22-5390	#23-5586	#24-5405	#25-5437	#26-5463	#27-5435	#28-5387	#29-5604	#30-5436
#31-5266	#32-5272	#33-5584	#34-5273	#35-5407	#36-5687	#37-5529	#38-5579	#39-5359	#40-5695
#41-5414	#42-5440	#43-5397	#44-5714	#45-5553	#46-5654	#47-5544	#48-5684	#49-5434	#50-5324
#51-5298	#52-5690	#53-5326	#54-5693	#55-5515	#56-5255	#57-5698	#58-5403	#59-5613	#60-5569
#61-5634	#62-5462	#63-5320	#64-5595	#65-5380	#66-5368	#67-5583	#68-5666	#69-5552	#70-5699
#71-5594	#72-5700	#73-5395	#74-5258	#75-5447	#76-5616	#77-5428	#78-5420	#79-5362	#80-5306
#81-5282	#82-5615	#83-5483	#84-5401	#85-5376	#86-5457	#87-5505	#88-5369	#89-5423	#90-5536
#91-5685	#92-5267	#93-5511	#94-5496	#95-5493	#96-5715	#97-5717	#98-5722	#99-5501	#100-5677

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5309	#02-5463	#03-5350	#04-5351	#05-5538	#06-5347	#07-5477	#08-5514	#09-5658	#10-5426
#11-5564	#12-5433	#13-5386	#14-5444	#15-5417	#16-5656	#17-5328	#18-5460	#19-5298	#20-5655
#21-5410	#22-5634	#23-5590	#24-5450	#25-5315	#26-5550	#27-5623	#28-5363	#29-5404	#30-5607
#31-5661	#32-5563	#33-5397	#34-5292	#35-5602	#36-5699	#37-5555	#38-5326	#39-5308	#40-5585
#41-5577	#42-5320	#43-5654	#44-5532	#45-5522	#46-5676	#47-5423	#48-5282	#49-5705	#50-5271
#51-5624	#52-5554	#53-5485	#54-5626	#55-5472	#56-5579	#57-5711	#58-5360	#59-5445	#60-5543
#61-5627	#62-5595	#63-5713	#64-5402	#65-5540	#66-5681	#67-5497	#68-5384	#69-5714	#70-5319
#71-5657	#72-5306	#73-5519	#74-5521	#75-5508	#76-5479	#77-5411	#78-5338	#79-5289	#80-5574
#81-5680	#82-5541	#83-5498	#84-5462	#85-5367	#86-5323	#87-5333	#88-5528	#89-5454	#90-5598
#91-5381	#92-5501	#93-5276	#94-5331	#95-5369	#96-5359	#97-5650	#98-5716	#99-5677	#100-5691

Type 6 #26 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5497	#02-5690	#03-5355	#04-5689	#05-5292	#06-5478	#07-5550	#08-5271	#09-5405	#10-5694
#11-5672	#12-5304	#13-5464	#14-5664	#15-5423	#16-5608	#17-5413	#18-5580	#19-5510	#20-5446
#21-5539	#22-5650	#23-5268	#24-5494	#25-5571	#26-5397	#27-5705	#28-5274	#29-5704	#30-5364
#31-5676	#32-5589	#33-5532	#34-5402	#35-5692	#36-5369	#37-5485	#38-5700	#39-5298	#40-5346
#41-5329	#42-5607	#43-5591	#44-5430	#45-5688	#46-5475	#47-5486	#48-5455	#49-5480	#50-5401
#51-5671	#52-5586	#53-5367	#54-5620	#55-5498	#56-5525	#57-5291	#58-5267	#59-5707	#60-5440
#61-5657	#62-5699	#63-5270	#64-5641	#65-5294	#66-5345	#67-5535	#68-5443	#69-5674	#70-5461
#71-5415	#72-5530	#73-5311	#74-5479	#75-5602	#76-5634	#77-5484	#78-5358	#79-5381	#80-5368
#81-5356	#82-5252	#83-5590	#84-5451	#85-5658	#86-5514	#87-5416	#88-5659	#89-5456	#90-5667
#91-5559	#92-5442	#93-5645	#94-5332	#95-5682	#96-5622	#97-5460	#98-5420	#99-5339	#100-5698

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5464	#02-5537	#03-5414	#04-5357	#05-5473	#06-5332	#07-5526	#08-5580	#09-5540	#10-5535
#11-5292	#12-5479	#13-5333	#14-5625	#15-5389	#16-5265	#17-5671	#18-5318	#19-5523	#20-5596
#21-5319	#22-5368	#23-5644	#24-5410	#25-5687	#26-5564	#27-5275	#28-5423	#29-5471	#30-5720
#31-5660	#32-5574	#33-5501	#34-5478	#35-5283	#36-5492	#37-5494	#38-5406	#39-5598	#40-5334
#41-5382	#42-5600	#43-5377	#44-5274	#45-5399	#46-5442	#47-5561	#48-5432	#49-5543	#50-5606
#51-5513	#52-5351	#53-5604	#54-5467	#55-5628	#56-5345	#57-5617	#58-5254	#59-5395	#60-5633
#61-5307	#62-5353	#63-5358	#64-5544	#65-5599	#66-5443	#67-5702	#68-5579	#69-5591	#70-5621
#71-5496	#72-5515	#73-5445	#74-5438	#75-5463	#76-5716	#77-5620	#78-5260	#79-5252	#80-5567
#81-5590	#82-5457	#83-5559	#84-5695	#85-5284	#86-5575	#87-5663	#88-5489	#89-5261	#90-5689
#91-5277	#92-5279	#93-5557	#94-5681	#95-5465	#96-5707	#97-5566	#98-5646	#99-5359	#100-5723

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5631	#02-5415	#03-5253	#04-5435	#05-5353	#06-5721	#07-5719	#08-5625	#09-5464	#10-5473
#11-5493	#12-5337	#13-5290	#14-5668	#15-5254	#16-5653	#17-5272	#18-5257	#19-5503	#20-5480
#21-5411	#22-5434	#23-5675	#24-5409	#25-5471	#26-5304	#27-5279	#28-5269	#29-5251	#30-5682
#31-5481	#32-5459	#33-5652	#34-5529	#35-5280	#36-5389	#37-5559	#38-5602	#39-5495	#40-5360
#41-5308	#42-5537	#43-5530	#44-5724	#45-5470	#46-5359	#47-5458	#48-5521	#49-5702	#50-5637
#51-5624	#52-5352	#53-5469	#54-5401	#55-5544	#56-5484	#57-5669	#58-5500	#59-5664	#60-5595
#61-5611	#62-5463	#63-5515	#64-5262	#65-5362	#66-5638	#67-5590	#68-5343	#69-5395	#70-5487
#71-5393	#72-5422	#73-5599	#74-5628	#75-5676	#76-5663	#77-5361	#78-5571	#79-5483	#80-5291
#81-5338	#82-5378	#83-5715	#84-5501	#85-5525	#86-5460	#87-5629	#88-5615	#89-5351	#90-5555
#91-5489	#92-5421	#93-5324	#94-5265	#95-5711	#96-5592	#97-5722	#98-5514	#99-5608	#100-5479

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5590	#02-5325	#03-5703	#04-5380	#05-5641	#06-5532	#07-5255	#08-5389	#09-5343	#10-5362
#11-5569	#12-5374	#13-5457	#14-5608	#15-5612	#16-5586	#17-5393	#18-5427	#19-5685	#20-5453
#21-5293	#22-5656	#23-5628	#24-5250	#25-5524	#26-5613	#27-5689	#28-5320	#29-5364	#30-5307
#31-5600	#32-5654	#33-5519	#34-5554	#35-5513	#36-5639	#37-5522	#38-5394	#39-5544	#40-5346
#41-5609	#42-5687	#43-5462	#44-5377	#45-5576	#46-5674	#47-5353	#48-5705	#49-5386	#50-5370
#51-5430	#52-5402	#53-5341	#54-5435	#55-5658	#56-5422	#57-5580	#58-5278	#59-5567	#60-5660
#61-5274	#62-5286	#63-5487	#64-5640	#65-5579	#66-5627	#67-5344	#68-5697	#69-5313	#70-5723
#71-5588	#72-5568	#73-5330	#74-5444	#75-5501	#76-5399	#77-5575	#78-5340	#79-5661	#80-5419
#81-5428	#82-5368	#83-5467	#84-5539	#85-5515	#86-5504	#87-5663	#88-5426	#89-5614	#90-5630
#91-5259	#92-5257	#93-5322	#94-5371	#95-5546	#96-5497	#97-5355	#98-5464	#99-5645	#100-5553

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5255	#02-5673	#03-5706	#04-5570	#05-5296	#06-5349	#07-5317	#08-5389	#09-5401	#10-5508
#11-5489	#12-5480	#13-5494	#14-5434	#15-5342	#16-5334	#17-5619	#18-5392	#19-5267	#20-5611
#21-5463	#22-5424	#23-5577	#24-5332	#25-5630	#26-5540	#27-5598	#28-5687	#29-5655	#30-5263
#31-5365	#32-5546	#33-5715	#34-5534	#35-5567	#36-5522	#37-5353	#38-5616	#39-5326	#40-5547
#41-5521	#42-5668	#43-5372	#44-5495	#45-5502	#46-5553	#47-5662	#48-5454	#49-5603	#50-5688
#51-5446	#52-5283	#53-5340	#54-5500	#55-5498	#56-5379	#57-5488	#58-5390	#59-5533	#60-5444
#61-5427	#62-5470	#63-5373	#64-5659	#65-5503	#66-5625	#67-5536	#68-5515	#69-5666	#70-5314
#71-5537	#72-5302	#73-5331	#74-5555	#75-5327	#76-5393	#77-5482	#78-5300	#79-5643	#80-5512
#81-5284	#82-5318	#83-5590	#84-5476	#85-5517	#86-5344	#87-5447	#88-5602	#89-5371	#90-5299
#91-5286	#92-5678	#93-5337	#94-5437	#95-5505	#96-5694	#97-5398	#98-5297	#99-5657	#100-5313

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Type 5 #1 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	687560	77	0	0	62363	750000
2	3	12	396475	89	1616	1876	349766	750000
3	2	10	221272	67	1455	0	527139	750000
4	3	17	134197	51	1931	1390	612329	750000
5	2	12	156369	84	1854	0	591609	750000
6	3	7	46483	85	1603	1392	700267	750000
7	2	7	130433	60	1583	0	617864	750000
8	2	7	385559	52	1280	0	363057	750000
9	1	18	20909	56	0	0	729035	750000
10	2	8	566775	57	1866	0	181245	750000
11	2	17	489473	73	1496	0	258885	750000
12	3	6	590944	58	1690	1025	156167	750000
13	2	7	567012	63	1391	0	181471	750000
14	1	16	486902	64	0	0	263034	750000
15	2	17	497695	88	1110	0	251019	750000
16	1	14	619528	77	0	0	130395	750000

Type 5 #2 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	658537	73	1845	0	6138	666666
2	2	16	472549	89	1516	0	192423	666666
3	1	10	85438	74	0	0	581154	666666
4	2	17	317887	52	1988	0	346687	666666
5	1	18	348702	65	0	0	317899	666666
6	1	15	458978	63	0	0	207625	666666
7	3	10	157064	92	1330	1551	506445	666666
8	3	10	98660	71	1193	1428	565172	666666
9	3	11	422966	99	1769	1002	240632	666666
10	1	15	414547	70	0	0	252049	666666
11	2	13	369814	75	1132	0	295570	666666
12	2	20	389880	87	1062	0	275550	666666
13	2	6	117809	96	1872	0	546793	666666
14	2	8	469297	73	1447	0	195776	666666
15	1	11	559349	93	0	0	107224	666666
16	3	19	384220	65	1100	1521	279630	666666
17	1	5	46837	61	0	0	619768	666666
18	1	17	279056	92	0	0	387518	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	630495	85	1131	0	118204	750000
2	3	19	464539	95	1547	1591	282038	750000
3	1	20	707486	89	0	0	42425	750000
4	2	7	336130	89	1715	0	411977	750000
5	1	15	315502	79	0	0	434419	750000
6	2	6	15836	67	1869	0	732161	750000
7	2	14	419282	67	1041	0	329543	750000
8	1	17	538616	50	0	0	211334	750000
9	2	17	255632	52	1414	0	492850	750000
10	2	11	204255	95	1458	0	544097	750000
11	1	11	530154	81	0	0	219765	750000
12	1	11	641611	99	0	0	108290	750000
13	1	15	370534	99	0	0	379367	750000
14	3	18	14022	50	1886	1246	732696	750000
15	1	20	695105	61	0	0	54834	750000
16	3	14	631253	52	1671	1653	115267	750000

Type 5 #4 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	971265	76	0	0	119568	1090909
2	3	11	588912	89	1225	1638	498867	1090909
3	1	7	1047526	57	0	0	43326	1090909
4	3	5	600865	53	1369	1778	486738	1090909
5	2	19	258510	63	1267	0	831006	1090909
6	1	19	417912	58	0	0	672939	1090909
7	1	10	628226	69	0	0	462614	1090909
8	2	12	657543	97	1566	0	431606	1090909
9	3	12	519139	62	1661	1609	568314	1090909
10	1	17	1054420	54	0	0	36435	1090909
11	3	13	318756	100	1301	1875	768677	1090909

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Type 5 #5 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	400108	82	1653	1526	263133	666666
2	2	13	503015	92	1150	0	162317	666666
3	2	5	335565	77	1371	0	329576	666666
4	2	13	529618	77	1101	0	135793	666666
5	2	8	348932	70	1155	0	316439	666666
6	1	11	384882	53	0	0	281731	666666
7	1	9	552420	72	0	0	114174	666666
8	1	17	633650	90	0	0	32926	666666
9	1	20	545697	82	0	0	120887	666666
10	1	9	346253	66	0	0	320347	666666
11	1	12	319344	97	0	0	347225	666666
12	1	10	127712	88	0	0	538866	666666
13	3	8	1072	60	1610	1498	662306	666666
14	2	12	40447	71	1941	0	624136	666666
15	1	16	636378	64	0	0	30224	666666
16	2	12	591517	88	1244	0	73729	666666
17	1	14	50185	99	0	0	616382	666666
18	3	9	610796	82	1263	1562	52799	666666

Type 5 #6 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	719407	55	0	0	137680	857142
2	3	7	206784	78	1453	1298	647373	857142
3	2	7	848944	69	1266	0	6794	857142
4	1	20	794051	78	0	0	63013	857142
5	3	13	10319	81	1454	1059	844067	857142
6	2	16	629787	58	1862	0	225377	857142
7	1	13	398397	93	0	0	458652	857142
8	3	8	10280	60	1871	1087	843724	857142
9	2	20	500888	51	1647	0	354505	857142
10	2	17	338785	71	1906	0	516309	857142
11	3	15	697951	64	1194	1864	155941	857142
12	2	18	337700	51	1224	0	518116	857142
13	2	13	587350	80	1104	0	268528	857142
14	3	13	579663	84	1777	1051	274399	857142

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	14	297439	55	1569	1807	330598	631578
2	2	10	293219	61	1807	0	336430	631578
3	1	8	206613	93	0	0	424872	631578
4	2	14	27293	96	1156	0	602937	631578
5	3	7	340881	81	1446	1384	287624	631578
6	3	16	216988	88	1272	1129	411925	631578
7	1	16	51235	69	0	0	580274	631578
8	1	18	352656	62	0	0	278860	631578
9	2	5	78879	100	1622	0	550877	631578
10	2	12	53394	62	1527	0	576533	631578
11	2	19	20826	60	1636	0	608996	631578
12	1	7	116562	97	0	0	514919	631578
13	1	15	317105	79	0	0	314394	631578
14	1	6	621037	84	0	0	10457	631578
15	2	8	417825	75	1311	0	212292	631578
16	3	15	352861	80	1869	1579	275029	631578
17	1	9	276917	92	0	0	354569	631578
18	1	15	583278	82	0	0	48218	631578
19	2	10	95492	70	1424	0	534522	631578

Type 5 #8 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	901180	79	0	0	298741	1200000
2	2	20	668567	98	1004	0	530233	1200000
3	3	9	566404	98	1774	1962	629566	1200000
4	1	7	862040	50	0	0	337910	1200000
5	2	10	162637	91	1968	0	1035213	1200000
6	2	11	803082	93	1754	0	394978	1200000
7	2	6	178861	56	1094	0	1019933	1200000
8	2	14	450770	58	1877	0	747237	1200000
9	2	10	631564	81	1285	0	566989	1200000
10	2	18	539215	97	1686	0	658905	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	472953	59	1784	0	858478	1333333
2	3	18	690611	80	1305	1633	639544	1333333
3	1	20	855527	67	0	0	477739	1333333
4	3	14	908256	59	1363	1315	422222	1333333
5	1	6	1000560	90	0	0	332683	1333333
6	2	12	677698	52	1653	0	653878	1333333
7	3	9	1254470	88	1517	1188	75894	1333333
8	2	17	734866	65	1877	0	596460	1333333
9	3	16	1307020	79	1104	1426	23546	1333333

Type 5 #10 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	134206	80	1244	1322	862988	1000000
2	2	11	33462	63	1610	0	964802	1000000
3	3	7	640394	83	1195	1796	356366	1000000
4	3	18	497409	95	1788	1699	498819	1000000
5	3	12	558260	92	1764	1917	437783	1000000
6	1	10	507758	100	0	0	492142	1000000
7	3	5	426387	78	1759	1746	569874	1000000
8	1	19	546091	52	0	0	453857	1000000
9	3	19	568927	64	1210	1387	428284	1000000
10	3	10	519707	55	1538	1164	477426	1000000
11	1	18	413992	55	0	0	585953	1000000
12	3	13	617114	68	1701	1352	379629	1000000

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Type 5 #11 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	14	26265	96	1149	0	678276	705882
2	3	16	107137	67	1773	1862	594909	705882
3	3	19	243628	80	1276	1377	459361	705882
4	3	15	159065	98	1788	1343	543392	705882
5	2	19	417039	97	1332	0	287317	705882
6	3	8	399668	75	1194	1146	303649	705882
7	2	17	520064	64	1421	0	184269	705882
8	1	18	276922	100	0	0	428860	705882
9	2	10	360994	51	1274	0	343512	705882
10	2	8	287210	100	1917	0	416555	705882
11	3	5	148639	96	1692	1240	554023	705882
12	1	16	650467	78	0	0	55337	705882
13	1	20	414560	82	0	0	291240	705882
14	1	20	422900	66	0	0	282916	705882
15	3	16	667586	52	1661	1969	34510	705882
16	2	14	577169	67	1610	0	126969	705882
17	1	9	218063	90	0	0	487729	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	13	400454	82	0	0	266130	666666
2	2	14	163729	60	1640	0	501177	666666
3	3	5	161494	55	1075	1787	502145	666666
4	1	11	188115	79	0	0	478472	666666
5	3	9	82944	84	1953	1063	580454	666666
6	3	13	78469	83	1745	1716	584487	666666
7	3	7	512734	66	1404	1384	150946	666666
8	2	16	66238	53	1461	0	598861	666666
9	2	18	172874	53	1543	0	492143	666666
10	3	15	1177	68	1456	1408	662421	666666
11	2	19	328595	55	1694	0	336267	666666
12	2	13	595893	82	1042	0	69567	666666
13	2	6	600074	89	1697	0	64717	666666
14	2	11	221840	93	1193	0	443447	666666
15	2	14	585125	70	1889	0	79512	666666
16	1	15	581289	79	0	0	85298	666666
17	1	9	473573	55	0	0	193038	666666
18	3	5	184580	95	1524	1690	478587	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	557513	57	1204	0	72747	631578
2	1	18	225635	86	0	0	405857	631578
3	2	8	46944	75	1263	0	583221	631578
4	2	13	512283	51	1993	0	117200	631578
5	1	20	435386	95	0	0	196097	631578
6	3	9	508618	90	1067	1119	120504	631578
7	3	7	568546	93	1131	1286	60336	631578
8	2	10	369712	100	1003	0	260663	631578
9	2	9	421007	87	1478	0	208919	631578
10	3	15	318095	100	1560	1858	309765	631578
11	2	5	278534	94	1013	0	351843	631578
12	2	11	142305	78	1615	0	487502	631578
13	2	13	213592	51	1535	0	416349	631578
14	1	7	14103	99	0	0	617376	631578
15	1	20	143557	59	0	0	487962	631578
16	3	16	571364	58	1211	1198	57631	631578
17	1	13	600142	72	0	0	31364	631578
18	2	9	171700	66	1123	0	458623	631578
19	2	12	244814	98	1949	0	384619	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	781000	85	1943	1329	215473	1000000
2	1	13	819289	73	0	0	180638	1000000
3	1	15	237220	77	0	0	762703	1000000
4	3	9	340555	87	1352	1508	656324	1000000
5	3	6	46708	52	1169	1209	950758	1000000
6	3	16	234414	85	1074	1599	762658	1000000
7	2	19	920685	94	1460	0	77667	1000000
8	1	6	253128	94	0	0	746778	1000000
9	3	7	641230	51	1018	1783	355816	1000000
10	3	16	439853	71	1695	1087	557152	1000000
11	1	18	609972	78	0	0	389950	1000000
12	2	9	314495	87	1811	0	683520	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	550621	61	1945	0	153194	705882
2	2	18	340208	70	1986	0	363548	705882
3	2	18	674203	54	1023	0	30548	705882
4	1	11	61013	71	0	0	644798	705882
5	1	11	360783	100	0	0	344999	705882
6	3	9	220371	78	1026	1851	482400	705882
7	2	10	147270	79	1938	0	556516	705882
8	2	19	605871	96	1838	0	97981	705882
9	2	19	425310	51	1710	0	278760	705882
10	1	16	583300	98	0	0	122484	705882
11	2	9	510089	73	1879	0	193768	705882
12	1	6	500759	89	0	0	205034	705882
13	1	12	235946	69	0	0	469867	705882
14	2	12	48928	75	1897	0	654907	705882
15	1	12	32711	81	0	0	673090	705882
16	1	13	396156	80	0	0	309646	705882
17	1	15	640263	54	0	0	65565	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	8	603089	78	1197	0	101440	705882
2	1	14	642799	86	0	0	62997	705882
3	2	8	314058	74	1637	0	390039	705882
4	2	12	182091	59	1394	0	522279	705882
5	3	17	426797	100	1121	1362	276302	705882
6	1	10	115342	86	0	0	590454	705882
7	3	11	560854	84	1803	1558	141415	705882
8	3	10	132613	56	1650	1223	570228	705882
9	2	7	595060	62	1991	0	108707	705882
10	2	7	555837	57	1370	0	148561	705882
11	3	8	308980	70	1747	1785	393160	705882
12	3	14	298911	80	1510	1372	403849	705882
13	1	5	281204	88	0	0	424590	705882
14	1	12	40126	83	0	0	665673	705882
15	1	5	366111	87	0	0	339684	705882
16	2	20	536355	79	1372	0	167997	705882
17	2	7	684305	79	1793	0	19626	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	8207	80	0	0	591713	600000
2	2	17	426696	65	1030	0	172144	600000
3	3	6	266700	52	1420	1930	329794	600000
4	2	16	394974	75	1313	0	203563	600000
5	3	15	297075	69	1239	1216	300263	600000
6	2	20	119914	92	1936	0	477966	600000
7	2	17	476511	59	1057	0	122314	600000
8	1	20	456625	82	0	0	143293	600000
9	2	10	270654	86	1702	0	327472	600000
10	2	12	88143	76	1314	0	510391	600000
11	1	12	187310	73	0	0	412617	600000
12	1	19	343040	81	0	0	256879	600000
13	3	18	463378	100	1930	1064	133328	600000
14	2	19	521931	71	1651	0	76276	600000
15	2	18	330427	62	1731	0	267718	600000
16	1	5	587222	62	0	0	12716	600000
17	3	20	489211	87	1024	1514	107990	600000
18	3	7	256686	87	1866	1729	339458	600000
19	3	18	263380	85	1993	1932	332440	600000
20	2	6	338814	77	1029	0	260003	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	462842	83	1217	0	167353	631578
2	3	17	493019	51	1574	1943	134889	631578
3	1	17	262227	50	0	0	369301	631578
4	1	19	170623	96	0	0	460859	631578
5	1	12	490865	97	0	0	140616	631578
6	2	16	533156	51	1621	0	96699	631578
7	2	19	108223	75	1757	0	521448	631578
8	1	18	574489	73	0	0	57016	631578
9	2	8	581623	50	1842	0	48013	631578
10	3	19	79836	97	1777	1984	547690	631578
11	1	15	130089	70	0	0	501419	631578
12	3	20	230926	76	1127	1886	397411	631578
13	1	9	111916	100	0	0	519562	631578
14	1	5	17657	53	0	0	613868	631578
15	3	10	175524	96	1564	1335	452867	631578
16	3	8	531254	52	1999	1585	96584	631578
17	2	17	516349	62	1493	0	113612	631578
18	1	15	630218	94	0	0	1266	631578
19	2	10	341311	57	1966	0	288187	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	650931	96	0	0	272049	923076
2	3	19	715305	94	1889	1078	204522	923076
3	2	10	658881	53	1327	0	262762	923076
4	1	13	36475	98	0	0	886503	923076
5	3	8	32641	98	1814	1357	886970	923076
6	1	5	216239	68	0	0	706769	923076
7	3	14	803754	51	1794	1831	115544	923076
8	1	9	734850	77	0	0	188149	923076
9	3	10	328188	88	1676	1716	591232	923076
10	1	10	261299	77	0	0	661700	923076
11	2	17	742285	60	1926	0	178745	923076
12	2	6	617243	88	1306	0	304351	923076
13	2	18	301951	76	1654	0	619319	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	13	541306	63	1453	1590	161344	705882
2	2	6	409483	88	1988	0	294235	705882
3	2	5	461891	54	1921	0	241962	705882
4	1	19	385379	88	0	0	320415	705882
5	1	20	228848	84	0	0	476950	705882
6	1	8	440240	50	0	0	265592	705882
7	1	19	498387	72	0	0	207423	705882
8	2	12	10366	98	1841	0	693479	705882
9	3	14	598770	85	1548	1039	104270	705882
10	3	8	527037	97	1008	1306	176240	705882
11	3	6	364449	76	1762	1782	337661	705882
12	1	8	240166	64	0	0	465652	705882
13	2	5	440881	77	1551	0	263296	705882
14	1	8	97144	94	0	0	608644	705882
15	2	15	37838	54	1097	0	666839	705882
16	1	8	579520	100	0	0	126262	705882
17	1	19	7284	70	0	0	698528	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	19	337420	62	1790	1945	258659	600000
2	2	13	338755	65	1822	0	259293	600000
3	1	13	292933	51	0	0	307016	600000
4	1	5	584976	87	0	0	14937	600000
5	3	15	31167	90	1303	1415	565845	600000
6	2	10	70384	89	1370	0	528068	600000
7	3	13	179629	71	1606	1158	417394	600000
8	3	19	122843	65	1654	1697	473611	600000
9	2	13	170971	91	1932	0	426915	600000
10	2	14	210054	86	1443	0	388331	600000
11	3	7	310089	57	1204	1947	286589	600000
12	3	17	260275	75	1119	1932	336449	600000
13	1	13	257727	57	0	0	342216	600000
14	2	13	70360	59	1424	0	528098	600000
15	1	14	86327	58	0	0	513615	600000
16	2	6	180030	95	1153	0	418627	600000
17	2	15	286861	89	1442	0	311519	600000
18	2	20	102489	74	1354	0	496009	600000
19	2	18	164134	71	1578	0	434146	600000
20	1	11	222128	90	0	0	377782	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	12026	76	0	0	619476	631578
2	1	20	339895	81	0	0	291602	631578
3	1	15	389671	73	0	0	241834	631578
4	2	13	480067	74	1157	0	150206	631578
5	2	7	253310	83	1954	0	376148	631578
6	3	18	374735	68	1691	1451	253497	631578
7	1	16	314171	52	0	0	317355	631578
8	3	7	412001	65	1091	1714	216577	631578
9	1	12	591902	93	0	0	39583	631578
10	3	13	244624	95	1948	1075	383646	631578
11	1	10	128817	55	0	0	502706	631578
12	3	19	437982	61	1724	1689	190000	631578
13	1	7	232900	77	0	0	398601	631578
14	1	17	87037	50	0	0	544491	631578
15	3	9	66773	52	1415	1443	561791	631578
16	2	15	320899	91	1016	0	309481	631578
17	3	19	330175	92	1616	1061	298450	631578
18	1	12	489606	87	0	0	141885	631578
19	2	12	10272	70	1403	0	619763	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	758525	85	1717	0	96730	857142
2	1	6	18464	70	0	0	838608	857142
3	1	15	190080	83	0	0	666979	857142
4	3	13	637030	96	1886	1215	216723	857142
5	3	19	16567	62	1109	1844	837436	857142
6	1	10	297103	64	0	0	559975	857142
7	2	5	522064	93	1427	0	333465	857142
8	3	14	701284	56	1299	1622	152769	857142
9	2	14	743227	92	1980	0	111751	857142
10	2	15	832699	75	1860	0	22433	857142
11	2	15	212898	61	1146	0	642976	857142
12	3	8	717118	79	1698	1607	136482	857142
13	1	10	192513	87	0	0	664542	857142
14	2	14	682077	62	1114	0	173827	857142

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	248807	80	1441	0	349592	600000
2	1	20	295603	56	0	0	304341	600000
3	3	13	371603	81	1373	1149	225632	600000
4	2	10	322883	64	1972	0	275017	600000
5	2	5	235386	80	1981	0	362473	600000
6	1	17	135564	61	0	0	464375	600000
7	1	13	37657	95	0	0	562248	600000
8	1	15	438848	97	0	0	161055	600000
9	3	11	122417	92	1449	1269	474589	600000
10	3	13	359789	61	1361	1214	237453	600000
11	1	9	85420	99	0	0	514481	600000
12	1	20	346353	80	0	0	253567	600000
13	3	10	447020	52	1100	1375	150349	600000
14	1	6	263991	95	0	0	335914	600000
15	2	20	343964	61	1625	0	254289	600000
16	2	6	237547	78	1083	0	361214	600000
17	1	18	441674	88	0	0	158238	600000
18	1	20	187836	57	0	0	412107	600000
19	2	17	561970	70	1428	0	36462	600000
20	1	15	308707	90	0	0	291203	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	947638	76	0	0	52286	1000000
2	1	5	987980	54	0	0	11966	1000000
3	2	11	578477	83	1722	0	419635	1000000
4	1	14	392500	76	0	0	607424	1000000
5	1	14	82203	59	0	0	917738	1000000
6	1	19	240245	91	0	0	759664	1000000
7	2	19	913754	82	1286	0	84796	1000000
8	3	5	561153	96	1254	1016	436289	1000000
9	2	14	722372	62	1768	0	275736	1000000
10	1	9	921487	77	0	0	78436	1000000
11	3	15	669985	92	1915	1351	326473	1000000
12	2	19	850578	74	1226	0	148048	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	12	323667	86	0	0	382129	705882
2	1	16	582820	85	0	0	122977	705882
3	2	10	669515	86	1149	0	35046	705882
4	1	14	294925	57	0	0	410900	705882
5	3	16	224059	52	1534	1979	478154	705882
6	3	5	164985	100	1936	1242	537419	705882
7	2	5	599728	54	1165	0	104881	705882
8	1	6	218507	77	0	0	487298	705882
9	2	18	314266	66	1450	0	390034	705882
10	1	12	680796	75	0	0	25011	705882
11	1	5	38754	76	0	0	667052	705882
12	1	7	125443	58	0	0	580381	705882
13	1	15	327789	69	0	0	378024	705882
14	1	12	417037	89	0	0	288756	705882
15	1	9	694571	81	0	0	11230	705882
16	1	15	330934	94	0	0	374854	705882
17	1	16	613998	61	0	0	91823	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	55450	55	1503	0	1276270	1333333
2	3	8	1135712	87	1388	1007	194965	1333333
3	1	8	188365	84	0	0	1144884	1333333
4	2	13	476641	93	1562	0	854944	1333333
5	3	14	1151409	71	1204	1507	179000	1333333
6	1	13	1262107	95	0	0	71131	1333333
7	3	9	376298	72	1094	1581	954144	1333333
8	1	5	1332805	99	0	0	429	1333333
9	3	15	1301207	69	1619	1444	28856	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	148805	74	1263	1679	771107	923076
2	2	6	118118	61	1518	0	803318	923076
3	3	12	406270	58	1835	1661	513136	923076
4	1	16	534662	70	0	0	388344	923076
5	2	7	463609	93	1884	0	457397	923076
6	2	12	892253	81	1771	0	28890	923076
7	3	12	493815	76	1629	1407	425997	923076
8	3	9	425669	58	1778	1870	493585	923076
9	3	20	831426	60	1868	1532	88070	923076
10	3	12	779211	60	1041	1262	141382	923076
11	1	19	349841	81	0	0	573154	923076
12	1	19	685119	80	0	0	237877	923076
13	2	10	678568	78	1468	0	242884	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	17	76566	56	1991	0	587997	666666
2	3	7	609960	86	1093	1929	53426	666666
3	2	16	378550	51	1766	0	286248	666666
4	2	9	383886	86	1593	0	281015	666666
5	3	9	586202	83	1994	1689	76532	666666
6	1	8	553003	55	0	0	113608	666666
7	2	16	393553	56	1476	0	271525	666666
8	2	19	91161	73	1323	0	574036	666666
9	3	20	377339	77	1460	1540	286096	666666
10	1	17	26731	99	0	0	639836	666666
11	2	7	430720	60	1261	0	234565	666666
12	2	20	36272	73	1426	0	628822	666666
13	2	19	281429	52	1099	0	384034	666666
14	2	8	83999	67	1174	0	581359	666666
15	1	20	304163	90	0	0	362413	666666
16	3	16	79812	62	1845	1453	583370	666666
17	3	10	196013	57	1175	1179	468128	666666
18	3	18	312287	72	1115	1990	351058	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	18	560244	78	0	0	296820	857142
2	3	5	684896	51	1232	1940	168921	857142
3	2	18	587648	100	1257	0	268037	857142
4	2	17	465771	70	1609	0	389622	857142
5	1	11	600994	67	0	0	256081	857142
6	3	7	349786	96	1517	1905	503646	857142
7	1	14	251178	56	0	0	605908	857142
8	3	18	689842	95	1595	1828	163592	857142
9	2	17	587737	95	1349	0	267866	857142
10	1	5	258166	66	0	0	598910	857142
11	3	10	165533	71	1380	1927	688089	857142
12	3	7	775356	56	1951	1942	77725	857142
13	2	13	440076	66	1744	0	415190	857142
14	2	14	645607	78	1786	0	209593	857142

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Type 6 #1 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5632	#02-5706	#03-5630	#04-5309	#05-5448	#06-5525	#07-5288	#08-5256	#09-5500	#10-5533
#11-5292	#12-5352	#13-5274	#14-5715	#15-5597	#16-5609	#17-5555	#18-5297	#19-5608	#20-5618
#21-5568	#22-5556	#23-5670	#24-5677	#25-5516	#26-5362	#27-5537	#28-5331	#29-5604	#30-5466
#31-5494	#32-5296	#33-5546	#34-5424	#35-5411	#36-5270	#37-5316	#38-5450	#39-5413	#40-5638
#41-5393	#42-5381	#43-5510	#44-5610	#45-5622	#46-5470	#47-5642	#48-5254	#49-5290	#50-5326
#51-5285	#52-5678	#53-5357	#54-5657	#55-5412	#56-5476	#57-5649	#58-5620	#59-5551	#60-5582
#61-5703	#62-5418	#63-5422	#64-5333	#65-5650	#66-5403	#67-5447	#68-5598	#69-5501	#70-5355
#71-5507	#72-5385	#73-5576	#74-5531	#75-5446	#76-5388	#77-5548	#78-5490	#79-5255	#80-5572
#81-5522	#82-5686	#83-5723	#84-5519	#85-5392	#86-5554	#87-5489	#88-5337	#89-5536	#90-5342
#91-5558	#92-5526	#93-5697	#94-5317	#95-5445	#96-5514	#97-5695	#98-5502	#99-5639	#100-5560

Type 6 #2 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5669	#02-5453	#03-5639	#04-5510	#05-5252	#06-5342	#07-5697	#08-5672	#09-5283	#10-5486
#11-5378	#12-5441	#13-5449	#14-5328	#15-5359	#16-5525	#17-5268	#18-5676	#19-5722	#20-5706
#21-5484	#22-5698	#23-5645	#24-5259	#25-5321	#26-5353	#27-5466	#28-5500	#29-5611	#30-5657
#31-5699	#32-5414	#33-5412	#34-5575	#35-5663	#36-5640	#37-5703	#38-5334	#39-5443	#40-5430
#41-5394	#42-5524	#43-5290	#44-5568	#45-5601	#46-5720	#47-5302	#48-5405	#49-5419	#50-5688
#51-5550	#52-5540	#53-5326	#54-5696	#55-5532	#56-5629	#57-5439	#58-5624	#59-5708	#60-5480
#61-5422	#62-5397	#63-5553	#64-5403	#65-5276	#66-5287	#67-5478	#68-5420	#69-5609	#70-5289
#71-5591	#72-5529	#73-5526	#74-5340	#75-5423	#76-5604	#77-5415	#78-5444	#79-5357	#80-5306
#81-5311	#82-5330	#83-5376	#84-5694	#85-5398	#86-5599	#87-5335	#88-5603	#89-5380	#90-5261
#91-5514	#92-5435	#93-5460	#94-5675	#95-5461	#96-5574	#97-5683	#98-5549	#99-5709	#100-5534

Type 6 #3 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5444	#02-5347	#03-5271	#04-5263	#05-5711	#06-5522	#07-5652	#08-5463	#09-5719	#10-5516
#11-5651	#12-5419	#13-5341	#14-5270	#15-5584	#16-5255	#17-5402	#18-5676	#19-5599	#20-5289
#21-5598	#22-5499	#23-5406	#24-5318	#25-5575	#26-5367	#27-5297	#28-5393	#29-5251	#30-5595
#31-5398	#32-5482	#33-5326	#34-5520	#35-5657	#36-5597	#37-5377	#38-5585	#39-5349	#40-5331
#41-5452	#42-5523	#43-5643	#44-5533	#45-5506	#46-5605	#47-5355	#48-5602	#49-5409	#50-5422
#51-5257	#52-5674	#53-5670	#54-5661	#55-5669	#56-5665	#57-5677	#58-5413	#59-5593	#60-5475
#61-5509	#62-5462	#63-5373	#64-5368	#65-5342	#66-5546	#67-5338	#68-5541	#69-5576	#70-5518
#71-5561	#72-5325	#73-5704	#74-5488	#75-5319	#76-5487	#77-5666	#78-5515	#79-5566	#80-5423
#81-5390	#82-5532	#83-5380	#84-5712	#85-5656	#86-5424	#87-5481	#88-5581	#89-5667	#90-5310
#91-5396	#92-5524	#93-5364	#94-5309	#95-5266	#96-5616	#97-5405	#98-5359	#99-5586	#100-5690

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Type 6 #4 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5426	#02-5417	#03-5343	#04-5355	#05-5533	#06-5719	#07-5621	#08-5675	#09-5702	#10-5611
#11-5686	#12-5687	#13-5351	#14-5305	#15-5427	#16-5368	#17-5344	#18-5662	#19-5618	#20-5264
#21-5557	#22-5688	#23-5395	#24-5631	#25-5428	#26-5649	#27-5624	#28-5283	#29-5542	#30-5709
#31-5376	#32-5271	#33-5722	#34-5272	#35-5479	#36-5257	#37-5328	#38-5375	#39-5297	#40-5673
#41-5414	#42-5446	#43-5547	#44-5477	#45-5451	#46-5347	#47-5640	#48-5560	#49-5354	#50-5487
#51-5312	#52-5468	#53-5465	#54-5572	#55-5382	#56-5463	#57-5437	#58-5652	#59-5608	#60-5345
#61-5587	#62-5383	#63-5717	#64-5484	#65-5664	#66-5689	#67-5550	#68-5420	#69-5289	#70-5693
#71-5614	#72-5670	#73-5574	#74-5361	#75-5390	#76-5643	#77-5429	#78-5331	#79-5259	#80-5313
#81-5654	#82-5647	#83-5633	#84-5531	#85-5400	#86-5266	#87-5616	#88-5448	#89-5577	#90-5552
#91-5554	#92-5511	#93-5562	#94-5260	#95-5659	#96-5447	#97-5579	#98-5520	#99-5322	#100-5353

Type 6 #5 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5257	#02-5571	#03-5599	#04-5282	#05-5657	#06-5327	#07-5320	#08-5576	#09-5383	#10-5539
#11-5438	#12-5533	#13-5435	#14-5398	#15-5495	#16-5450	#17-5342	#18-5271	#19-5297	#20-5561
#21-5650	#22-5643	#23-5673	#24-5422	#25-5302	#26-5719	#27-5583	#28-5553	#29-5303	#30-5261
#31-5402	#32-5593	#33-5668	#34-5606	#35-5609	#36-5602	#37-5544	#38-5619	#39-5710	#40-5483
#41-5390	#42-5377	#43-5568	#44-5373	#45-5451	#46-5474	#47-5298	#48-5573	#49-5379	#50-5427
#51-5701	#52-5698	#53-5486	#54-5339	#55-5622	#56-5704	#57-5663	#58-5469	#59-5492	#60-5522
#61-5372	#62-5386	#63-5570	#64-5590	#65-5554	#66-5513	#67-5617	#68-5636	#69-5523	#70-5376
#71-5312	#72-5510	#73-5515	#74-5354	#75-5534	#76-5649	#77-5559	#78-5426	#79-5432	#80-5428
#81-5519	#82-5361	#83-5565	#84-5681	#85-5490	#86-5716	#87-5592	#88-5255	#89-5527	#90-5586
#91-5644	#92-5680	#93-5468	#94-5629	#95-5574	#96-5408	#97-5642	#98-5549	#99-5518	#100-5378

Type 6 #6 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5378	#02-5417	#03-5660	#04-5512	#05-5598	#06-5538	#07-5685	#08-5675	#09-5407	#10-5375
#11-5719	#12-5638	#13-5524	#14-5683	#15-5419	#16-5546	#17-5335	#18-5642	#19-5509	#20-5647
#21-5496	#22-5714	#23-5575	#24-5274	#25-5431	#26-5654	#27-5576	#28-5708	#29-5510	#30-5695
#31-5436	#32-5707	#33-5513	#34-5555	#35-5454	#36-5442	#37-5472	#38-5429	#39-5519	#40-5515
#41-5291	#42-5668	#43-5671	#44-5404	#45-5339	#46-5322	#47-5250	#48-5289	#49-5595	#50-5607
#51-5389	#52-5567	#53-5636	#54-5487	#55-5416	#56-5608	#57-5358	#58-5692	#59-5383	#60-5590
#61-5273	#62-5452	#63-5541	#64-5631	#65-5716	#66-5606	#67-5317	#68-5425	#69-5644	#70-5535
#71-5306	#72-5483	#73-5421	#74-5618	#75-5676	#76-5655	#77-5565	#78-5350	#79-5296	#80-5643
#81-5691	#82-5552	#83-5558	#84-5363	#85-5609	#86-5295	#87-5653	#88-5492	#89-5563	#90-5376
#91-5424	#92-5498	#93-5348	#94-5441	#95-5327	#96-5697	#97-5688	#98-5578	#99-5403	#100-5505

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Type 6 #7 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5653	#02-5624	#03-5661	#04-5323	#05-5432	#06-5330	#07-5342	#08-5612	#09-5441	#10-5450
#11-5684	#12-5322	#13-5639	#14-5345	#15-5483	#16-5312	#17-5284	#18-5489	#19-5377	#20-5715
#21-5393	#22-5361	#23-5534	#24-5648	#25-5520	#26-5484	#27-5431	#28-5683	#29-5396	#30-5386
#31-5442	#32-5411	#33-5490	#34-5436	#35-5623	#36-5659	#37-5427	#38-5536	#39-5588	#40-5572
#41-5399	#42-5676	#43-5699	#44-5539	#45-5275	#46-5526	#47-5707	#48-5463	#49-5357	#50-5339
#51-5382	#52-5412	#53-5542	#54-5263	#55-5527	#56-5672	#57-5383	#58-5465	#59-5305	#60-5257
#61-5523	#62-5557	#63-5453	#64-5446	#65-5548	#66-5609	#67-5473	#68-5625	#69-5530	#70-5566
#71-5426	#72-5560	#73-5359	#74-5495	#75-5449	#76-5469	#77-5289	#78-5457	#79-5353	#80-5278
#81-5328	#82-5324	#83-5569	#84-5414	#85-5259	#86-5641	#87-5673	#88-5265	#89-5460	#90-5604
#91-5691	#92-5266	#93-5511	#94-5472	#95-5430	#96-5438	#97-5577	#98-5571	#99-5644	#100-5366

Type 6 #8 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5504	#02-5629	#03-5282	#04-5714	#05-5424	#06-5638	#07-5426	#08-5572	#09-5628	#10-5494
#11-5479	#12-5379	#13-5365	#14-5704	#15-5445	#16-5464	#17-5709	#18-5581	#19-5550	#20-5706
#21-5546	#22-5593	#23-5342	#24-5302	#25-5610	#26-5663	#27-5555	#28-5541	#29-5276	#30-5640
#31-5425	#32-5481	#33-5405	#34-5689	#35-5315	#36-5509	#37-5701	#38-5652	#39-5499	#40-5351
#41-5284	#42-5313	#43-5496	#44-5688	#45-5668	#46-5395	#47-5660	#48-5691	#49-5453	#50-5721
#51-5270	#52-5662	#53-5545	#54-5635	#55-5536	#56-5353	#57-5486	#58-5333	#59-5713	#60-5318
#61-5722	#62-5698	#63-5401	#64-5661	#65-5487	#66-5307	#67-5331	#68-5448	#69-5672	#70-5513
#71-5530	#72-5571	#73-5338	#74-5666	#75-5517	#76-5619	#77-5515	#78-5309	#79-5436	#80-5429
#81-5461	#82-5467	#83-5394	#84-5404	#85-5548	#86-5262	#87-5268	#88-5399	#89-5324	#90-5427
#91-5694	#92-5719	#93-5271	#94-5340	#95-5454	#96-5396	#97-5639	#98-5547	#99-5715	#100-5281

Type 6 #9 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5355	#02-5689	#03-5615	#04-5411	#05-5693	#06-5439	#07-5344	#08-5485	#09-5527	#10-5614
#11-5511	#12-5480	#13-5256	#14-5484	#15-5687	#16-5489	#17-5319	#18-5430	#19-5523	#20-5302
#21-5455	#22-5393	#23-5372	#24-5697	#25-5597	#26-5424	#27-5580	#28-5289	#29-5514	#30-5638
#31-5477	#32-5363	#33-5299	#34-5258	#35-5356	#36-5386	#37-5293	#38-5553	#39-5304	#40-5701
#41-5522	#42-5538	#43-5463	#44-5712	#45-5512	#46-5378	#47-5690	#48-5637	#49-5570	#50-5367
#51-5442	#52-5703	#53-5624	#54-5546	#55-5493	#56-5420	#57-5566	#58-5645	#59-5630	#60-5487
#61-5349	#62-5253	#63-5618	#64-5435	#65-5678	#66-5383	#67-5347	#68-5275	#69-5601	#70-5468
#71-5325	#72-5658	#73-5666	#74-5483	#75-5536	#76-5335	#77-5296	#78-5377	#79-5669	#80-5521
#81-5284	#82-5384	#83-5399	#84-5437	#85-5587	#86-5671	#87-5598	#88-5320	#89-5438	#90-5557
#91-5460	#92-5326	#93-5539	#94-5545	#95-5490	#96-5698	#97-5628	#98-5691	#99-5551	#100-5681

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Type 6 #10 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5609	#02-5480	#03-5598	#04-5265	#05-5360	#06-5405	#07-5326	#08-5694	#09-5484	#10-5285
#11-5490	#12-5520	#13-5400	#14-5401	#15-5613	#16-5334	#17-5255	#18-5624	#19-5391	#20-5358
#21-5272	#22-5441	#23-5258	#24-5596	#25-5307	#26-5562	#27-5373	#28-5280	#29-5310	#30-5481
#31-5433	#32-5471	#33-5715	#34-5714	#35-5510	#36-5305	#37-5649	#38-5282	#39-5491	#40-5585
#41-5291	#42-5658	#43-5286	#44-5389	#45-5393	#46-5602	#47-5614	#48-5623	#49-5316	#50-5549
#51-5442	#52-5417	#53-5251	#54-5682	#55-5522	#56-5281	#57-5295	#58-5633	#59-5252	#60-5576
#61-5269	#62-5410	#63-5412	#64-5381	#65-5674	#66-5700	#67-5506	#68-5581	#69-5692	#70-5662
#71-5271	#72-5423	#73-5705	#74-5403	#75-5421	#76-5583	#77-5367	#78-5647	#79-5568	#80-5306
#81-5546	#82-5260	#83-5508	#84-5347	#85-5376	#86-5435	#87-5582	#88-5439	#89-5639	#90-5527
#91-5703	#92-5470	#93-5315	#94-5673	#95-5340	#96-5440	#97-5565	#98-5402	#99-5560	#100-5503

Type 6 #11 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5313	#02-5661	#03-5348	#04-5301	#05-5617	#06-5461	#07-5394	#08-5459	#09-5347	#10-5641
#11-5354	#12-5590	#13-5371	#14-5290	#15-5576	#16-5573	#17-5357	#18-5416	#19-5648	#20-5724
#21-5503	#22-5273	#23-5468	#24-5445	#25-5250	#26-5657	#27-5356	#28-5634	#29-5276	#30-5456
#31-5252	#32-5629	#33-5711	#34-5481	#35-5411	#36-5278	#37-5675	#38-5543	#39-5437	#40-5704
#41-5542	#42-5611	#43-5599	#44-5364	#45-5275	#46-5346	#47-5492	#48-5333	#49-5399	#50-5478
#51-5560	#52-5442	#53-5628	#54-5300	#55-5684	#56-5484	#57-5432	#58-5616	#59-5638	#60-5449
#61-5604	#62-5615	#63-5569	#64-5415	#65-5545	#66-5407	#67-5597	#68-5527	#69-5536	#70-5523
#71-5455	#72-5582	#73-5570	#74-5610	#75-5559	#76-5331	#77-5538	#78-5509	#79-5372	#80-5577
#81-5401	#82-5400	#83-5480	#84-5404	#85-5694	#86-5375	#87-5624	#88-5583	#89-5267	#90-5678
#91-5522	#92-5651	#93-5697	#94-5485	#95-5458	#96-5430	#97-5655	#98-5672	#99-5526	#100-5452

Type 6 #12 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5559	#02-5584	#03-5307	#04-5415	#05-5375	#06-5272	#07-5670	#08-5648	#09-5493	#10-5311
#11-5298	#12-5453	#13-5384	#14-5414	#15-5446	#16-5419	#17-5507	#18-5264	#19-5510	#20-5583
#21-5251	#22-5529	#23-5610	#24-5420	#25-5374	#26-5351	#27-5626	#28-5607	#29-5561	#30-5301
#31-5450	#32-5377	#33-5278	#34-5570	#35-5359	#36-5317	#37-5458	#38-5719	#39-5257	#40-5598
#41-5407	#42-5636	#43-5282	#44-5323	#45-5265	#46-5459	#47-5502	#48-5393	#49-5512	#50-5279
#51-5699	#52-5611	#53-5290	#54-5274	#55-5371	#56-5312	#57-5336	#58-5297	#59-5260	#60-5573
#61-5325	#62-5355	#63-5569	#64-5337	#65-5352	#66-5299	#67-5530	#68-5515	#69-5576	#70-5378
#71-5319	#72-5342	#73-5277	#74-5398	#75-5309	#76-5302	#77-5513	#78-5284	#79-5687	#80-5552
#81-5540	#82-5431	#83-5417	#84-5434	#85-5669	#86-5511	#87-5360	#88-5625	#89-5503	#90-5681
#91-5692	#92-5421	#93-5372	#94-5400	#95-5344	#96-5706	#97-5624	#98-5563	#99-5322	#100-5633

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Type 6 #13 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5724	#02-5542	#03-5673	#04-5722	#05-5485	#06-5639	#07-5277	#08-5720	#09-5471	#10-5538
#11-5363	#12-5528	#13-5278	#14-5677	#15-5646	#16-5606	#17-5346	#18-5642	#19-5631	#20-5591
#21-5261	#22-5323	#23-5540	#24-5385	#25-5309	#26-5439	#27-5276	#28-5634	#29-5683	#30-5531
#31-5373	#32-5480	#33-5632	#34-5384	#35-5613	#36-5469	#37-5437	#38-5280	#39-5483	#40-5364
#41-5404	#42-5690	#43-5568	#44-5414	#45-5392	#46-5419	#47-5479	#48-5463	#49-5610	#50-5707
#51-5656	#52-5455	#53-5621	#54-5651	#55-5251	#56-5662	#57-5295	#58-5612	#59-5368	#60-5286
#61-5665	#62-5403	#63-5714	#64-5297	#65-5371	#66-5282	#67-5386	#68-5529	#69-5601	#70-5358
#71-5644	#72-5575	#73-5619	#74-5581	#75-5470	#76-5645	#77-5402	#78-5442	#79-5274	#80-5458
#81-5611	#82-5499	#83-5317	#84-5365	#85-5327	#86-5537	#87-5578	#88-5367	#89-5271	#90-5602
#91-5446	#92-5326	#93-5701	#94-5428	#95-5305	#96-5347	#97-5256	#98-5401	#99-5293	#100-5723

Type 6 #14 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5280	#02-5688	#03-5541	#04-5269	#05-5250	#06-5522	#07-5273	#08-5360	#09-5333	#10-5395
#11-5455	#12-5384	#13-5461	#14-5458	#15-5717	#16-5544	#17-5430	#18-5288	#19-5689	#20-5502
#21-5275	#22-5704	#23-5683	#24-5394	#25-5669	#26-5699	#27-5387	#28-5651	#29-5261	#30-5451
#31-5460	#32-5660	#33-5319	#34-5362	#35-5401	#36-5511	#37-5444	#38-5536	#39-5305	#40-5343
#41-5635	#42-5518	#43-5300	#44-5595	#45-5566	#46-5691	#47-5571	#48-5355	#49-5551	#50-5363
#51-5281	#52-5516	#53-5697	#54-5255	#55-5397	#56-5325	#57-5385	#58-5346	#59-5348	#60-5607
#61-5520	#62-5654	#63-5391	#64-5565	#65-5282	#66-5711	#67-5476	#68-5633	#69-5408	#70-5365
#71-5436	#72-5632	#73-5523	#74-5352	#75-5257	#76-5540	#77-5546	#78-5556	#79-5625	#80-5628
#81-5664	#82-5311	#83-5396	#84-5369	#85-5510	#86-5644	#87-5722	#88-5537	#89-5636	#90-5637
#91-5549	#92-5474	#93-5514	#94-5564	#95-5612	#96-5372	#97-5358	#98-5582	#99-5589	#100-5347

Type 6 #15 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5599	#02-5697	#03-5268	#04-5569	#05-5524	#06-5517	#07-5706	#08-5564	#09-5616	#10-5715
#11-5294	#12-5284	#13-5419	#14-5644	#15-5591	#16-5690	#17-5713	#18-5411	#19-5552	#20-5525
#21-5448	#22-5440	#23-5432	#24-5315	#25-5282	#26-5408	#27-5310	#28-5459	#29-5506	#30-5555
#31-5489	#32-5447	#33-5298	#34-5397	#35-5492	#36-5325	#37-5269	#38-5654	#39-5526	#40-5433
#41-5647	#42-5505	#43-5345	#44-5477	#45-5698	#46-5383	#47-5671	#48-5279	#49-5313	#50-5400
#51-5560	#52-5503	#53-5358	#54-5646	#55-5354	#56-5360	#57-5409	#58-5530	#59-5562	#60-5370
#61-5405	#62-5444	#63-5638	#64-5689	#65-5533	#66-5595	#67-5716	#68-5264	#69-5518	#70-5652
#71-5600	#72-5661	#73-5656	#74-5337	#75-5537	#76-5372	#77-5609	#78-5460	#79-5467	#80-5338
#81-5615	#82-5657	#83-5546	#84-5679	#85-5636	#86-5258	#87-5421	#88-5323	#89-5487	#90-5699
#91-5602	#92-5322	#93-5449	#94-5470	#95-5707	#96-5471	#97-5442	#98-5385	#99-5632	#100-5628

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5556	#02-5427	#03-5558	#04-5542	#05-5713	#06-5525	#07-5320	#08-5429	#09-5627	#10-5316
#11-5554	#12-5514	#13-5342	#14-5259	#15-5621	#16-5587	#17-5544	#18-5666	#19-5280	#20-5677
#21-5723	#22-5686	#23-5583	#24-5559	#25-5337	#26-5626	#27-5665	#28-5628	#29-5274	#30-5643
#31-5373	#32-5458	#33-5425	#34-5603	#35-5335	#36-5687	#37-5629	#38-5423	#39-5322	#40-5255
#41-5673	#42-5659	#43-5377	#44-5698	#45-5574	#46-5580	#47-5269	#48-5444	#49-5683	#50-5679
#51-5594	#52-5568	#53-5455	#54-5336	#55-5623	#56-5331	#57-5488	#58-5724	#59-5363	#60-5653
#61-5490	#62-5424	#63-5611	#64-5412	#65-5581	#66-5317	#67-5298	#68-5549	#69-5614	#70-5577
#71-5610	#72-5402	#73-5498	#74-5388	#75-5608	#76-5483	#77-5668	#78-5319	#79-5263	#80-5504
#81-5615	#82-5426	#83-5398	#84-5313	#85-5547	#86-5323	#87-5616	#88-5270	#89-5419	#90-5678
#91-5411	#92-5417	#93-5328	#94-5631	#95-5329	#96-5704	#97-5716	#98-5302	#99-5562	#100-5695

Type 6 #17 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5667	#02-5403	#03-5365	#04-5604	#05-5710	#06-5420	#07-5411	#08-5357	#09-5522	#10-5711
#11-5517	#12-5582	#13-5254	#14-5475	#15-5615	#16-5540	#17-5685	#18-5590	#19-5707	#20-5545
#21-5566	#22-5702	#23-5642	#24-5529	#25-5621	#26-5302	#27-5413	#28-5658	#29-5524	#30-5623
#31-5312	#32-5345	#33-5342	#34-5605	#35-5505	#36-5682	#37-5261	#38-5285	#39-5724	#40-5704
#41-5614	#42-5431	#43-5535	#44-5255	#45-5611	#46-5405	#47-5439	#48-5414	#49-5280	#50-5497
#51-5319	#52-5267	#53-5379	#54-5690	#55-5486	#56-5561	#57-5708	#58-5657	#59-5256	#60-5477
#61-5558	#62-5648	#63-5422	#64-5636	#65-5595	#66-5359	#67-5583	#68-5673	#69-5555	#70-5277
#71-5587	#72-5337	#73-5461	#74-5718	#75-5415	#76-5258	#77-5468	#78-5360	#79-5593	#80-5275
#81-5394	#82-5688	#83-5639	#84-5269	#85-5371	#86-5278	#87-5352	#88-5717	#89-5289	#90-5396
#91-5715	#92-5507	#93-5363	#94-5559	#95-5700	#96-5329	#97-5331	#98-5336	#99-5714	#100-5516

Type 6 #18 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5275	#03-5567	#04-5342	#05-5491	#06-5723	#07-5259	#08-5447	#09-5279	#10-5358
#11-5396	#12-5276	#13-5672	#14-5680	#15-5340	#16-5461	#17-5645	#18-5452	#19-5715	#20-5712
#21-5440	#22-5347	#23-5678	#24-5605	#25-5306	#26-5388	#27-5529	#28-5512	#29-5597	#30-5664
#31-5404	#32-5421	#33-5286	#34-5718	#35-5660	#36-5585	#37-5719	#38-5280	#39-5673	#40-5685
#41-5398	#42-5691	#43-5533	#44-5278	#45-5579	#46-5714	#47-5343	#48-5410	#49-5464	#50-5345
#51-5251	#52-5325	#53-5505	#54-5321	#55-5687	#56-5301	#57-5525	#58-5595	#59-5643	#60-5492
#61-5486	#62-5457	#63-5596	#64-5500	#65-5644	#66-5346	#67-5657	#68-5710	#69-5592	#70-5721
#71-5681	#72-5386	#73-5638	#74-5498	#75-5412	#76-5593	#77-5399	#78-5435	#79-5351	#80-5382
#81-5568	#82-5402	#83-5506	#84-5647	#85-5566	#86-5623	#87-5534	#88-5443	#89-5637	#90-5484
#91-5661	#92-5502	#93-5659	#94-5617	#95-5411	#96-5425	#97-5349	#98-5295	#99-5558	#100-5368

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5517	#02-5299	#03-5513	#04-5614	#05-5656	#06-5445	#07-5457	#08-5390	#09-5353	#10-5443
#11-5404	#12-5388	#13-5424	#14-5341	#15-5336	#16-5307	#17-5528	#18-5521	#19-5462	#20-5668
#21-5616	#22-5403	#23-5561	#24-5634	#25-5658	#26-5506	#27-5274	#28-5651	#29-5510	#30-5469
#31-5357	#32-5512	#33-5387	#34-5379	#35-5360	#36-5645	#37-5511	#38-5690	#39-5547	#40-5302
#41-5534	#42-5595	#43-5467	#44-5348	#45-5320	#46-5338	#47-5539	#48-5545	#49-5499	#50-5346
#51-5425	#52-5625	#53-5620	#54-5676	#55-5704	#56-5723	#57-5664	#58-5433	#59-5464	#60-5568
#61-5394	#62-5617	#63-5250	#64-5294	#65-5548	#66-5701	#67-5266	#68-5556	#69-5639	#70-5332
#71-5533	#72-5344	#73-5536	#74-5313	#75-5679	#76-5562	#77-5695	#78-5648	#79-5583	#80-5416
#81-5687	#82-5479	#83-5622	#84-5409	#85-5665	#86-5275	#87-5363	#88-5691	#89-5450	#90-5381
#91-5456	#92-5398	#93-5496	#94-5362	#95-5402	#96-5529	#97-5431	#98-5542	#99-5581	#100-5417

Type 6 #20 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5586	#02-5600	#03-5479	#04-5626	#05-5597	#06-5471	#07-5477	#08-5450	#09-5288	#10-5539
#11-5651	#12-5541	#13-5446	#14-5478	#15-5530	#16-5525	#17-5303	#18-5366	#19-5333	#20-5688
#21-5330	#22-5590	#23-5639	#24-5432	#25-5543	#26-5369	#27-5640	#28-5709	#29-5403	#30-5662
#31-5535	#32-5552	#33-5498	#34-5652	#35-5400	#36-5609	#37-5661	#38-5343	#39-5704	#40-5628
#41-5255	#42-5483	#43-5584	#44-5569	#45-5545	#46-5680	#47-5300	#48-5388	#49-5630	#50-5480
#51-5426	#52-5253	#53-5618	#54-5337	#55-5720	#56-5686	#57-5296	#58-5304	#59-5352	#60-5562
#61-5466	#62-5602	#63-5714	#64-5673	#65-5551	#66-5380	#67-5641	#68-5367	#69-5272	#70-5353
#71-5310	#72-5325	#73-5357	#74-5305	#75-5587	#76-5629	#77-5318	#78-5502	#79-5328	#80-5648
#81-5485	#82-5531	#83-5659	#84-5410	#85-5656	#86-5438	#87-5563	#88-5315	#89-5513	#90-5598
#91-5706	#92-5453	#93-5556	#94-5256	#95-5474	#96-5258	#97-5363	#98-5624	#99-5558	#100-5262

Type 6 #21 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5612	#02-5630	#03-5433	#04-5522	#05-5441	#06-5283	#07-5310	#08-5387	#09-5685	#10-5367
#11-5559	#12-5304	#13-5512	#14-5619	#15-5666	#16-5327	#17-5607	#18-5709	#19-5476	#20-5719
#21-5536	#22-5484	#23-5324	#24-5384	#25-5322	#26-5581	#27-5568	#28-5494	#29-5338	#30-5535
#31-5331	#32-5631	#33-5351	#34-5398	#35-5294	#36-5532	#37-5379	#38-5687	#39-5571	#40-5254
#41-5376	#42-5637	#43-5589	#44-5618	#45-5501	#46-5468	#47-5580	#48-5316	#49-5636	#50-5481
#51-5419	#52-5563	#53-5450	#54-5378	#55-5556	#56-5299	#57-5449	#58-5585	#59-5440	#60-5541
#61-5298	#62-5400	#63-5285	#64-5652	#65-5678	#66-5364	#67-5574	#68-5383	#69-5673	#70-5644
#71-5633	#72-5714	#73-5410	#74-5459	#75-5490	#76-5546	#77-5362	#78-5712	#79-5427	#80-5426
#81-5483	#82-5672	#83-5640	#84-5700	#85-5329	#86-5488	#87-5711	#88-5438	#89-5487	#90-5553
#91-5691	#92-5547	#93-5354	#94-5256	#95-5657	#96-5688	#97-5562	#98-5282	#99-5573	#100-5290

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5532	#02-5347	#03-5534	#04-5627	#05-5472	#06-5452	#07-5363	#08-5597	#09-5346	#10-5373
#11-5418	#12-5415	#13-5416	#14-5658	#15-5408	#16-5593	#17-5405	#18-5401	#19-5504	#20-5526
#21-5332	#22-5333	#23-5630	#24-5524	#25-5723	#26-5258	#27-5706	#28-5494	#29-5463	#30-5467
#31-5604	#32-5718	#33-5664	#34-5632	#35-5358	#36-5603	#37-5520	#38-5586	#39-5488	#40-5651
#41-5324	#42-5455	#43-5391	#44-5430	#45-5522	#46-5381	#47-5663	#48-5322	#49-5499	#50-5344
#51-5406	#52-5606	#53-5710	#54-5297	#55-5682	#56-5449	#57-5441	#58-5259	#59-5629	#60-5464
#61-5470	#62-5594	#63-5383	#64-5493	#65-5425	#66-5476	#67-5508	#68-5550	#69-5529	#70-5544
#71-5637	#72-5578	#73-5602	#74-5666	#75-5450	#76-5252	#77-5591	#78-5319	#79-5634	#80-5720
#81-5368	#82-5310	#83-5617	#84-5674	#85-5412	#86-5511	#87-5681	#88-5273	#89-5321	#90-5512
#91-5662	#92-5404	#93-5497	#94-5695	#95-5271	#96-5587	#97-5693	#98-5569	#99-5329	#100-5507

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5716	#02-5257	#03-5287	#04-5395	#05-5560	#06-5599	#07-5264	#08-5544	#09-5494	#10-5417
#11-5584	#12-5558	#13-5640	#14-5367	#15-5536	#16-5587	#17-5613	#18-5397	#19-5721	#20-5531
#21-5404	#22-5512	#23-5630	#24-5686	#25-5639	#26-5387	#27-5274	#28-5347	#29-5447	#30-5280
#31-5601	#32-5297	#33-5595	#34-5377	#35-5421	#36-5503	#37-5644	#38-5603	#39-5594	#40-5581
#41-5307	#42-5693	#43-5418	#44-5654	#45-5296	#46-5570	#47-5578	#48-5459	#49-5250	#50-5330
#51-5709	#52-5573	#53-5523	#54-5352	#55-5453	#56-5326	#57-5480	#58-5423	#59-5574	#60-5642
#61-5346	#62-5464	#63-5540	#64-5688	#65-5513	#66-5670	#67-5283	#68-5667	#69-5259	#70-5528
#71-5390	#72-5474	#73-5436	#74-5344	#75-5700	#76-5319	#77-5612	#78-5446	#79-5675	#80-5617
#81-5449	#82-5321	#83-5401	#84-5568	#85-5373	#86-5256	#87-5389	#88-5596	#89-5678	#90-5364
#91-5484	#92-5606	#93-5317	#94-5632	#95-5426	#96-5308	#97-5320	#98-5430	#99-5432	#100-5299

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5641	#02-5358	#03-5377	#04-5411	#05-5410	#06-5617	#07-5402	#08-5279	#09-5625	#10-5514
#11-5648	#12-5337	#13-5488	#14-5702	#15-5607	#16-5349	#17-5610	#18-5356	#19-5383	#20-5334
#21-5564	#22-5390	#23-5586	#24-5405	#25-5437	#26-5463	#27-5435	#28-5387	#29-5604	#30-5436
#31-5266	#32-5272	#33-5584	#34-5273	#35-5407	#36-5687	#37-5529	#38-5579	#39-5359	#40-5695
#41-5414	#42-5440	#43-5397	#44-5714	#45-5553	#46-5654	#47-5544	#48-5684	#49-5434	#50-5324
#51-5298	#52-5690	#53-5326	#54-5693	#55-5515	#56-5255	#57-5698	#58-5403	#59-5613	#60-5569
#61-5634	#62-5462	#63-5320	#64-5595	#65-5380	#66-5368	#67-5583	#68-5666	#69-5552	#70-5699
#71-5594	#72-5700	#73-5395	#74-5258	#75-5447	#76-5616	#77-5428	#78-5420	#79-5362	#80-5306
#81-5282	#82-5615	#83-5483	#84-5401	#85-5376	#86-5457	#87-5505	#88-5369	#89-5423	#90-5536
#91-5685	#92-5267	#93-5511	#94-5496	#95-5493	#96-5715	#97-5717	#98-5722	#99-5501	#100-5677

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5309	#02-5463	#03-5350	#04-5351	#05-5538	#06-5347	#07-5477	#08-5514	#09-5658	#10-5426
#11-5564	#12-5433	#13-5386	#14-5444	#15-5417	#16-5656	#17-5328	#18-5460	#19-5298	#20-5655
#21-5410	#22-5634	#23-5590	#24-5450	#25-5315	#26-5550	#27-5623	#28-5363	#29-5404	#30-5607
#31-5661	#32-5563	#33-5397	#34-5292	#35-5602	#36-5699	#37-5555	#38-5326	#39-5308	#40-5585
#41-5577	#42-5320	#43-5654	#44-5532	#45-5522	#46-5676	#47-5423	#48-5282	#49-5705	#50-5271
#51-5624	#52-5554	#53-5485	#54-5626	#55-5472	#56-5579	#57-5711	#58-5360	#59-5445	#60-5543
#61-5627	#62-5595	#63-5713	#64-5402	#65-5540	#66-5681	#67-5497	#68-5384	#69-5714	#70-5319
#71-5657	#72-5306	#73-5519	#74-5521	#75-5508	#76-5479	#77-5411	#78-5338	#79-5289	#80-5574
#81-5680	#82-5541	#83-5498	#84-5462	#85-5367	#86-5323	#87-5333	#88-5528	#89-5454	#90-5598
#91-5381	#92-5501	#93-5276	#94-5331	#95-5369	#96-5359	#97-5650	#98-5716	#99-5677	#100-5691

Type 6 #26 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5497	#02-5690	#03-5355	#04-5689	#05-5292	#06-5478	#07-5550	#08-5271	#09-5405	#10-5694
#11-5672	#12-5304	#13-5464	#14-5664	#15-5423	#16-5608	#17-5413	#18-5580	#19-5510	#20-5446
#21-5539	#22-5650	#23-5268	#24-5494	#25-5571	#26-5397	#27-5705	#28-5274	#29-5704	#30-5364
#31-5676	#32-5589	#33-5532	#34-5402	#35-5692	#36-5369	#37-5485	#38-5700	#39-5298	#40-5346
#41-5329	#42-5607	#43-5591	#44-5430	#45-5688	#46-5475	#47-5486	#48-5455	#49-5480	#50-5401
#51-5671	#52-5586	#53-5367	#54-5620	#55-5498	#56-5525	#57-5291	#58-5267	#59-5707	#60-5440
#61-5657	#62-5699	#63-5270	#64-5641	#65-5294	#66-5345	#67-5535	#68-5443	#69-5674	#70-5461
#71-5415	#72-5530	#73-5311	#74-5479	#75-5602	#76-5634	#77-5484	#78-5358	#79-5381	#80-5368
#81-5356	#82-5252	#83-5590	#84-5451	#85-5658	#86-5514	#87-5416	#88-5659	#89-5456	#90-5667
#91-5559	#92-5442	#93-5645	#94-5332	#95-5682	#96-5622	#97-5460	#98-5420	#99-5339	#100-5698

Type 6 #27 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5464	#02-5537	#03-5414	#04-5357	#05-5473	#06-5332	#07-5526	#08-5580	#09-5540	#10-5535
#11-5292	#12-5479	#13-5333	#14-5625	#15-5389	#16-5265	#17-5671	#18-5318	#19-5523	#20-5596
#21-5319	#22-5368	#23-5644	#24-5410	#25-5687	#26-5564	#27-5275	#28-5423	#29-5471	#30-5720
#31-5660	#32-5574	#33-5501	#34-5478	#35-5283	#36-5492	#37-5494	#38-5406	#39-5598	#40-5334
#41-5382	#42-5600	#43-5377	#44-5274	#45-5399	#46-5442	#47-5561	#48-5432	#49-5543	#50-5606
#51-5513	#52-5351	#53-5604	#54-5467	#55-5628	#56-5345	#57-5617	#58-5254	#59-5395	#60-5633
#61-5307	#62-5353	#63-5358	#64-5544	#65-5599	#66-5443	#67-5702	#68-5579	#69-5591	#70-5621
#71-5496	#72-5515	#73-5445	#74-5438	#75-5463	#76-5716	#77-5620	#78-5260	#79-5252	#80-5567
#81-5590	#82-5457	#83-5559	#84-5695	#85-5284	#86-5575	#87-5663	#88-5489	#89-5261	#90-5689
#91-5277	#92-5279	#93-5557	#94-5681	#95-5465	#96-5707	#97-5566	#98-5646	#99-5359	#100-5723

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5631	#02-5415	#03-5253	#04-5435	#05-5353	#06-5721	#07-5719	#08-5625	#09-5464	#10-5473
#11-5493	#12-5337	#13-5290	#14-5668	#15-5254	#16-5653	#17-5272	#18-5257	#19-5503	#20-5480
#21-5411	#22-5434	#23-5675	#24-5409	#25-5471	#26-5304	#27-5279	#28-5269	#29-5251	#30-5682
#31-5481	#32-5459	#33-5652	#34-5529	#35-5280	#36-5389	#37-5559	#38-5602	#39-5495	#40-5360
#41-5308	#42-5537	#43-5530	#44-5724	#45-5470	#46-5359	#47-5458	#48-5521	#49-5702	#50-5637
#51-5624	#52-5352	#53-5469	#54-5401	#55-5544	#56-5484	#57-5669	#58-5500	#59-5664	#60-5595
#61-5611	#62-5463	#63-5515	#64-5262	#65-5362	#66-5638	#67-5590	#68-5343	#69-5395	#70-5487
#71-5393	#72-5422	#73-5599	#74-5628	#75-5676	#76-5663	#77-5361	#78-5571	#79-5483	#80-5291
#81-5338	#82-5378	#83-5715	#84-5501	#85-5525	#86-5460	#87-5629	#88-5615	#89-5351	#90-5555
#91-5489	#92-5421	#93-5324	#94-5265	#95-5711	#96-5592	#97-5722	#98-5514	#99-5608	#100-5479

Type 6 #29 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5590	#02-5325	#03-5703	#04-5380	#05-5641	#06-5532	#07-5255	#08-5389	#09-5343	#10-5362
#11-5569	#12-5374	#13-5457	#14-5608	#15-5612	#16-5586	#17-5393	#18-5427	#19-5685	#20-5453
#21-5293	#22-5656	#23-5628	#24-5250	#25-5524	#26-5613	#27-5689	#28-5320	#29-5364	#30-5307
#31-5600	#32-5654	#33-5519	#34-5554	#35-5513	#36-5639	#37-5522	#38-5394	#39-5544	#40-5346
#41-5609	#42-5687	#43-5462	#44-5377	#45-5576	#46-5674	#47-5353	#48-5705	#49-5386	#50-5370
#51-5430	#52-5402	#53-5341	#54-5435	#55-5658	#56-5422	#57-5580	#58-5278	#59-5567	#60-5660
#61-5274	#62-5286	#63-5487	#64-5640	#65-5579	#66-5627	#67-5344	#68-5697	#69-5313	#70-5723
#71-5588	#72-5568	#73-5330	#74-5444	#75-5501	#76-5399	#77-5575	#78-5340	#79-5661	#80-5419
#81-5428	#82-5368	#83-5467	#84-5539	#85-5515	#86-5504	#87-5663	#88-5426	#89-5614	#90-5630
#91-5259	#92-5257	#93-5322	#94-5371	#95-5546	#96-5497	#97-5355	#98-5464	#99-5645	#100-5553

Type 6 #30 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5255	#02-5673	#03-5706	#04-5570	#05-5296	#06-5349	#07-5317	#08-5389	#09-5401	#10-5508
#11-5489	#12-5480	#13-5494	#14-5434	#15-5342	#16-5334	#17-5619	#18-5392	#19-5267	#20-5611
#21-5463	#22-5424	#23-5577	#24-5332	#25-5630	#26-5540	#27-5598	#28-5687	#29-5655	#30-5263
#31-5365	#32-5546	#33-5715	#34-5534	#35-5567	#36-5522	#37-5353	#38-5616	#39-5326	#40-5547
#41-5521	#42-5668	#43-5372	#44-5495	#45-5502	#46-5553	#47-5662	#48-5454	#49-5603	#50-5688
#51-5446	#52-5283	#53-5340	#54-5500	#55-5498	#56-5379	#57-5488	#58-5390	#59-5533	#60-5444
#61-5427	#62-5470	#63-5373	#64-5659	#65-5503	#66-5625	#67-5536	#68-5515	#69-5666	#70-5314
#71-5537	#72-5302	#73-5331	#74-5555	#75-5327	#76-5393	#77-5482	#78-5300	#79-5643	#80-5512
#81-5284	#82-5318	#83-5590	#84-5476	#85-5517	#86-5344	#87-5447	#88-5602	#89-5371	#90-5299
#91-5286	#92-5678	#93-5337	#94-5437	#95-5505	#96-5694	#97-5398	#98-5297	#99-5657	#100-5313

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Type 5 #1 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	687560	77	0	0	62363	750000
2	3	12	396475	89	1616	1876	349766	750000
3	2	10	221272	67	1455	0	527139	750000
4	3	17	134197	51	1931	1390	612329	750000
5	2	12	156369	84	1854	0	591609	750000
6	3	7	46483	85	1603	1392	700267	750000
7	2	7	130433	60	1583	0	617864	750000
8	2	7	385559	52	1280	0	363057	750000
9	1	18	20909	56	0	0	729035	750000
10	2	8	566775	57	1866	0	181245	750000
11	2	17	489473	73	1496	0	258885	750000
12	3	6	590944	58	1690	1025	156167	750000
13	2	7	567012	63	1391	0	181471	750000
14	1	16	486902	64	0	0	263034	750000
15	2	17	497695	88	1110	0	251019	750000
16	1	14	619528	77	0	0	130395	750000

Type 5 #2 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	658537	73	1845	0	6138	666666
2	2	16	472549	89	1516	0	192423	666666
3	1	10	85438	74	0	0	581154	666666
4	2	17	317887	52	1988	0	346687	666666
5	1	18	348702	65	0	0	317899	666666
6	1	15	458978	63	0	0	207625	666666
7	3	10	157064	92	1330	1551	506445	666666
8	3	10	98660	71	1193	1428	565172	666666
9	3	11	422966	99	1769	1002	240632	666666
10	1	15	414547	70	0	0	252049	666666
11	2	13	369814	75	1132	0	295570	666666
12	2	20	389880	87	1062	0	275550	666666
13	2	6	117809	96	1872	0	546793	666666
14	2	8	469297	73	1447	0	195776	666666
15	1	11	559349	93	0	0	107224	666666
16	3	19	384220	65	1100	1521	279630	666666
17	1	5	46837	61	0	0	619768	666666
18	1	17	279056	92	0	0	387518	666666

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Type 5 #3 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	630495	85	1131	0	118204	750000
2	3	19	464539	95	1547	1591	282038	750000
3	1	20	707486	89	0	0	42425	750000
4	2	7	336130	89	1715	0	411977	750000
5	1	15	315502	79	0	0	434419	750000
6	2	6	15836	67	1869	0	732161	750000
7	2	14	419282	67	1041	0	329543	750000
8	1	17	538616	50	0	0	211334	750000
9	2	17	255632	52	1414	0	492850	750000
10	2	11	204255	95	1458	0	544097	750000
11	1	11	530154	81	0	0	219765	750000
12	1	11	641611	99	0	0	108290	750000
13	1	15	370534	99	0	0	379367	750000
14	3	18	14022	50	1886	1246	732696	750000
15	1	20	695105	61	0	0	54834	750000
16	3	14	631253	52	1671	1653	115267	750000

Type 5 #4 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	971265	76	0	0	119568	1090909
2	3	11	588912	89	1225	1638	498867	1090909
3	1	7	1047526	57	0	0	43326	1090909
4	3	5	600865	53	1369	1778	486738	1090909
5	2	19	258510	63	1267	0	831006	1090909
6	1	19	417912	58	0	0	672939	1090909
7	1	10	628226	69	0	0	462614	1090909
8	2	12	657543	97	1566	0	431606	1090909
9	3	12	519139	62	1661	1609	568314	1090909
10	1	17	1054420	54	0	0	36435	1090909
11	3	13	318756	100	1301	1875	768677	1090909

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	400108	82	1653	1526	263133	666666
2	2	13	503015	92	1150	0	162317	666666
3	2	5	335565	77	1371	0	329576	666666
4	2	13	529618	77	1101	0	135793	666666
5	2	8	348932	70	1155	0	316439	666666
6	1	11	384882	53	0	0	281731	666666
7	1	9	552420	72	0	0	114174	666666
8	1	17	633650	90	0	0	32926	666666
9	1	20	545697	82	0	0	120887	666666
10	1	9	346253	66	0	0	320347	666666
11	1	12	319344	97	0	0	347225	666666
12	1	10	127712	88	0	0	538866	666666
13	3	8	1072	60	1610	1498	662306	666666
14	2	12	40447	71	1941	0	624136	666666
15	1	16	636378	64	0	0	30224	666666
16	2	12	591517	88	1244	0	73729	666666
17	1	14	50185	99	0	0	616382	666666
18	3	9	610796	82	1263	1562	52799	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	719407	55	0	0	137680	857142
2	3	7	206784	78	1453	1298	647373	857142
3	2	7	848944	69	1266	0	6794	857142
4	1	20	794051	78	0	0	63013	857142
5	3	13	10319	81	1454	1059	844067	857142
6	2	16	629787	58	1862	0	225377	857142
7	1	13	398397	93	0	0	458652	857142
8	3	8	10280	60	1871	1087	843724	857142
9	2	20	500888	51	1647	0	354505	857142
10	2	17	338785	71	1906	0	516309	857142
11	3	15	697951	64	1194	1864	155941	857142
12	2	18	337700	51	1224	0	518116	857142
13	2	13	587350	80	1104	0	268528	857142
14	3	13	579663	84	1777	1051	274399	857142

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	14	297439	55	1569	1807	330598	631578
2	2	10	293219	61	1807	0	336430	631578
3	1	8	206613	93	0	0	424872	631578
4	2	14	27293	96	1156	0	602937	631578
5	3	7	340881	81	1446	1384	287624	631578
6	3	16	216988	88	1272	1129	411925	631578
7	1	16	51235	69	0	0	580274	631578
8	1	18	352656	62	0	0	278860	631578
9	2	5	78879	100	1622	0	550877	631578
10	2	12	53394	62	1527	0	576533	631578
11	2	19	20826	60	1636	0	608996	631578
12	1	7	116562	97	0	0	514919	631578
13	1	15	317105	79	0	0	314394	631578
14	1	6	621037	84	0	0	10457	631578
15	2	8	417825	75	1311	0	212292	631578
16	3	15	352861	80	1869	1579	275029	631578
17	1	9	276917	92	0	0	354569	631578
18	1	15	583278	82	0	0	48218	631578
19	2	10	95492	70	1424	0	534522	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	901180	79	0	0	298741	1200000
2	2	20	668567	98	1004	0	530233	1200000
3	3	9	566404	98	1774	1962	629566	1200000
4	1	7	862040	50	0	0	337910	1200000
5	2	10	162637	91	1968	0	1035213	1200000
6	2	11	803082	93	1754	0	394978	1200000
7	2	6	178861	56	1094	0	1019933	1200000
8	2	14	450770	58	1877	0	747237	1200000
9	2	10	631564	81	1285	0	566989	1200000
10	2	18	539215	97	1686	0	658905	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	472953	59	1784	0	858478	1333333
2	3	18	690611	80	1305	1633	639544	1333333
3	1	20	855527	67	0	0	477739	1333333
4	3	14	908256	59	1363	1315	422222	1333333
5	1	6	1000560	90	0	0	332683	1333333
6	2	12	677698	52	1653	0	653878	1333333
7	3	9	1254470	88	1517	1188	75894	1333333
8	2	17	734866	65	1877	0	596460	1333333
9	3	16	1307020	79	1104	1426	23546	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	134206	80	1244	1322	862988	1000000
2	2	11	33462	63	1610	0	964802	1000000
3	3	7	640394	83	1195	1796	356366	1000000
4	3	18	497409	95	1788	1699	498819	1000000
5	3	12	558260	92	1764	1917	437783	1000000
6	1	10	507758	100	0	0	492142	1000000
7	3	5	426387	78	1759	1746	569874	1000000
8	1	19	546091	52	0	0	453857	1000000
9	3	19	568927	64	1210	1387	428284	1000000
10	3	10	519707	55	1538	1164	477426	1000000
11	1	18	413992	55	0	0	585953	1000000
12	3	13	617114	68	1701	1352	379629	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	14	26265	96	1149	0	678276	705882
2	3	16	107137	67	1773	1862	594909	705882
3	3	19	243628	80	1276	1377	459361	705882
4	3	15	159065	98	1788	1343	543392	705882
5	2	19	417039	97	1332	0	287317	705882
6	3	8	399668	75	1194	1146	303649	705882
7	2	17	520064	64	1421	0	184269	705882
8	1	18	276922	100	0	0	428860	705882
9	2	10	360994	51	1274	0	343512	705882
10	2	8	287210	100	1917	0	416555	705882
11	3	5	148639	96	1692	1240	554023	705882
12	1	16	650467	78	0	0	55337	705882
13	1	20	414560	82	0	0	291240	705882
14	1	20	422900	66	0	0	282916	705882
15	3	16	667586	52	1661	1969	34510	705882
16	2	14	577169	67	1610	0	126969	705882
17	1	9	218063	90	0	0	487729	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	13	400454	82	0	0	266130	666666
2	2	14	163729	60	1640	0	501177	666666
3	3	5	161494	55	1075	1787	502145	666666
4	1	11	188115	79	0	0	478472	666666
5	3	9	82944	84	1953	1063	580454	666666
6	3	13	78469	83	1745	1716	584487	666666
7	3	7	512734	66	1404	1384	150946	666666
8	2	16	66238	53	1461	0	598861	666666
9	2	18	172874	53	1543	0	492143	666666
10	3	15	1177	68	1456	1408	662421	666666
11	2	19	328595	55	1694	0	336267	666666
12	2	13	595893	82	1042	0	69567	666666
13	2	6	600074	89	1697	0	64717	666666
14	2	11	221840	93	1193	0	443447	666666
15	2	14	585125	70	1889	0	79512	666666
16	1	15	581289	79	0	0	85298	666666
17	1	9	473573	55	0	0	193038	666666
18	3	5	184580	95	1524	1690	478587	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	557513	57	1204	0	72747	631578
2	1	18	225635	86	0	0	405857	631578
3	2	8	46944	75	1263	0	583221	631578
4	2	13	512283	51	1993	0	117200	631578
5	1	20	435386	95	0	0	196097	631578
6	3	9	508618	90	1067	1119	120504	631578
7	3	7	568546	93	1131	1286	60336	631578
8	2	10	369712	100	1003	0	260663	631578
9	2	9	421007	87	1478	0	208919	631578
10	3	15	318095	100	1560	1858	309765	631578
11	2	5	278534	94	1013	0	351843	631578
12	2	11	142305	78	1615	0	487502	631578
13	2	13	213592	51	1535	0	416349	631578
14	1	7	14103	99	0	0	617376	631578
15	1	20	143557	59	0	0	487962	631578
16	3	16	571364	58	1211	1198	57631	631578
17	1	13	600142	72	0	0	31364	631578
18	2	9	171700	66	1123	0	458623	631578
19	2	12	244814	98	1949	0	384619	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	781000	85	1943	1329	215473	1000000
2	1	13	819289	73	0	0	180638	1000000
3	1	15	237220	77	0	0	762703	1000000
4	3	9	340555	87	1352	1508	656324	1000000
5	3	6	46708	52	1169	1209	950758	1000000
6	3	16	234414	85	1074	1599	762658	1000000
7	2	19	920685	94	1460	0	77667	1000000
8	1	6	253128	94	0	0	746778	1000000
9	3	7	641230	51	1018	1783	355816	1000000
10	3	16	439853	71	1695	1087	557152	1000000
11	1	18	609972	78	0	0	389950	1000000
12	2	9	314495	87	1811	0	683520	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	550621	61	1945	0	153194	705882
2	2	18	340208	70	1986	0	363548	705882
3	2	18	674203	54	1023	0	30548	705882
4	1	11	61013	71	0	0	644798	705882
5	1	11	360783	100	0	0	344999	705882
6	3	9	220371	78	1026	1851	482400	705882
7	2	10	147270	79	1938	0	556516	705882
8	2	19	605871	96	1838	0	97981	705882
9	2	19	425310	51	1710	0	278760	705882
10	1	16	583300	98	0	0	122484	705882
11	2	9	510089	73	1879	0	193768	705882
12	1	6	500759	89	0	0	205034	705882
13	1	12	235946	69	0	0	469867	705882
14	2	12	48928	75	1897	0	654907	705882
15	1	12	32711	81	0	0	673090	705882
16	1	13	396156	80	0	0	309646	705882
17	1	15	640263	54	0	0	65565	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	8	603089	78	1197	0	101440	705882
2	1	14	642799	86	0	0	62997	705882
3	2	8	314058	74	1637	0	390039	705882
4	2	12	182091	59	1394	0	522279	705882
5	3	17	426797	100	1121	1362	276302	705882
6	1	10	115342	86	0	0	590454	705882
7	3	11	560854	84	1803	1558	141415	705882
8	3	10	132613	56	1650	1223	570228	705882
9	2	7	595060	62	1991	0	108707	705882
10	2	7	555837	57	1370	0	148561	705882
11	3	8	308980	70	1747	1785	393160	705882
12	3	14	298911	80	1510	1372	403849	705882
13	1	5	281204	88	0	0	424590	705882
14	1	12	40126	83	0	0	665673	705882
15	1	5	366111	87	0	0	339684	705882
16	2	20	536355	79	1372	0	167997	705882
17	2	7	684305	79	1793	0	19626	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	8207	80	0	0	591713	600000
2	2	17	426696	65	1030	0	172144	600000
3	3	6	266700	52	1420	1930	329794	600000
4	2	16	394974	75	1313	0	203563	600000
5	3	15	297075	69	1239	1216	300263	600000
6	2	20	119914	92	1936	0	477966	600000
7	2	17	476511	59	1057	0	122314	600000
8	1	20	456625	82	0	0	143293	600000
9	2	10	270654	86	1702	0	327472	600000
10	2	12	88143	76	1314	0	510391	600000
11	1	12	187310	73	0	0	412617	600000
12	1	19	343040	81	0	0	256879	600000
13	3	18	463378	100	1930	1064	133328	600000
14	2	19	521931	71	1651	0	76276	600000
15	2	18	330427	62	1731	0	267718	600000
16	1	5	587222	62	0	0	12716	600000
17	3	20	489211	87	1024	1514	107990	600000
18	3	7	256686	87	1866	1729	339458	600000
19	3	18	263380	85	1993	1932	332440	600000
20	2	6	338814	77	1029	0	260003	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	462842	83	1217	0	167353	631578
2	3	17	493019	51	1574	1943	134889	631578
3	1	17	262227	50	0	0	369301	631578
4	1	19	170623	96	0	0	460859	631578
5	1	12	490865	97	0	0	140616	631578
6	2	16	533156	51	1621	0	96699	631578
7	2	19	108223	75	1757	0	521448	631578
8	1	18	574489	73	0	0	57016	631578
9	2	8	581623	50	1842	0	48013	631578
10	3	19	79836	97	1777	1984	547690	631578
11	1	15	130089	70	0	0	501419	631578
12	3	20	230926	76	1127	1886	397411	631578
13	1	9	111916	100	0	0	519562	631578
14	1	5	17657	53	0	0	613868	631578
15	3	10	175524	96	1564	1335	452867	631578
16	3	8	531254	52	1999	1585	96584	631578
17	2	17	516349	62	1493	0	113612	631578
18	1	15	630218	94	0	0	1266	631578
19	2	10	341311	57	1966	0	288187	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	650931	96	0	0	272049	923076
2	3	19	715305	94	1889	1078	204522	923076
3	2	10	658881	53	1327	0	262762	923076
4	1	13	36475	98	0	0	886503	923076
5	3	8	32641	98	1814	1357	886970	923076
6	1	5	216239	68	0	0	706769	923076
7	3	14	803754	51	1794	1831	115544	923076
8	1	9	734850	77	0	0	188149	923076
9	3	10	328188	88	1676	1716	591232	923076
10	1	10	261299	77	0	0	661700	923076
11	2	17	742285	60	1926	0	178745	923076
12	2	6	617243	88	1306	0	304351	923076
13	2	18	301951	76	1654	0	619319	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	13	541306	63	1453	1590	161344	705882
2	2	6	409483	88	1988	0	294235	705882
3	2	5	461891	54	1921	0	241962	705882
4	1	19	385379	88	0	0	320415	705882
5	1	20	228848	84	0	0	476950	705882
6	1	8	440240	50	0	0	265592	705882
7	1	19	498387	72	0	0	207423	705882
8	2	12	10366	98	1841	0	693479	705882
9	3	14	598770	85	1548	1039	104270	705882
10	3	8	527037	97	1008	1306	176240	705882
11	3	6	364449	76	1762	1782	337661	705882
12	1	8	240166	64	0	0	465652	705882
13	2	5	440881	77	1551	0	263296	705882
14	1	8	97144	94	0	0	608644	705882
15	2	15	37838	54	1097	0	666839	705882
16	1	8	579520	100	0	0	126262	705882
17	1	19	7284	70	0	0	698528	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	19	337420	62	1790	1945	258659	600000
2	2	13	338755	65	1822	0	259293	600000
3	1	13	292933	51	0	0	307016	600000
4	1	5	584976	87	0	0	14937	600000
5	3	15	31167	90	1303	1415	565845	600000
6	2	10	70384	89	1370	0	528068	600000
7	3	13	179629	71	1606	1158	417394	600000
8	3	19	122843	65	1654	1697	473611	600000
9	2	13	170971	91	1932	0	426915	600000
10	2	14	210054	86	1443	0	388331	600000
11	3	7	310089	57	1204	1947	286589	600000
12	3	17	260275	75	1119	1932	336449	600000
13	1	13	257727	57	0	0	342216	600000
14	2	13	70360	59	1424	0	528098	600000
15	1	14	86327	58	0	0	513615	600000
16	2	6	180030	95	1153	0	418627	600000
17	2	15	286861	89	1442	0	311519	600000
18	2	20	102489	74	1354	0	496009	600000
19	2	18	164134	71	1578	0	434146	600000
20	1	11	222128	90	0	0	377782	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	12026	76	0	0	619476	631578
2	1	20	339895	81	0	0	291602	631578
3	1	15	389671	73	0	0	241834	631578
4	2	13	480067	74	1157	0	150206	631578
5	2	7	253310	83	1954	0	376148	631578
6	3	18	374735	68	1691	1451	253497	631578
7	1	16	314171	52	0	0	317355	631578
8	3	7	412001	65	1091	1714	216577	631578
9	1	12	591902	93	0	0	39583	631578
10	3	13	244624	95	1948	1075	383646	631578
11	1	10	128817	55	0	0	502706	631578
12	3	19	437982	61	1724	1689	190000	631578
13	1	7	232900	77	0	0	398601	631578
14	1	17	87037	50	0	0	544491	631578
15	3	9	66773	52	1415	1443	561791	631578
16	2	15	320899	91	1016	0	309481	631578
17	3	19	330175	92	1616	1061	298450	631578
18	1	12	489606	87	0	0	141885	631578
19	2	12	10272	70	1403	0	619763	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	758525	85	1717	0	96730	857142
2	1	6	18464	70	0	0	838608	857142
3	1	15	190080	83	0	0	666979	857142
4	3	13	637030	96	1886	1215	216723	857142
5	3	19	16567	62	1109	1844	837436	857142
6	1	10	297103	64	0	0	559975	857142
7	2	5	522064	93	1427	0	333465	857142
8	3	14	701284	56	1299	1622	152769	857142
9	2	14	743227	92	1980	0	111751	857142
10	2	15	832699	75	1860	0	22433	857142
11	2	15	212898	61	1146	0	642976	857142
12	3	8	717118	79	1698	1607	136482	857142
13	1	10	192513	87	0	0	664542	857142
14	2	14	682077	62	1114	0	173827	857142

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	248807	80	1441	0	349592	600000
2	1	20	295603	56	0	0	304341	600000
3	3	13	371603	81	1373	1149	225632	600000
4	2	10	322883	64	1972	0	275017	600000
5	2	5	235386	80	1981	0	362473	600000
6	1	17	135564	61	0	0	464375	600000
7	1	13	37657	95	0	0	562248	600000
8	1	15	438848	97	0	0	161055	600000
9	3	11	122417	92	1449	1269	474589	600000
10	3	13	359789	61	1361	1214	237453	600000
11	1	9	85420	99	0	0	514481	600000
12	1	20	346353	80	0	0	253567	600000
13	3	10	447020	52	1100	1375	150349	600000
14	1	6	263991	95	0	0	335914	600000
15	2	20	343964	61	1625	0	254289	600000
16	2	6	237547	78	1083	0	361214	600000
17	1	18	441674	88	0	0	158238	600000
18	1	20	187836	57	0	0	412107	600000
19	2	17	561970	70	1428	0	36462	600000
20	1	15	308707	90	0	0	291203	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	947638	76	0	0	52286	1000000
2	1	5	987980	54	0	0	11966	1000000
3	2	11	578477	83	1722	0	419635	1000000
4	1	14	392500	76	0	0	607424	1000000
5	1	14	82203	59	0	0	917738	1000000
6	1	19	240245	91	0	0	759664	1000000
7	2	19	913754	82	1286	0	84796	1000000
8	3	5	561153	96	1254	1016	436289	1000000
9	2	14	722372	62	1768	0	275736	1000000
10	1	9	921487	77	0	0	78436	1000000
11	3	15	669985	92	1915	1351	326473	1000000
12	2	19	850578	74	1226	0	148048	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	12	323667	86	0	0	382129	705882
2	1	16	582820	85	0	0	122977	705882
3	2	10	669515	86	1149	0	35046	705882
4	1	14	294925	57	0	0	410900	705882
5	3	16	224059	52	1534	1979	478154	705882
6	3	5	164985	100	1936	1242	537419	705882
7	2	5	599728	54	1165	0	104881	705882
8	1	6	218507	77	0	0	487298	705882
9	2	18	314266	66	1450	0	390034	705882
10	1	12	680796	75	0	0	25011	705882
11	1	5	38754	76	0	0	667052	705882
12	1	7	125443	58	0	0	580381	705882
13	1	15	327789	69	0	0	378024	705882
14	1	12	417037	89	0	0	288756	705882
15	1	9	694571	81	0	0	11230	705882
16	1	15	330934	94	0	0	374854	705882
17	1	16	613998	61	0	0	91823	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	55450	55	1503	0	1276270	1333333
2	3	8	1135712	87	1388	1007	194965	1333333
3	1	8	188365	84	0	0	1144884	1333333
4	2	13	476641	93	1562	0	854944	1333333
5	3	14	1151409	71	1204	1507	179000	1333333
6	1	13	1262107	95	0	0	71131	1333333
7	3	9	376298	72	1094	1581	954144	1333333
8	1	5	1332805	99	0	0	429	1333333
9	3	15	1301207	69	1619	1444	28856	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	148805	74	1263	1679	771107	923076
2	2	6	118118	61	1518	0	803318	923076
3	3	12	406270	58	1835	1661	513136	923076
4	1	16	534662	70	0	0	388344	923076
5	2	7	463609	93	1884	0	457397	923076
6	2	12	892253	81	1771	0	28890	923076
7	3	12	493815	76	1629	1407	425997	923076
8	3	9	425669	58	1778	1870	493585	923076
9	3	20	831426	60	1868	1532	88070	923076
10	3	12	779211	60	1041	1262	141382	923076
11	1	19	349841	81	0	0	573154	923076
12	1	19	685119	80	0	0	237877	923076
13	2	10	678568	78	1468	0	242884	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	17	76566	56	1991	0	587997	666666
2	3	7	609960	86	1093	1929	53426	666666
3	2	16	378550	51	1766	0	286248	666666
4	2	9	383886	86	1593	0	281015	666666
5	3	9	586202	83	1994	1689	76532	666666
6	1	8	553003	55	0	0	113608	666666
7	2	16	393553	56	1476	0	271525	666666
8	2	19	91161	73	1323	0	574036	666666
9	3	20	377339	77	1460	1540	286096	666666
10	1	17	26731	99	0	0	639836	666666
11	2	7	430720	60	1261	0	234565	666666
12	2	20	36272	73	1426	0	628822	666666
13	2	19	281429	52	1099	0	384034	666666
14	2	8	83999	67	1174	0	581359	666666
15	1	20	304163	90	0	0	362413	666666
16	3	16	79812	62	1845	1453	583370	666666
17	3	10	196013	57	1175	1179	468128	666666
18	3	18	312287	72	1115	1990	351058	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	18	560244	78	0	0	296820	857142
2	3	5	684896	51	1232	1940	168921	857142
3	2	18	587648	100	1257	0	268037	857142
4	2	17	465771	70	1609	0	389622	857142
5	1	11	600994	67	0	0	256081	857142
6	3	7	349786	96	1517	1905	503646	857142
7	1	14	251178	56	0	0	605908	857142
8	3	18	689842	95	1595	1828	163592	857142
9	2	17	587737	95	1349	0	267866	857142
10	1	5	258166	66	0	0	598910	857142
11	3	10	165533	71	1380	1927	688089	857142
12	3	7	775356	56	1951	1942	77725	857142
13	2	13	440076	66	1744	0	415190	857142
14	2	14	645607	78	1786	0	209593	857142

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Type 6 #1 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5632	#02-5706	#03-5630	#04-5309	#05-5448	#06-5525	#07-5288	#08-5256	#09-5500	#10-5533
#11-5292	#12-5352	#13-5274	#14-5715	#15-5597	#16-5609	#17-5555	#18-5297	#19-5608	#20-5618
#21-5568	#22-5556	#23-5670	#24-5677	#25-5516	#26-5362	#27-5537	#28-5331	#29-5604	#30-5466
#31-5494	#32-5296	#33-5546	#34-5424	#35-5411	#36-5270	#37-5316	#38-5450	#39-5413	#40-5638
#41-5393	#42-5381	#43-5510	#44-5610	#45-5622	#46-5470	#47-5642	#48-5254	#49-5290	#50-5326
#51-5285	#52-5678	#53-5357	#54-5657	#55-5412	#56-5476	#57-5649	#58-5620	#59-5551	#60-5582
#61-5703	#62-5418	#63-5422	#64-5333	#65-5650	#66-5403	#67-5447	#68-5598	#69-5501	#70-5355
#71-5507	#72-5385	#73-5576	#74-5531	#75-5446	#76-5388	#77-5548	#78-5490	#79-5255	#80-5572
#81-5522	#82-5686	#83-5723	#84-5519	#85-5392	#86-5554	#87-5489	#88-5337	#89-5536	#90-5342
#91-5558	#92-5526	#93-5697	#94-5317	#95-5445	#96-5514	#97-5695	#98-5502	#99-5639	#100-5560

Type 6 #2 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5669	#02-5453	#03-5639	#04-5510	#05-5252	#06-5342	#07-5697	#08-5672	#09-5283	#10-5486
#11-5378	#12-5441	#13-5449	#14-5328	#15-5359	#16-5525	#17-5268	#18-5676	#19-5722	#20-5706
#21-5484	#22-5698	#23-5645	#24-5259	#25-5321	#26-5353	#27-5466	#28-5500	#29-5611	#30-5657
#31-5699	#32-5414	#33-5412	#34-5575	#35-5663	#36-5640	#37-5703	#38-5334	#39-5443	#40-5430
#41-5394	#42-5524	#43-5290	#44-5568	#45-5601	#46-5720	#47-5302	#48-5405	#49-5419	#50-5688
#51-5550	#52-5540	#53-5326	#54-5696	#55-5532	#56-5629	#57-5439	#58-5624	#59-5708	#60-5480
#61-5422	#62-5397	#63-5553	#64-5403	#65-5276	#66-5287	#67-5478	#68-5420	#69-5609	#70-5289
#71-5591	#72-5529	#73-5526	#74-5340	#75-5423	#76-5604	#77-5415	#78-5444	#79-5357	#80-5306
#81-5311	#82-5330	#83-5376	#84-5694	#85-5398	#86-5599	#87-5335	#88-5603	#89-5380	#90-5261
#91-5514	#92-5435	#93-5460	#94-5675	#95-5461	#96-5574	#97-5683	#98-5549	#99-5709	#100-5534

Type 6 #3 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5444	#02-5347	#03-5271	#04-5263	#05-5711	#06-5522	#07-5652	#08-5463	#09-5719	#10-5516
#11-5651	#12-5419	#13-5341	#14-5270	#15-5584	#16-5255	#17-5402	#18-5676	#19-5599	#20-5289
#21-5598	#22-5499	#23-5406	#24-5318	#25-5575	#26-5367	#27-5297	#28-5393	#29-5251	#30-5595
#31-5398	#32-5482	#33-5326	#34-5520	#35-5657	#36-5597	#37-5377	#38-5585	#39-5349	#40-5331
#41-5452	#42-5523	#43-5643	#44-5533	#45-5506	#46-5605	#47-5355	#48-5602	#49-5409	#50-5422
#51-5257	#52-5674	#53-5670	#54-5661	#55-5669	#56-5665	#57-5677	#58-5413	#59-5593	#60-5475
#61-5509	#62-5462	#63-5373	#64-5368	#65-5342	#66-5546	#67-5338	#68-5541	#69-5576	#70-5518
#71-5561	#72-5325	#73-5704	#74-5488	#75-5319	#76-5487	#77-5666	#78-5515	#79-5566	#80-5423
#81-5390	#82-5532	#83-5380	#84-5712	#85-5656	#86-5424	#87-5481	#88-5581	#89-5667	#90-5310
#91-5396	#92-5524	#93-5364	#94-5309	#95-5266	#96-5616	#97-5405	#98-5359	#99-5586	#100-5690

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Type 6 #4 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5426	#02-5417	#03-5343	#04-5355	#05-5533	#06-5719	#07-5621	#08-5675	#09-5702	#10-5611
#11-5686	#12-5687	#13-5351	#14-5305	#15-5427	#16-5368	#17-5344	#18-5662	#19-5618	#20-5264
#21-5557	#22-5688	#23-5395	#24-5631	#25-5428	#26-5649	#27-5624	#28-5283	#29-5542	#30-5709
#31-5376	#32-5271	#33-5722	#34-5272	#35-5479	#36-5257	#37-5328	#38-5375	#39-5297	#40-5673
#41-5414	#42-5446	#43-5547	#44-5477	#45-5451	#46-5347	#47-5640	#48-5560	#49-5354	#50-5487
#51-5312	#52-5468	#53-5465	#54-5572	#55-5382	#56-5463	#57-5437	#58-5652	#59-5608	#60-5345
#61-5587	#62-5383	#63-5717	#64-5484	#65-5664	#66-5689	#67-5550	#68-5420	#69-5289	#70-5693
#71-5614	#72-5670	#73-5574	#74-5361	#75-5390	#76-5643	#77-5429	#78-5331	#79-5259	#80-5313
#81-5654	#82-5647	#83-5633	#84-5531	#85-5400	#86-5266	#87-5616	#88-5448	#89-5577	#90-5552
#91-5554	#92-5511	#93-5562	#94-5260	#95-5659	#96-5447	#97-5579	#98-5520	#99-5322	#100-5353

Type 6 #5 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5257	#02-5571	#03-5599	#04-5282	#05-5657	#06-5327	#07-5320	#08-5576	#09-5383	#10-5539
#11-5438	#12-5533	#13-5435	#14-5398	#15-5495	#16-5450	#17-5342	#18-5271	#19-5297	#20-5561
#21-5650	#22-5643	#23-5673	#24-5422	#25-5302	#26-5719	#27-5583	#28-5553	#29-5303	#30-5261
#31-5402	#32-5593	#33-5668	#34-5606	#35-5609	#36-5602	#37-5544	#38-5619	#39-5710	#40-5483
#41-5390	#42-5377	#43-5568	#44-5373	#45-5451	#46-5474	#47-5298	#48-5573	#49-5379	#50-5427
#51-5701	#52-5698	#53-5486	#54-5339	#55-5622	#56-5704	#57-5663	#58-5469	#59-5492	#60-5522
#61-5372	#62-5386	#63-5570	#64-5590	#65-5554	#66-5513	#67-5617	#68-5636	#69-5523	#70-5376
#71-5312	#72-5510	#73-5515	#74-5354	#75-5534	#76-5649	#77-5559	#78-5426	#79-5432	#80-5428
#81-5519	#82-5361	#83-5565	#84-5681	#85-5490	#86-5716	#87-5592	#88-5255	#89-5527	#90-5586
#91-5644	#92-5680	#93-5468	#94-5629	#95-5574	#96-5408	#97-5642	#98-5549	#99-5518	#100-5378

Type 6 #6 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5378	#02-5417	#03-5660	#04-5512	#05-5598	#06-5538	#07-5685	#08-5675	#09-5407	#10-5375
#11-5719	#12-5638	#13-5524	#14-5683	#15-5419	#16-5546	#17-5335	#18-5642	#19-5509	#20-5647
#21-5496	#22-5714	#23-5575	#24-5274	#25-5431	#26-5654	#27-5576	#28-5708	#29-5510	#30-5695
#31-5436	#32-5707	#33-5513	#34-5555	#35-5454	#36-5442	#37-5472	#38-5429	#39-5519	#40-5515
#41-5291	#42-5668	#43-5671	#44-5404	#45-5339	#46-5322	#47-5250	#48-5289	#49-5595	#50-5607
#51-5389	#52-5567	#53-5636	#54-5487	#55-5416	#56-5608	#57-5358	#58-5692	#59-5383	#60-5590
#61-5273	#62-5452	#63-5541	#64-5631	#65-5716	#66-5606	#67-5317	#68-5425	#69-5644	#70-5535
#71-5306	#72-5483	#73-5421	#74-5618	#75-5676	#76-5655	#77-5565	#78-5350	#79-5296	#80-5643
#81-5691	#82-5552	#83-5558	#84-5363	#85-5609	#86-5295	#87-5653	#88-5492	#89-5563	#90-5376
#91-5424	#92-5498	#93-5348	#94-5441	#95-5327	#96-5697	#97-5688	#98-5578	#99-5403	#100-5505

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Type 6 #7 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5653	#02-5624	#03-5661	#04-5323	#05-5432	#06-5330	#07-5342	#08-5612	#09-5441	#10-5450
#11-5684	#12-5322	#13-5639	#14-5345	#15-5483	#16-5312	#17-5284	#18-5489	#19-5377	#20-5715
#21-5393	#22-5361	#23-5534	#24-5648	#25-5520	#26-5484	#27-5431	#28-5683	#29-5396	#30-5386
#31-5442	#32-5411	#33-5490	#34-5436	#35-5623	#36-5659	#37-5427	#38-5536	#39-5588	#40-5572
#41-5399	#42-5676	#43-5699	#44-5539	#45-5275	#46-5526	#47-5707	#48-5463	#49-5357	#50-5339
#51-5382	#52-5412	#53-5542	#54-5263	#55-5527	#56-5672	#57-5383	#58-5465	#59-5305	#60-5257
#61-5523	#62-5557	#63-5453	#64-5446	#65-5548	#66-5609	#67-5473	#68-5625	#69-5530	#70-5566
#71-5426	#72-5560	#73-5359	#74-5495	#75-5449	#76-5469	#77-5289	#78-5457	#79-5353	#80-5278
#81-5328	#82-5324	#83-5569	#84-5414	#85-5259	#86-5641	#87-5673	#88-5265	#89-5460	#90-5604
#91-5691	#92-5266	#93-5511	#94-5472	#95-5430	#96-5438	#97-5577	#98-5571	#99-5644	#100-5366

Type 6 #8 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5504	#02-5629	#03-5282	#04-5714	#05-5424	#06-5638	#07-5426	#08-5572	#09-5628	#10-5494
#11-5479	#12-5379	#13-5365	#14-5704	#15-5445	#16-5464	#17-5709	#18-5581	#19-5550	#20-5706
#21-5546	#22-5593	#23-5342	#24-5302	#25-5610	#26-5663	#27-5555	#28-5541	#29-5276	#30-5640
#31-5425	#32-5481	#33-5405	#34-5689	#35-5315	#36-5509	#37-5701	#38-5652	#39-5499	#40-5351
#41-5284	#42-5313	#43-5496	#44-5688	#45-5668	#46-5395	#47-5660	#48-5691	#49-5453	#50-5721
#51-5270	#52-5662	#53-5545	#54-5635	#55-5536	#56-5353	#57-5486	#58-5333	#59-5713	#60-5318
#61-5722	#62-5698	#63-5401	#64-5661	#65-5487	#66-5307	#67-5331	#68-5448	#69-5672	#70-5513
#71-5530	#72-5571	#73-5338	#74-5666	#75-5517	#76-5619	#77-5515	#78-5309	#79-5436	#80-5429
#81-5461	#82-5467	#83-5394	#84-5404	#85-5548	#86-5262	#87-5268	#88-5399	#89-5324	#90-5427
#91-5694	#92-5719	#93-5271	#94-5340	#95-5454	#96-5396	#97-5639	#98-5547	#99-5715	#100-5281

Type 6 #9 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5355	#02-5689	#03-5615	#04-5411	#05-5693	#06-5439	#07-5344	#08-5485	#09-5527	#10-5614
#11-5511	#12-5480	#13-5256	#14-5484	#15-5687	#16-5489	#17-5319	#18-5430	#19-5523	#20-5302
#21-5455	#22-5393	#23-5372	#24-5697	#25-5597	#26-5424	#27-5580	#28-5289	#29-5514	#30-5638
#31-5477	#32-5363	#33-5299	#34-5258	#35-5356	#36-5386	#37-5293	#38-5553	#39-5304	#40-5701
#41-5522	#42-5538	#43-5463	#44-5712	#45-5512	#46-5378	#47-5690	#48-5637	#49-5570	#50-5367
#51-5442	#52-5703	#53-5624	#54-5546	#55-5493	#56-5420	#57-5566	#58-5645	#59-5630	#60-5487
#61-5349	#62-5253	#63-5618	#64-5435	#65-5678	#66-5383	#67-5347	#68-5275	#69-5601	#70-5468
#71-5325	#72-5658	#73-5666	#74-5483	#75-5536	#76-5335	#77-5296	#78-5377	#79-5669	#80-5521
#81-5284	#82-5384	#83-5399	#84-5437	#85-5587	#86-5671	#87-5598	#88-5320	#89-5438	#90-5557
#91-5460	#92-5326	#93-5539	#94-5545	#95-5490	#96-5698	#97-5628	#98-5691	#99-5551	#100-5681

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Type 6 #10 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5609	#02-5480	#03-5598	#04-5265	#05-5360	#06-5405	#07-5326	#08-5694	#09-5484	#10-5285
#11-5490	#12-5520	#13-5400	#14-5401	#15-5613	#16-5334	#17-5255	#18-5624	#19-5391	#20-5358
#21-5272	#22-5441	#23-5258	#24-5596	#25-5307	#26-5562	#27-5373	#28-5280	#29-5310	#30-5481
#31-5433	#32-5471	#33-5715	#34-5714	#35-5510	#36-5305	#37-5649	#38-5282	#39-5491	#40-5585
#41-5291	#42-5658	#43-5286	#44-5389	#45-5393	#46-5602	#47-5614	#48-5623	#49-5316	#50-5549
#51-5442	#52-5417	#53-5251	#54-5682	#55-5522	#56-5281	#57-5295	#58-5633	#59-5252	#60-5576
#61-5269	#62-5410	#63-5412	#64-5381	#65-5674	#66-5700	#67-5506	#68-5581	#69-5692	#70-5662
#71-5271	#72-5423	#73-5705	#74-5403	#75-5421	#76-5583	#77-5367	#78-5647	#79-5568	#80-5306
#81-5546	#82-5260	#83-5508	#84-5347	#85-5376	#86-5435	#87-5582	#88-5439	#89-5639	#90-5527
#91-5703	#92-5470	#93-5315	#94-5673	#95-5340	#96-5440	#97-5565	#98-5402	#99-5560	#100-5503

Type 6 #11 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5313	#02-5661	#03-5348	#04-5301	#05-5617	#06-5461	#07-5394	#08-5459	#09-5347	#10-5641
#11-5354	#12-5590	#13-5371	#14-5290	#15-5576	#16-5573	#17-5357	#18-5416	#19-5648	#20-5724
#21-5503	#22-5273	#23-5468	#24-5445	#25-5250	#26-5657	#27-5356	#28-5634	#29-5276	#30-5456
#31-5252	#32-5629	#33-5711	#34-5481	#35-5411	#36-5278	#37-5675	#38-5543	#39-5437	#40-5704
#41-5542	#42-5611	#43-5599	#44-5364	#45-5275	#46-5346	#47-5492	#48-5333	#49-5399	#50-5478
#51-5560	#52-5442	#53-5628	#54-5300	#55-5684	#56-5484	#57-5432	#58-5616	#59-5638	#60-5449
#61-5604	#62-5615	#63-5569	#64-5415	#65-5545	#66-5407	#67-5597	#68-5527	#69-5536	#70-5523
#71-5455	#72-5582	#73-5570	#74-5610	#75-5559	#76-5331	#77-5538	#78-5509	#79-5372	#80-5577
#81-5401	#82-5400	#83-5480	#84-5404	#85-5694	#86-5375	#87-5624	#88-5583	#89-5267	#90-5678
#91-5522	#92-5651	#93-5697	#94-5485	#95-5458	#96-5430	#97-5655	#98-5672	#99-5526	#100-5452

Type 6 #12 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5559	#02-5584	#03-5307	#04-5415	#05-5375	#06-5272	#07-5670	#08-5648	#09-5493	#10-5311
#11-5298	#12-5453	#13-5384	#14-5414	#15-5446	#16-5419	#17-5507	#18-5264	#19-5510	#20-5583
#21-5251	#22-5529	#23-5610	#24-5420	#25-5374	#26-5351	#27-5626	#28-5607	#29-5561	#30-5301
#31-5450	#32-5377	#33-5278	#34-5570	#35-5359	#36-5317	#37-5458	#38-5719	#39-5257	#40-5598
#41-5407	#42-5636	#43-5282	#44-5323	#45-5265	#46-5459	#47-5502	#48-5393	#49-5512	#50-5279
#51-5699	#52-5611	#53-5290	#54-5274	#55-5371	#56-5312	#57-5336	#58-5297	#59-5260	#60-5573
#61-5325	#62-5355	#63-5569	#64-5337	#65-5352	#66-5299	#67-5530	#68-5515	#69-5576	#70-5378
#71-5319	#72-5342	#73-5277	#74-5398	#75-5309	#76-5302	#77-5513	#78-5284	#79-5687	#80-5552
#81-5540	#82-5431	#83-5417	#84-5434	#85-5669	#86-5511	#87-5360	#88-5625	#89-5503	#90-5681
#91-5692	#92-5421	#93-5372	#94-5400	#95-5344	#96-5706	#97-5624	#98-5563	#99-5322	#100-5633

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5724	#02-5542	#03-5673	#04-5722	#05-5485	#06-5639	#07-5277	#08-5720	#09-5471	#10-5538
#11-5363	#12-5528	#13-5278	#14-5677	#15-5646	#16-5606	#17-5346	#18-5642	#19-5631	#20-5591
#21-5261	#22-5323	#23-5540	#24-5385	#25-5309	#26-5439	#27-5276	#28-5634	#29-5683	#30-5531
#31-5373	#32-5480	#33-5632	#34-5384	#35-5613	#36-5469	#37-5437	#38-5280	#39-5483	#40-5364
#41-5404	#42-5690	#43-5568	#44-5414	#45-5392	#46-5419	#47-5479	#48-5463	#49-5610	#50-5707
#51-5656	#52-5455	#53-5621	#54-5651	#55-5251	#56-5662	#57-5295	#58-5612	#59-5368	#60-5286
#61-5665	#62-5403	#63-5714	#64-5297	#65-5371	#66-5282	#67-5386	#68-5529	#69-5601	#70-5358
#71-5644	#72-5575	#73-5619	#74-5581	#75-5470	#76-5645	#77-5402	#78-5442	#79-5274	#80-5458
#81-5611	#82-5499	#83-5317	#84-5365	#85-5327	#86-5537	#87-5578	#88-5367	#89-5271	#90-5602
#91-5446	#92-5326	#93-5701	#94-5428	#95-5305	#96-5347	#97-5256	#98-5401	#99-5293	#100-5723

Type 6 #14 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5280	#02-5688	#03-5541	#04-5269	#05-5250	#06-5522	#07-5273	#08-5360	#09-5333	#10-5395
#11-5455	#12-5384	#13-5461	#14-5458	#15-5717	#16-5544	#17-5430	#18-5288	#19-5689	#20-5502
#21-5275	#22-5704	#23-5683	#24-5394	#25-5669	#26-5699	#27-5387	#28-5651	#29-5261	#30-5451
#31-5460	#32-5660	#33-5319	#34-5362	#35-5401	#36-5511	#37-5444	#38-5536	#39-5305	#40-5343
#41-5635	#42-5518	#43-5300	#44-5595	#45-5566	#46-5691	#47-5571	#48-5355	#49-5551	#50-5363
#51-5281	#52-5516	#53-5697	#54-5255	#55-5397	#56-5325	#57-5385	#58-5346	#59-5348	#60-5607
#61-5520	#62-5654	#63-5391	#64-5565	#65-5282	#66-5711	#67-5476	#68-5633	#69-5408	#70-5365
#71-5436	#72-5632	#73-5523	#74-5352	#75-5257	#76-5540	#77-5546	#78-5556	#79-5625	#80-5628
#81-5664	#82-5311	#83-5396	#84-5369	#85-5510	#86-5644	#87-5722	#88-5537	#89-5636	#90-5637
#91-5549	#92-5474	#93-5514	#94-5564	#95-5612	#96-5372	#97-5358	#98-5582	#99-5589	#100-5347

Type 6 #15 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5599	#02-5697	#03-5268	#04-5569	#05-5524	#06-5517	#07-5706	#08-5564	#09-5616	#10-5715
#11-5294	#12-5284	#13-5419	#14-5644	#15-5591	#16-5690	#17-5713	#18-5411	#19-5552	#20-5525
#21-5448	#22-5440	#23-5432	#24-5315	#25-5282	#26-5408	#27-5310	#28-5459	#29-5506	#30-5555
#31-5489	#32-5447	#33-5298	#34-5397	#35-5492	#36-5325	#37-5269	#38-5654	#39-5526	#40-5433
#41-5647	#42-5505	#43-5345	#44-5477	#45-5698	#46-5383	#47-5671	#48-5279	#49-5313	#50-5400
#51-5560	#52-5503	#53-5358	#54-5646	#55-5354	#56-5360	#57-5409	#58-5530	#59-5562	#60-5370
#61-5405	#62-5444	#63-5638	#64-5689	#65-5533	#66-5595	#67-5716	#68-5264	#69-5518	#70-5652
#71-5600	#72-5661	#73-5656	#74-5337	#75-5537	#76-5372	#77-5609	#78-5460	#79-5467	#80-5338
#81-5615	#82-5657	#83-5546	#84-5679	#85-5636	#86-5258	#87-5421	#88-5323	#89-5487	#90-5699
#91-5602	#92-5322	#93-5449	#94-5470	#95-5707	#96-5471	#97-5442	#98-5385	#99-5632	#100-5628

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5556	#02-5427	#03-5558	#04-5542	#05-5713	#06-5525	#07-5320	#08-5429	#09-5627	#10-5316
#11-5554	#12-5514	#13-5342	#14-5259	#15-5621	#16-5587	#17-5544	#18-5666	#19-5280	#20-5677
#21-5723	#22-5686	#23-5583	#24-5559	#25-5337	#26-5626	#27-5665	#28-5628	#29-5274	#30-5643
#31-5373	#32-5458	#33-5425	#34-5603	#35-5335	#36-5687	#37-5629	#38-5423	#39-5322	#40-5255
#41-5673	#42-5659	#43-5377	#44-5698	#45-5574	#46-5580	#47-5269	#48-5444	#49-5683	#50-5679
#51-5594	#52-5568	#53-5455	#54-5336	#55-5623	#56-5331	#57-5488	#58-5724	#59-5363	#60-5653
#61-5490	#62-5424	#63-5611	#64-5412	#65-5581	#66-5317	#67-5298	#68-5549	#69-5614	#70-5577
#71-5610	#72-5402	#73-5498	#74-5388	#75-5608	#76-5483	#77-5668	#78-5319	#79-5263	#80-5504
#81-5615	#82-5426	#83-5398	#84-5313	#85-5547	#86-5323	#87-5616	#88-5270	#89-5419	#90-5678
#91-5411	#92-5417	#93-5328	#94-5631	#95-5329	#96-5704	#97-5716	#98-5302	#99-5562	#100-5695

Type 6 #17 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5667	#02-5403	#03-5365	#04-5604	#05-5710	#06-5420	#07-5411	#08-5357	#09-5522	#10-5711
#11-5517	#12-5582	#13-5254	#14-5475	#15-5615	#16-5540	#17-5685	#18-5590	#19-5707	#20-5545
#21-5566	#22-5702	#23-5642	#24-5529	#25-5621	#26-5302	#27-5413	#28-5658	#29-5524	#30-5623
#31-5312	#32-5345	#33-5342	#34-5605	#35-5505	#36-5682	#37-5261	#38-5285	#39-5724	#40-5704
#41-5614	#42-5431	#43-5535	#44-5255	#45-5611	#46-5405	#47-5439	#48-5414	#49-5280	#50-5497
#51-5319	#52-5267	#53-5379	#54-5690	#55-5486	#56-5561	#57-5708	#58-5657	#59-5256	#60-5477
#61-5558	#62-5648	#63-5422	#64-5636	#65-5595	#66-5359	#67-5583	#68-5673	#69-5555	#70-5277
#71-5587	#72-5337	#73-5461	#74-5718	#75-5415	#76-5258	#77-5468	#78-5360	#79-5593	#80-5275
#81-5394	#82-5688	#83-5639	#84-5269	#85-5371	#86-5278	#87-5352	#88-5717	#89-5289	#90-5396
#91-5715	#92-5507	#93-5363	#94-5559	#95-5700	#96-5329	#97-5331	#98-5336	#99-5714	#100-5516

Type 6 #18 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5275	#03-5567	#04-5342	#05-5491	#06-5723	#07-5259	#08-5447	#09-5279	#10-5358
#11-5396	#12-5276	#13-5672	#14-5680	#15-5340	#16-5461	#17-5645	#18-5452	#19-5715	#20-5712
#21-5440	#22-5347	#23-5678	#24-5605	#25-5306	#26-5388	#27-5529	#28-5512	#29-5597	#30-5664
#31-5404	#32-5421	#33-5286	#34-5718	#35-5660	#36-5585	#37-5719	#38-5280	#39-5673	#40-5685
#41-5398	#42-5691	#43-5533	#44-5278	#45-5579	#46-5714	#47-5343	#48-5410	#49-5464	#50-5345
#51-5251	#52-5325	#53-5505	#54-5321	#55-5687	#56-5301	#57-5525	#58-5595	#59-5643	#60-5492
#61-5486	#62-5457	#63-5596	#64-5500	#65-5644	#66-5346	#67-5657	#68-5710	#69-5592	#70-5721
#71-5681	#72-5386	#73-5638	#74-5498	#75-5412	#76-5593	#77-5399	#78-5435	#79-5351	#80-5382
#81-5568	#82-5402	#83-5506	#84-5647	#85-5566	#86-5623	#87-5534	#88-5443	#89-5637	#90-5484
#91-5661	#92-5502	#93-5659	#94-5617	#95-5411	#96-5425	#97-5349	#98-5295	#99-5558	#100-5368

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5517	#02-5299	#03-5513	#04-5614	#05-5656	#06-5445	#07-5457	#08-5390	#09-5353	#10-5443
#11-5404	#12-5388	#13-5424	#14-5341	#15-5336	#16-5307	#17-5528	#18-5521	#19-5462	#20-5668
#21-5616	#22-5403	#23-5561	#24-5634	#25-5658	#26-5506	#27-5274	#28-5651	#29-5510	#30-5469
#31-5357	#32-5512	#33-5387	#34-5379	#35-5360	#36-5645	#37-5511	#38-5690	#39-5547	#40-5302
#41-5534	#42-5595	#43-5467	#44-5348	#45-5320	#46-5338	#47-5539	#48-5545	#49-5499	#50-5346
#51-5425	#52-5625	#53-5620	#54-5676	#55-5704	#56-5723	#57-5664	#58-5433	#59-5464	#60-5568
#61-5394	#62-5617	#63-5250	#64-5294	#65-5548	#66-5701	#67-5266	#68-5556	#69-5639	#70-5332
#71-5533	#72-5344	#73-5536	#74-5313	#75-5679	#76-5562	#77-5695	#78-5648	#79-5583	#80-5416
#81-5687	#82-5479	#83-5622	#84-5409	#85-5665	#86-5275	#87-5363	#88-5691	#89-5450	#90-5381
#91-5456	#92-5398	#93-5496	#94-5362	#95-5402	#96-5529	#97-5431	#98-5542	#99-5581	#100-5417

Type 6 #20 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5586	#02-5600	#03-5479	#04-5626	#05-5597	#06-5471	#07-5477	#08-5450	#09-5288	#10-5539
#11-5651	#12-5541	#13-5446	#14-5478	#15-5530	#16-5525	#17-5303	#18-5366	#19-5333	#20-5688
#21-5330	#22-5590	#23-5639	#24-5432	#25-5543	#26-5369	#27-5640	#28-5709	#29-5403	#30-5662
#31-5535	#32-5552	#33-5498	#34-5652	#35-5400	#36-5609	#37-5661	#38-5343	#39-5704	#40-5628
#41-5255	#42-5483	#43-5584	#44-5569	#45-5545	#46-5680	#47-5300	#48-5388	#49-5630	#50-5480
#51-5426	#52-5253	#53-5618	#54-5337	#55-5720	#56-5686	#57-5296	#58-5304	#59-5352	#60-5562
#61-5466	#62-5602	#63-5714	#64-5673	#65-5551	#66-5380	#67-5641	#68-5367	#69-5272	#70-5353
#71-5310	#72-5325	#73-5357	#74-5305	#75-5587	#76-5629	#77-5318	#78-5502	#79-5328	#80-5648
#81-5485	#82-5531	#83-5659	#84-5410	#85-5656	#86-5438	#87-5563	#88-5315	#89-5513	#90-5598
#91-5706	#92-5453	#93-5556	#94-5256	#95-5474	#96-5258	#97-5363	#98-5624	#99-5558	#100-5262

Type 6 #21 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5612	#02-5630	#03-5433	#04-5522	#05-5441	#06-5283	#07-5310	#08-5387	#09-5685	#10-5367
#11-5559	#12-5304	#13-5512	#14-5619	#15-5666	#16-5327	#17-5607	#18-5709	#19-5476	#20-5719
#21-5536	#22-5484	#23-5324	#24-5384	#25-5322	#26-5581	#27-5568	#28-5494	#29-5338	#30-5535
#31-5331	#32-5631	#33-5351	#34-5398	#35-5294	#36-5532	#37-5379	#38-5687	#39-5571	#40-5254
#41-5376	#42-5637	#43-5589	#44-5618	#45-5501	#46-5468	#47-5580	#48-5316	#49-5636	#50-5481
#51-5419	#52-5563	#53-5450	#54-5378	#55-5556	#56-5299	#57-5449	#58-5585	#59-5440	#60-5541
#61-5298	#62-5400	#63-5285	#64-5652	#65-5678	#66-5364	#67-5574	#68-5383	#69-5673	#70-5644
#71-5633	#72-5714	#73-5410	#74-5459	#75-5490	#76-5546	#77-5362	#78-5712	#79-5427	#80-5426
#81-5483	#82-5672	#83-5640	#84-5700	#85-5329	#86-5488	#87-5711	#88-5438	#89-5487	#90-5553
#91-5691	#92-5547	#93-5354	#94-5256	#95-5657	#96-5688	#97-5562	#98-5282	#99-5573	#100-5290

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5532	#02-5347	#03-5534	#04-5627	#05-5472	#06-5452	#07-5363	#08-5597	#09-5346	#10-5373
#11-5418	#12-5415	#13-5416	#14-5658	#15-5408	#16-5593	#17-5405	#18-5401	#19-5504	#20-5526
#21-5332	#22-5333	#23-5630	#24-5524	#25-5723	#26-5258	#27-5706	#28-5494	#29-5463	#30-5467
#31-5604	#32-5718	#33-5664	#34-5632	#35-5358	#36-5603	#37-5520	#38-5586	#39-5488	#40-5651
#41-5324	#42-5455	#43-5391	#44-5430	#45-5522	#46-5381	#47-5663	#48-5322	#49-5499	#50-5344
#51-5406	#52-5606	#53-5710	#54-5297	#55-5682	#56-5449	#57-5441	#58-5259	#59-5629	#60-5464
#61-5470	#62-5594	#63-5383	#64-5493	#65-5425	#66-5476	#67-5508	#68-5550	#69-5529	#70-5544
#71-5637	#72-5578	#73-5602	#74-5666	#75-5450	#76-5252	#77-5591	#78-5319	#79-5634	#80-5720
#81-5368	#82-5310	#83-5617	#84-5674	#85-5412	#86-5511	#87-5681	#88-5273	#89-5321	#90-5512
#91-5662	#92-5404	#93-5497	#94-5695	#95-5271	#96-5587	#97-5693	#98-5569	#99-5329	#100-5507

Type 6 #23 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5716	#02-5257	#03-5287	#04-5395	#05-5560	#06-5599	#07-5264	#08-5544	#09-5494	#10-5417
#11-5584	#12-5558	#13-5640	#14-5367	#15-5536	#16-5587	#17-5613	#18-5397	#19-5721	#20-5531
#21-5404	#22-5512	#23-5630	#24-5686	#25-5639	#26-5387	#27-5274	#28-5347	#29-5447	#30-5280
#31-5601	#32-5297	#33-5595	#34-5377	#35-5421	#36-5503	#37-5644	#38-5603	#39-5594	#40-5581
#41-5307	#42-5693	#43-5418	#44-5654	#45-5296	#46-5570	#47-5578	#48-5459	#49-5250	#50-5330
#51-5709	#52-5573	#53-5523	#54-5352	#55-5453	#56-5326	#57-5480	#58-5423	#59-5574	#60-5642
#61-5346	#62-5464	#63-5540	#64-5688	#65-5513	#66-5670	#67-5283	#68-5667	#69-5259	#70-5528
#71-5390	#72-5474	#73-5436	#74-5344	#75-5700	#76-5319	#77-5612	#78-5446	#79-5675	#80-5617
#81-5449	#82-5321	#83-5401	#84-5568	#85-5373	#86-5256	#87-5389	#88-5596	#89-5678	#90-5364
#91-5484	#92-5606	#93-5317	#94-5632	#95-5426	#96-5308	#97-5320	#98-5430	#99-5432	#100-5299

Type 6 #24 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5641	#02-5358	#03-5377	#04-5411	#05-5410	#06-5617	#07-5402	#08-5279	#09-5625	#10-5514
#11-5648	#12-5337	#13-5488	#14-5702	#15-5607	#16-5349	#17-5610	#18-5356	#19-5383	#20-5334
#21-5564	#22-5390	#23-5586	#24-5405	#25-5437	#26-5463	#27-5435	#28-5387	#29-5604	#30-5436
#31-5266	#32-5272	#33-5584	#34-5273	#35-5407	#36-5687	#37-5529	#38-5579	#39-5359	#40-5695
#41-5414	#42-5440	#43-5397	#44-5714	#45-5553	#46-5654	#47-5544	#48-5684	#49-5434	#50-5324
#51-5298	#52-5690	#53-5326	#54-5693	#55-5515	#56-5255	#57-5698	#58-5403	#59-5613	#60-5569
#61-5634	#62-5462	#63-5320	#64-5595	#65-5380	#66-5368	#67-5583	#68-5666	#69-5552	#70-5699
#71-5594	#72-5700	#73-5395	#74-5258	#75-5447	#76-5616	#77-5428	#78-5420	#79-5362	#80-5306
#81-5282	#82-5615	#83-5483	#84-5401	#85-5376	#86-5457	#87-5505	#88-5369	#89-5423	#90-5536
#91-5685	#92-5267	#93-5511	#94-5496	#95-5493	#96-5715	#97-5717	#98-5722	#99-5501	#100-5677

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5309	#02-5463	#03-5350	#04-5351	#05-5538	#06-5347	#07-5477	#08-5514	#09-5658	#10-5426
#11-5564	#12-5433	#13-5386	#14-5444	#15-5417	#16-5656	#17-5328	#18-5460	#19-5298	#20-5655
#21-5410	#22-5634	#23-5590	#24-5450	#25-5315	#26-5550	#27-5623	#28-5363	#29-5404	#30-5607
#31-5661	#32-5563	#33-5397	#34-5292	#35-5602	#36-5699	#37-5555	#38-5326	#39-5308	#40-5585
#41-5577	#42-5320	#43-5654	#44-5532	#45-5522	#46-5676	#47-5423	#48-5282	#49-5705	#50-5271
#51-5624	#52-5554	#53-5485	#54-5626	#55-5472	#56-5579	#57-5711	#58-5360	#59-5445	#60-5543
#61-5627	#62-5595	#63-5713	#64-5402	#65-5540	#66-5681	#67-5497	#68-5384	#69-5714	#70-5319
#71-5657	#72-5306	#73-5519	#74-5521	#75-5508	#76-5479	#77-5411	#78-5338	#79-5289	#80-5574
#81-5680	#82-5541	#83-5498	#84-5462	#85-5367	#86-5323	#87-5333	#88-5528	#89-5454	#90-5598
#91-5381	#92-5501	#93-5276	#94-5331	#95-5369	#96-5359	#97-5650	#98-5716	#99-5677	#100-5691

Type 6 #26 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5497	#02-5690	#03-5355	#04-5689	#05-5292	#06-5478	#07-5550	#08-5271	#09-5405	#10-5694
#11-5672	#12-5304	#13-5464	#14-5664	#15-5423	#16-5608	#17-5413	#18-5580	#19-5510	#20-5446
#21-5539	#22-5650	#23-5268	#24-5494	#25-5571	#26-5397	#27-5705	#28-5274	#29-5704	#30-5364
#31-5676	#32-5589	#33-5532	#34-5402	#35-5692	#36-5369	#37-5485	#38-5700	#39-5298	#40-5346
#41-5329	#42-5607	#43-5591	#44-5430	#45-5688	#46-5475	#47-5486	#48-5455	#49-5480	#50-5401
#51-5671	#52-5586	#53-5367	#54-5620	#55-5498	#56-5525	#57-5291	#58-5267	#59-5707	#60-5440
#61-5657	#62-5699	#63-5270	#64-5641	#65-5294	#66-5345	#67-5535	#68-5443	#69-5674	#70-5461
#71-5415	#72-5530	#73-5311	#74-5479	#75-5602	#76-5634	#77-5484	#78-5358	#79-5381	#80-5368
#81-5356	#82-5252	#83-5590	#84-5451	#85-5658	#86-5514	#87-5416	#88-5659	#89-5456	#90-5667
#91-5559	#92-5442	#93-5645	#94-5332	#95-5682	#96-5622	#97-5460	#98-5420	#99-5339	#100-5698

Type 6 #27 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5464	#02-5537	#03-5414	#04-5357	#05-5473	#06-5332	#07-5526	#08-5580	#09-5540	#10-5535
#11-5292	#12-5479	#13-5333	#14-5625	#15-5389	#16-5265	#17-5671	#18-5318	#19-5523	#20-5596
#21-5319	#22-5368	#23-5644	#24-5410	#25-5687	#26-5564	#27-5275	#28-5423	#29-5471	#30-5720
#31-5660	#32-5574	#33-5501	#34-5478	#35-5283	#36-5492	#37-5494	#38-5406	#39-5598	#40-5334
#41-5382	#42-5600	#43-5377	#44-5274	#45-5399	#46-5442	#47-5561	#48-5432	#49-5543	#50-5606
#51-5513	#52-5351	#53-5604	#54-5467	#55-5628	#56-5345	#57-5617	#58-5254	#59-5395	#60-5633
#61-5307	#62-5353	#63-5358	#64-5544	#65-5599	#66-5443	#67-5702	#68-5579	#69-5591	#70-5621
#71-5496	#72-5515	#73-5445	#74-5438	#75-5463	#76-5716	#77-5620	#78-5260	#79-5252	#80-5567
#81-5590	#82-5457	#83-5559	#84-5695	#85-5284	#86-5575	#87-5663	#88-5489	#89-5261	#90-5689
#91-5277	#92-5279	#93-5557	#94-5681	#95-5465	#96-5707	#97-5566	#98-5646	#99-5359	#100-5723

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5631	#02-5415	#03-5253	#04-5435	#05-5353	#06-5721	#07-5719	#08-5625	#09-5464	#10-5473
#11-5493	#12-5337	#13-5290	#14-5668	#15-5254	#16-5653	#17-5272	#18-5257	#19-5503	#20-5480
#21-5411	#22-5434	#23-5675	#24-5409	#25-5471	#26-5304	#27-5279	#28-5269	#29-5251	#30-5682
#31-5481	#32-5459	#33-5652	#34-5529	#35-5280	#36-5389	#37-5559	#38-5602	#39-5495	#40-5360
#41-5308	#42-5537	#43-5530	#44-5724	#45-5470	#46-5359	#47-5458	#48-5521	#49-5702	#50-5637
#51-5624	#52-5352	#53-5469	#54-5401	#55-5544	#56-5484	#57-5669	#58-5500	#59-5664	#60-5595
#61-5611	#62-5463	#63-5515	#64-5262	#65-5362	#66-5638	#67-5590	#68-5343	#69-5395	#70-5487
#71-5393	#72-5422	#73-5599	#74-5628	#75-5676	#76-5663	#77-5361	#78-5571	#79-5483	#80-5291
#81-5338	#82-5378	#83-5715	#84-5501	#85-5525	#86-5460	#87-5629	#88-5615	#89-5351	#90-5555
#91-5489	#92-5421	#93-5324	#94-5265	#95-5711	#96-5592	#97-5722	#98-5514	#99-5608	#100-5479

Type 6 #29 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5590	#02-5325	#03-5703	#04-5380	#05-5641	#06-5532	#07-5255	#08-5389	#09-5343	#10-5362
#11-5569	#12-5374	#13-5457	#14-5608	#15-5612	#16-5586	#17-5393	#18-5427	#19-5685	#20-5453
#21-5293	#22-5656	#23-5628	#24-5250	#25-5524	#26-5613	#27-5689	#28-5320	#29-5364	#30-5307
#31-5600	#32-5654	#33-5519	#34-5554	#35-5513	#36-5639	#37-5522	#38-5394	#39-5544	#40-5346
#41-5609	#42-5687	#43-5462	#44-5377	#45-5576	#46-5674	#47-5353	#48-5705	#49-5386	#50-5370
#51-5430	#52-5402	#53-5341	#54-5435	#55-5658	#56-5422	#57-5580	#58-5278	#59-5567	#60-5660
#61-5274	#62-5286	#63-5487	#64-5640	#65-5579	#66-5627	#67-5344	#68-5697	#69-5313	#70-5723
#71-5588	#72-5568	#73-5330	#74-5444	#75-5501	#76-5399	#77-5575	#78-5340	#79-5661	#80-5419
#81-5428	#82-5368	#83-5467	#84-5539	#85-5515	#86-5504	#87-5663	#88-5426	#89-5614	#90-5630
#91-5259	#92-5257	#93-5322	#94-5371	#95-5546	#96-5497	#97-5355	#98-5464	#99-5645	#100-5553

Type 6 #30 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5255	#02-5673	#03-5706	#04-5570	#05-5296	#06-5349	#07-5317	#08-5389	#09-5401	#10-5508
#11-5489	#12-5480	#13-5494	#14-5434	#15-5342	#16-5334	#17-5619	#18-5392	#19-5267	#20-5611
#21-5463	#22-5424	#23-5577	#24-5332	#25-5630	#26-5540	#27-5598	#28-5687	#29-5655	#30-5263
#31-5365	#32-5546	#33-5715	#34-5534	#35-5567	#36-5522	#37-5353	#38-5616	#39-5326	#40-5547
#41-5521	#42-5668	#43-5372	#44-5495	#45-5502	#46-5553	#47-5662	#48-5454	#49-5603	#50-5688
#51-5446	#52-5283	#53-5340	#54-5500	#55-5498	#56-5379	#57-5488	#58-5390	#59-5533	#60-5444
#61-5427	#62-5470	#63-5373	#64-5659	#65-5503	#66-5625	#67-5536	#68-5515	#69-5666	#70-5314
#71-5537	#72-5302	#73-5331	#74-5555	#75-5327	#76-5393	#77-5482	#78-5300	#79-5643	#80-5512
#81-5284	#82-5318	#83-5590	#84-5476	#85-5517	#86-5344	#87-5447	#88-5602	#89-5371	#90-5299
#91-5286	#92-5678	#93-5337	#94-5437	#95-5505	#96-5694	#97-5398	#98-5297	#99-5657	#100-5313

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